

# Electromagnetic compatibility of Integrated Circuits



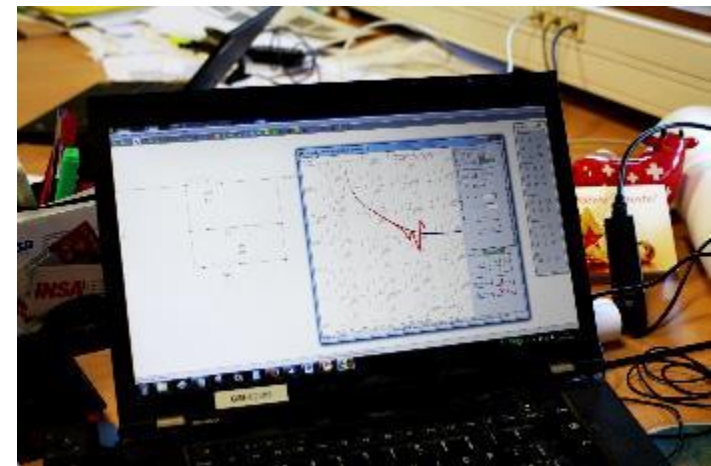
Etienne SICARD  
INSA/DGEI  
University of Toulouse  
31077 Toulouse - France  
[Etienne.sicard@insa-toulouse.fr](mailto:Etienne.sicard@insa-toulouse.fr)



Alexandre BOYER  
INSA/DGEI – LAAS-CNRS  
University of Toulouse  
31077 Toulouse - France  
[Alexandre.boyer@insa-toulouse.fr](mailto:Alexandre.boyer@insa-toulouse.fr)

# Objectives

- Understand parasitic emission mechanisms
- Introduce parasitic emission reduction strategies
- Give an overview of emission and susceptibility measurement standards
- Power Decoupling Network modelling
- Basis of conducted and radiated emission modelling
- Basis of immunity modelling
- Hands-on experience in IC emission and immunity measurements

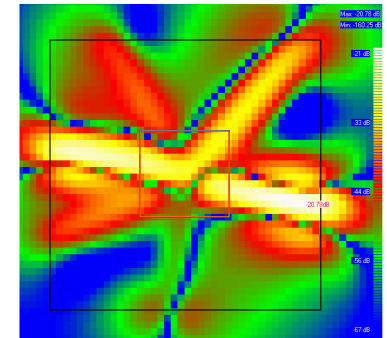
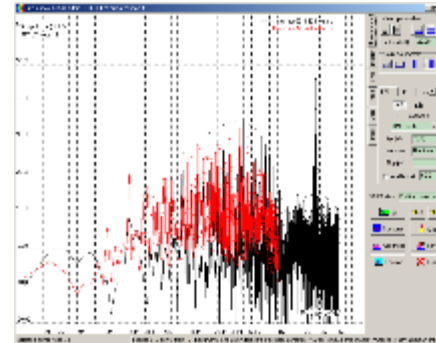
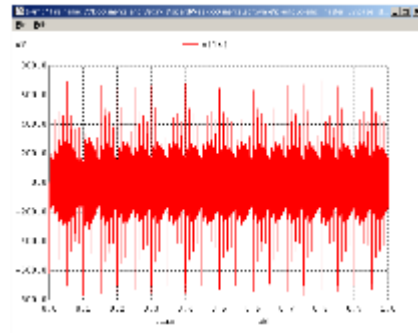
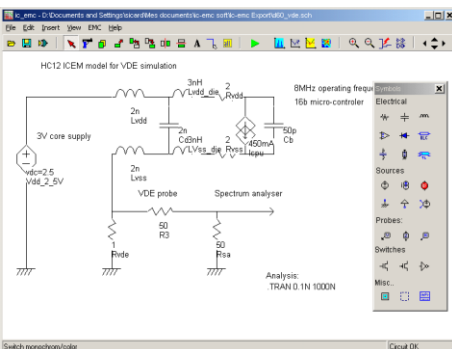
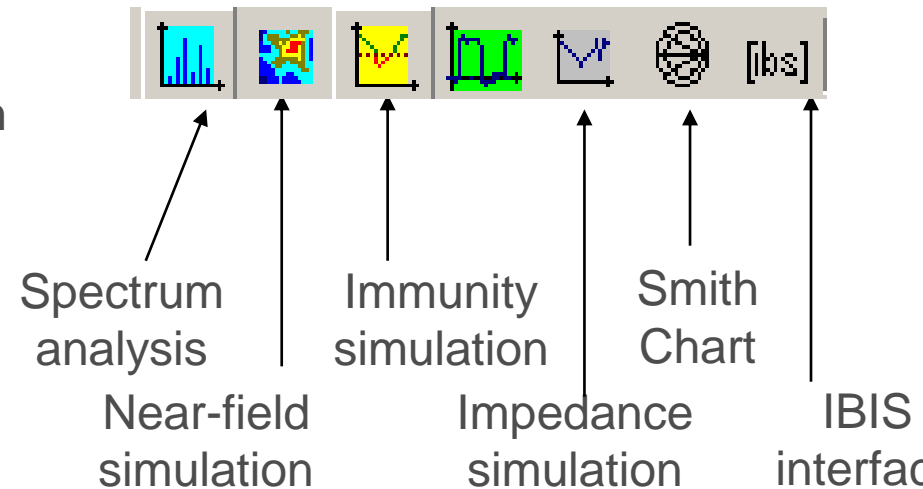


## Illustration with IC-EMC

## IC-EMC - A TOOL FOR EMC PREDICTION AT IC LEVEL

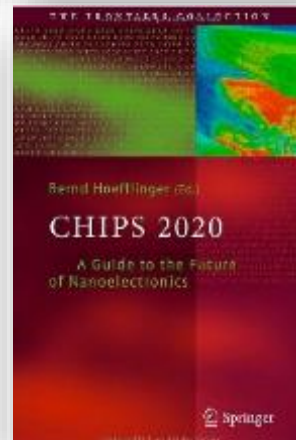
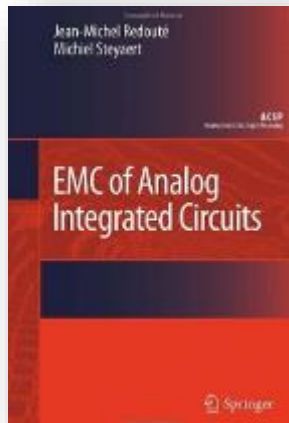
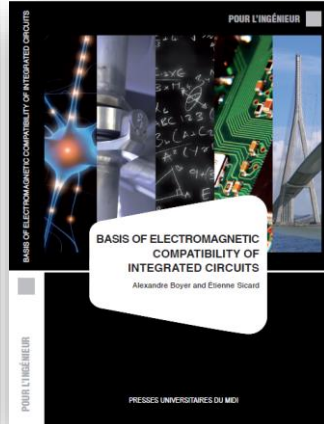
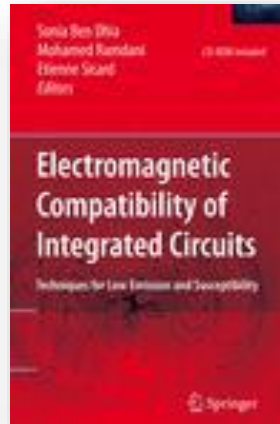
- ❑ A schematic editor
- ❑ An interface to WinSpice
- ❑ A post-processor to compare simulated with measured spectrum
- ❑ An Electromagnetic solver for radiated field
- ❑ Freeware, online
- ❑ 250 pp documentation, 15 case studies

## Key tools



# References

## Books

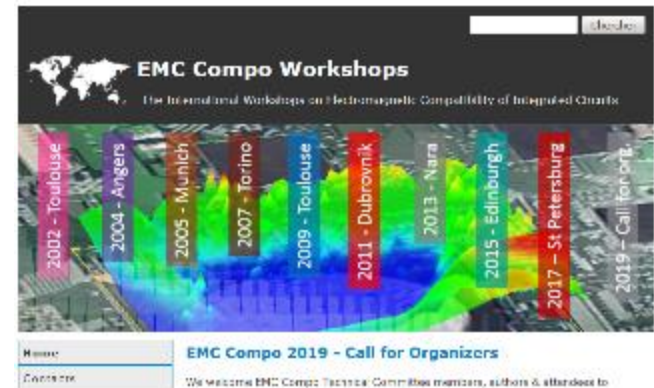


## Freeware



[www.ic-emc.org](http://www.ic-emc.org)

## Workshops



[www.emccompo.org](http://www.emccompo.org)

## Standards [www.iec.ch](http://www.iec.ch)



- IEC 61967, 2001, Integrated Circuits Emissions
- IEC 62132, 2003, Integrated circuits Immunity
- IEC 62433, 2008, Integrated Circuit Model

# 1. EMC of ICs

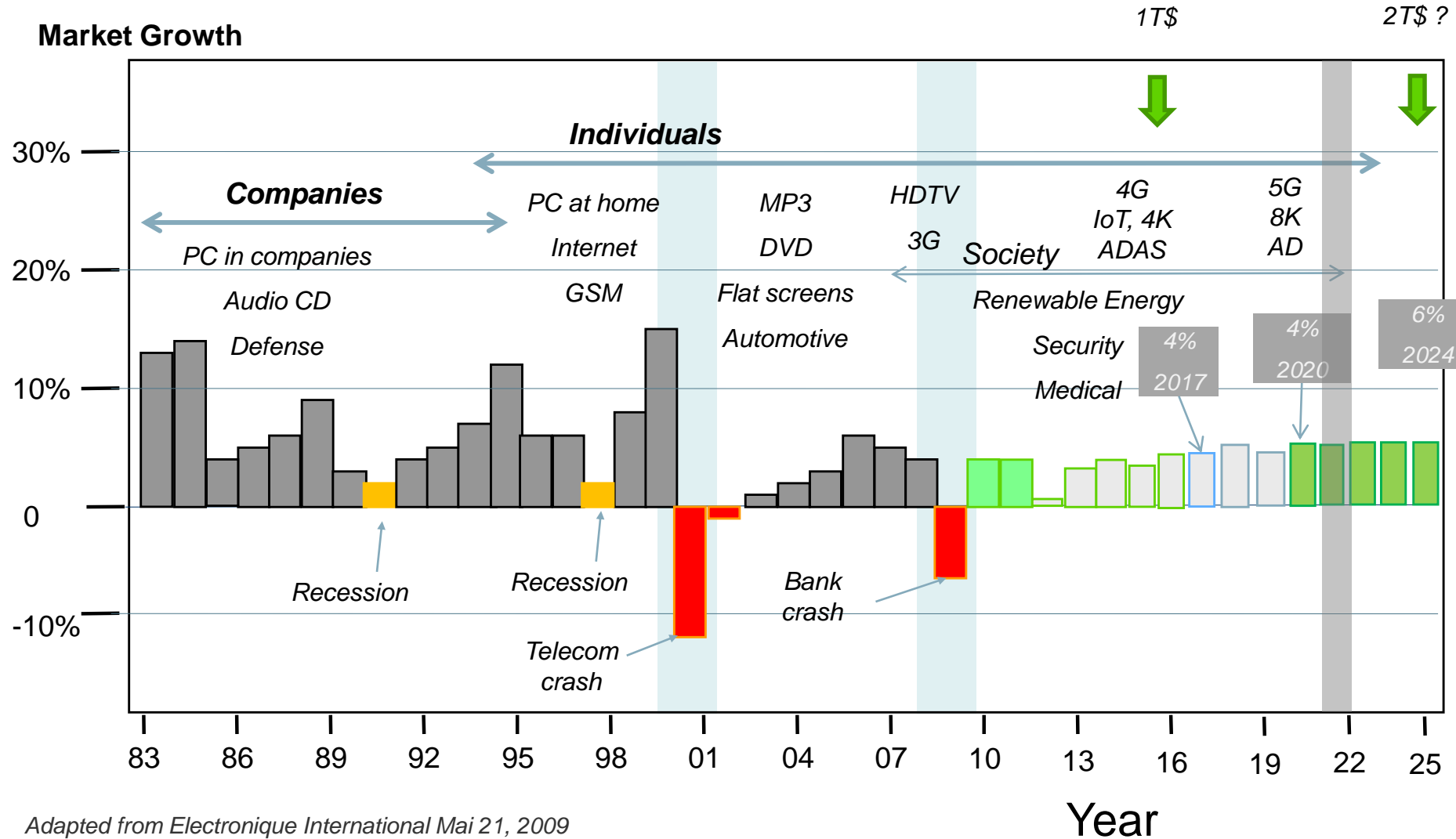
## An overview

---

# Outlines

- **Electronic Market Growth**
- **Electromagnetic interference**
- **What is EMC**
- **Technology scale down**
- **Going 3D**
- **Origin of parasitic emission**
- **Trends towards higher emission**
- **Origin on susceptibility**
- **Emission issues**
- **Susceptibility issues**
- **EMC issues**
- **Conclusion**

# Electronic Market Growth





# Electronic Market Growth

<https://www.semiconductorintelligence.com/semiconductor-growth-to-continue-in-2022/>

## Top Semiconductor Companies' Revenue

Change versus prior quarter in local currency

Rank	Company	\$Billion 2Q21	Reported 2Q21	Guidance 3Q21	Comments on 3Q21 revenue
1	Samsung SC	20.3	19.6%	n/a	strong demand for server/PC
2	Intel	19.6	-0.2%	-2.7%	supply constrained
3	SK Hynix	9.2	21.5%	n/a	strong demand for 5G & server
4	Micron Technology	7.4	19.0%	10.5%	memory supply below demand
5	Broadcom	6.8	*	2.1%	n/a * 2Q21 is guidance from 1Q21
6	Qualcomm (IC)	6.5	3.0%	12.0%	strong handset growth
7	Nvidia	6.3	*	11.3%	n/a * 2Q21 is guidance from 1Q21
8	Texas Instruments	4.6	6.8%	0.0%	capacity limited
9	MediaTek	4.5	16.3%	2.5%	strong 5G market
10	AMD	3.9	11.8%	6.5%	growth in data center & gaming
11	Infineon Technologies	3.3	0.8%	6.5%	recovery in smartphones
12	STMicroelectronics	3.0	-0.8%	7.0%	improved pricing & volume
13	Kioxia	3.0	11.8%	n/a	strong SSD & 5G demand
14	NXP Semiconductors	2.6	1.1%	9.8%	strong demand across markets
Total of above companies			10%		
Memory Companies (US\$)			22%		Samsung, SK Hynix, Micron, Kioxia
Non-Memory Companies			3%	2%	companies providing guidance

2021

2022

## Semiconductor Market Forecasts





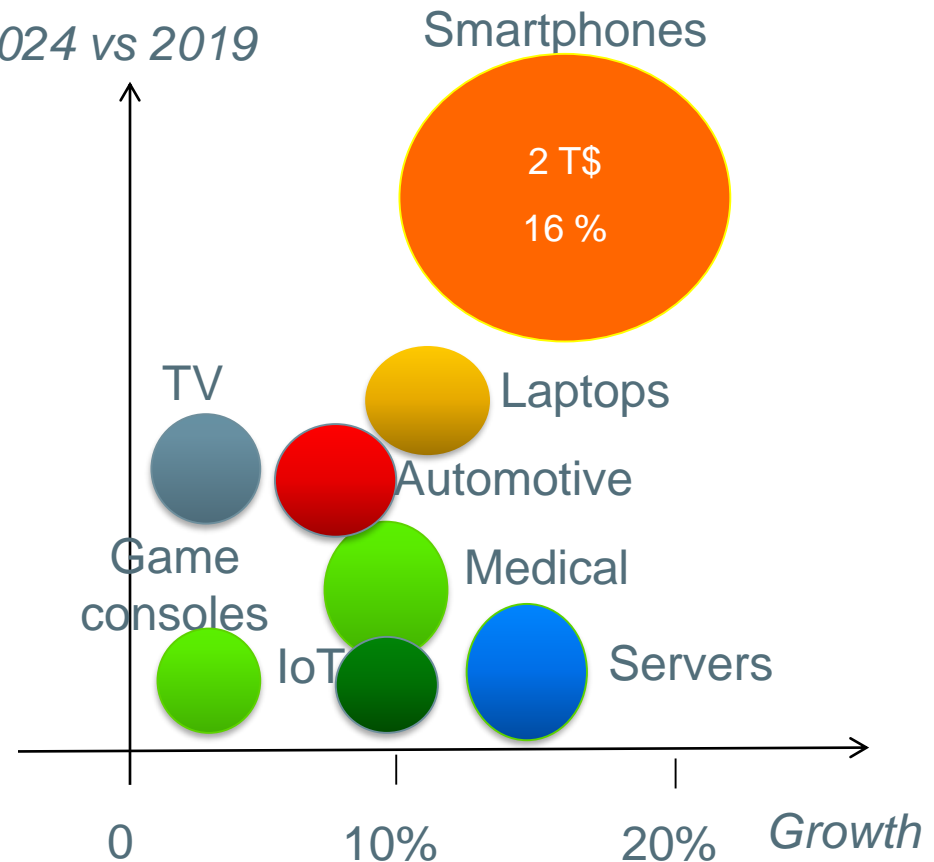
# Electronic Market Growth

## ■ Vision 2024

- Increasing disposable income,
- expanding urban population,
- growing internet penetration and
- availability of strong distribution network

*Share of system sales*

*2024 vs 2019*



# Electromagnetic Interference

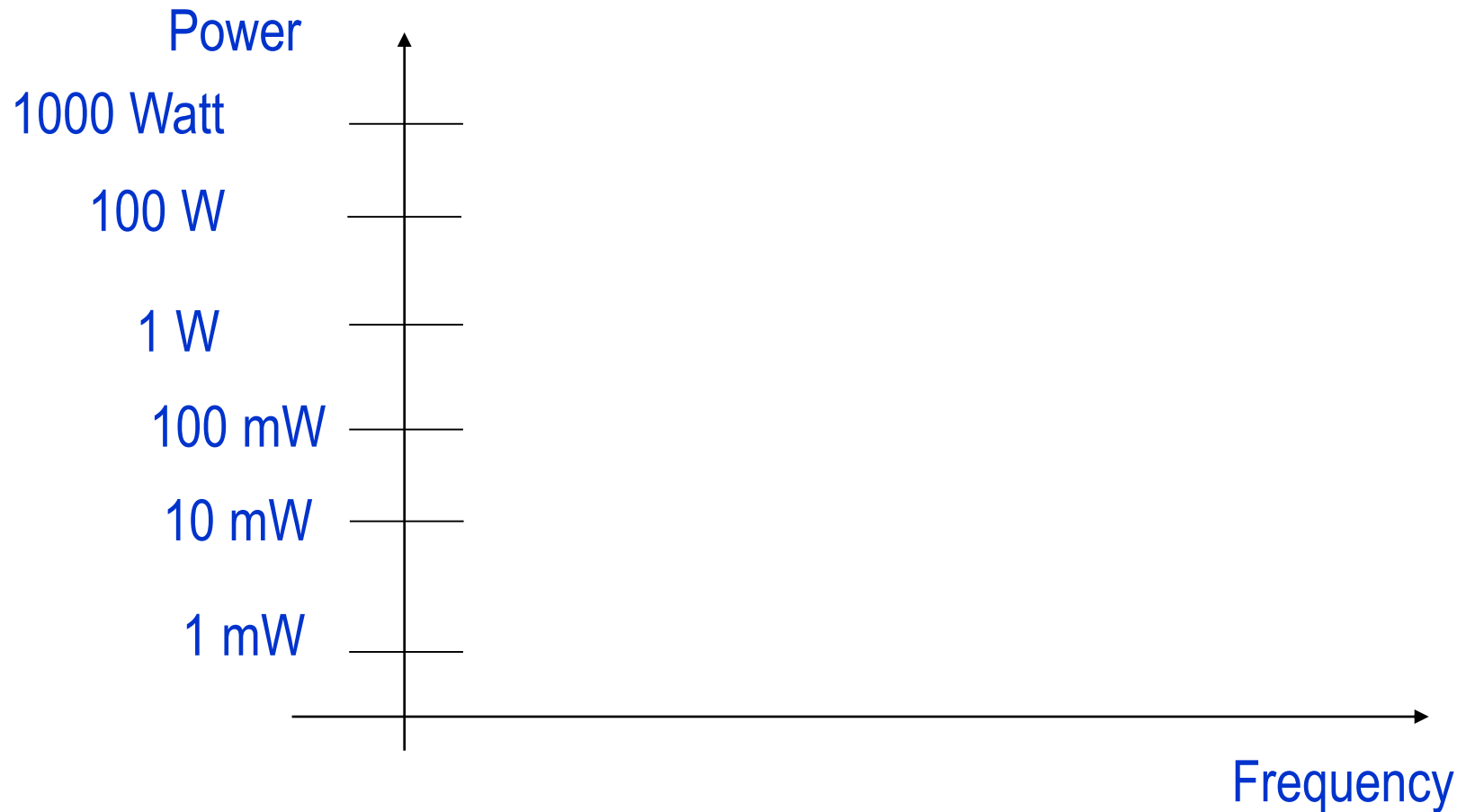
## EMI ISSUES IN WIRELESS DEVICES



- Numerous interference cases reported over the ISM band 2400 – 2483.5 MHz.
- From Cisco, « 20 Myths of WiFi Interference », White Paper, 2008:
  - “Interference contributes to 50 % of the problems on the customer’s Wi-Fi network. “
  - “In a recent survey of 300 of their customers, a major Wi-Fi tools provider reported that “troubleshooting interference won ‘top honors’ as the biggest challenge in managing a Wi-Fi network.””
  - “67 percent of all residential Wi-Fi problems are linked to interfering devices, such as cordless phones, baby monitors, and microwave ovens.”
  - “At 8m, a microwave oven degrades data throughput by 64%.”

# Electromagnetic Interference

## ■ Wifi & Microwave



# Electronic Market Growth

GSMA<sup>®</sup>  
**Intelligence**

## TOTAL CELLULAR CONNECTIONS

Including licensed cellular IoT - Q1 2022

10 461 122 395

▲ 6.57%

## UNIQUE MOBILE SUBSCRIBERS

Q1 2022

5 298 158 087

▲ 1.74%

## ARPU/MONTH

FY 2020/21

\$8.08

▼ -0.12%

SIX YEARS AGO... (OCT. 2016)

## GLOBAL DATA

Mobile connections, including M2M  
Oct 2016

7,802,658,518

▲ 4.70%

Unique mobile subscribers  
Oct 2016

4,752,110,923

▲ 4.76%

Revenue/year  
FY 2015

\$1.06T

▲ 2.18%

ARPU/month  
FY 2015

\$10.25

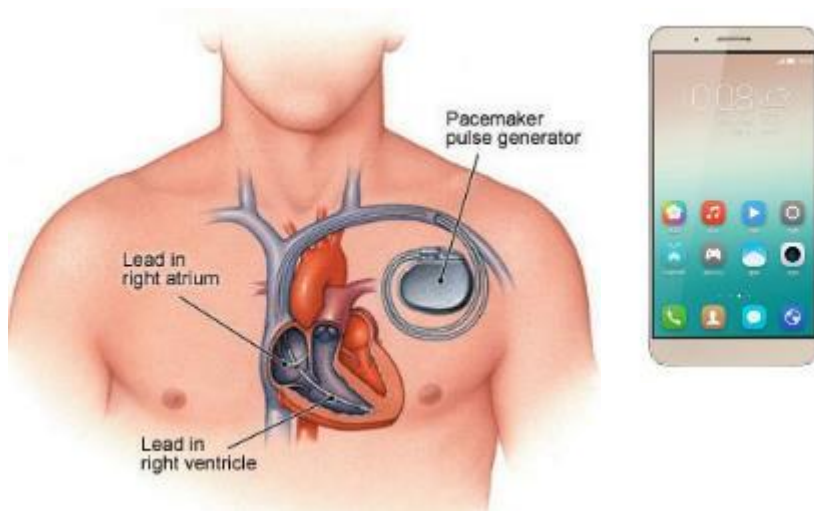
▼ -2.78%

# Electromagnetic Interference

## EMI ISSUES IN MEDICAL DEVICES

*Interference Technology –  
June 2015*

**interference**<sup>ITEM™</sup>  
THE INTERNATIONAL JOURNAL OF  
ELECTROMAGNETIC COMPATIBILITY | **technology**



“Pacemakers can mistakenly detect electromagnetic interference (EMI) from smartphones as a cardiac signal, causing them to briefly stop working. This leads to a pause in the cardiac rhythm of the pacing dependent patient and may result in syncope.” Dr. Lennerz

“For implantable cardioverter defibrillators (ICDs) the external signal mimics a life threatening ventricular tachyarrhythmia, leading the ICD to deliver a painful shock” Dr. Lennerz

<http://www.interferencetechnology.com>

# Electromagnetic Interference

## EMI ISSUES IN AVIATION



*Interference Technology –  
January 2013*

FAA said Wi-Fi systems may interfere with the Honeywell phase 3 display units aboard 157 Boeing airplanes in use by various U.S. airlines. These display units are critical for flight safety, providing crewmembers with information such as airspeed, altitude, heading, and pitch and roll [...] the issue was discovered two years ago during testing to certify a Wi-Fi system for use on Boeing 737 Next Generation.





# Electromagnetic Interference

## EMI ISSUES IN AUTOMOTIVE

<http://incompliancemag.com/2-12-million-vehicles-recalled-for-airbag-issues>

*In Compliance, 2015*

### IN COMPLIANCE

## 2.12 Million Vehicles Recalled For Airbag Issues

POSTED BY IN COMPLIANCE NEWS ON FEBRUARY 2, 2015 IN ENGINEERING NEWS, PRODUCT RECALLS | [LEAVE A RESPONSE](#)

The National Highway Traffic Safety Administration (NHTSA) announced this weekend that Chrysler, Honda, and Toyota are recalling 2.12 million cars because a previous attempt to resolve an issue with faulty electrical components in airbags does not completely solve the problem. The new recalls include the following models from the early 2000s: Acura MDX, Dodge Viper, Jeep Grand Cherokee and Liberty, Honda Odyssey, Pontiac Vibe, Toyota Corolla, Toyota Matrix and Toyota Avalon.



# Electromagnetic Interference

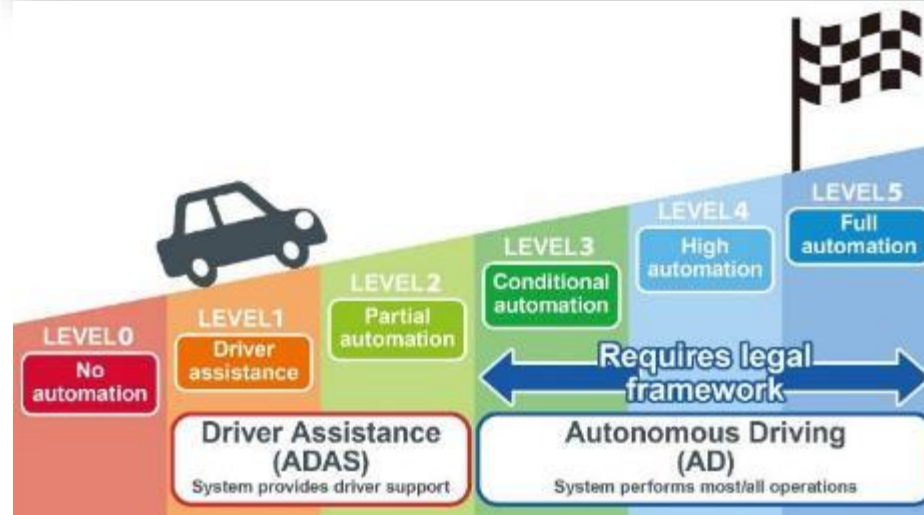
## EMI ISSUES IN AUTOMOTIVE

- ADAS - Advanced Driver Assistance Systems in 2020
- AD - Autonomous driving in 2030
- Much more sensors, cameras, embedded calculators & security

VISIONS FOR VEHICLE MOTION AND SAFETY



Image Sensor Systems

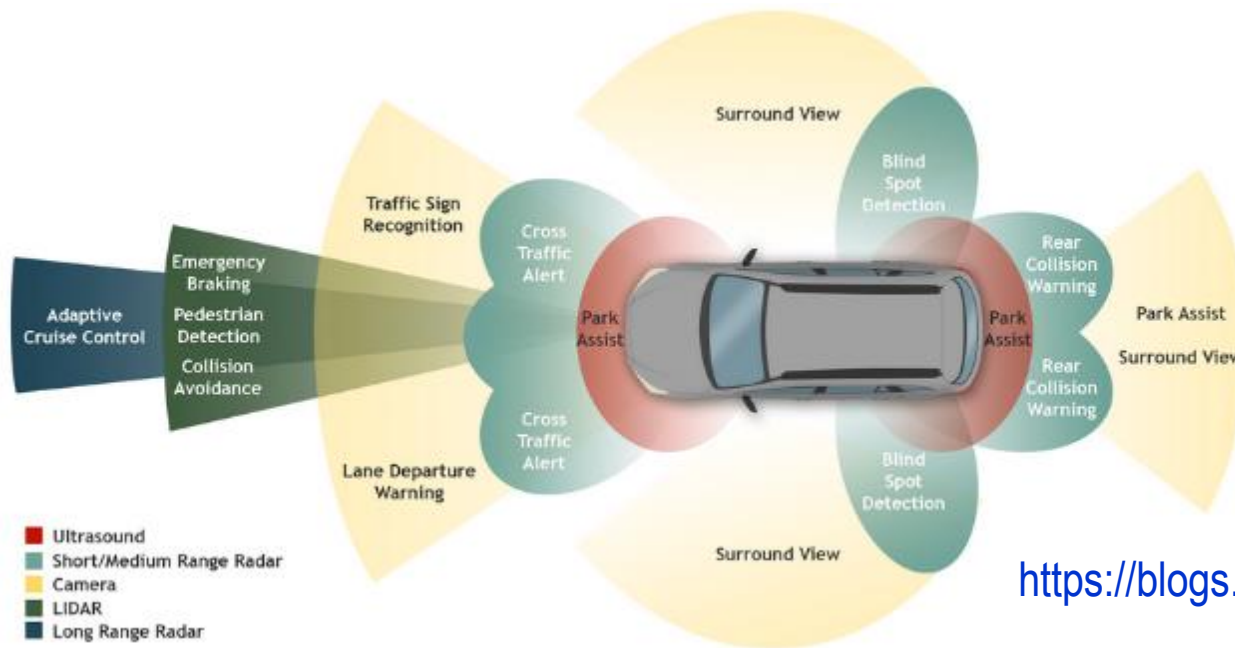


# Electromagnetic Interference

## ■ EMI ISSUES IN AUTOMOTIVE

ADAS automobile : 100 million lines of software code, 100 microprocessor-based electronic control units (ECUs) networked throughout the body of the car.

ISP (image signal processor), VPU (video processing unit), PVA (programmable vision accelerator), DLA (deep learning accelerator), CUDA GPU, and CPU

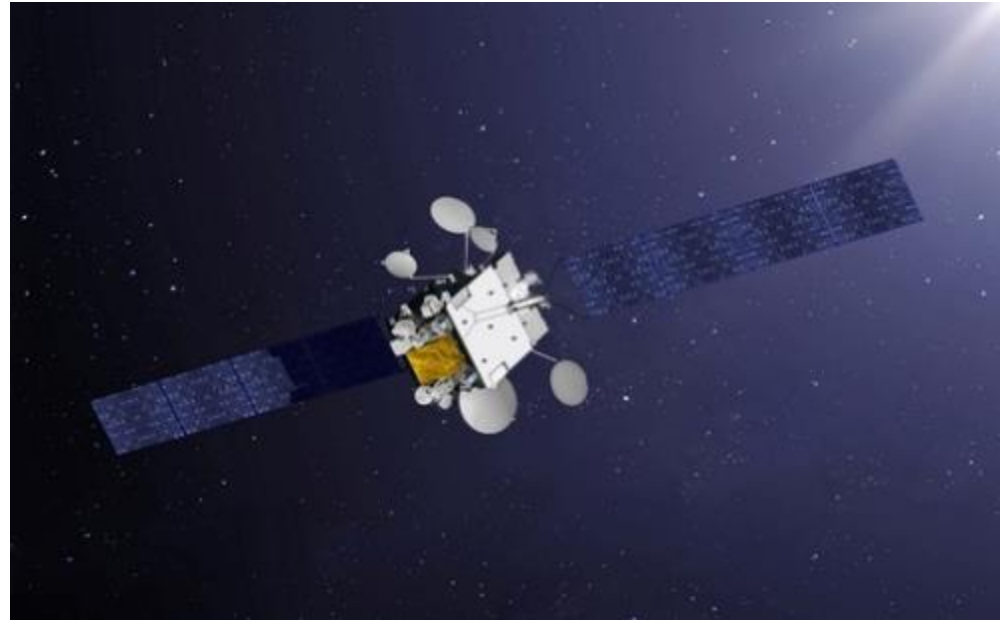


<https://blogs.nvidia.com/blog/2018/05/23/xavier-architected-for-safety/>

# Electromagnetic Interference

## Lancement réussi pour Syracuse 4A, un satellite militaire de dernière génération

- 25/10/2021 - “Maîtriser l’espace est essentiel pour la souveraineté de notre défense et la sécurité nationale. Encore faut-il savoir **se défendre**, à des milliers de kilomètres au-dessus de nos têtes. Aussi, le satellite est muni de dispositifs de surveillance pour détecter l’approche de débris ou de **satellites « butineurs »**, qui viendraient se placer dans le rayon d’émission pour tenter de capter les communications. Surtout, Syracuse 4A est doté d’une meilleure **résistance au brouillage, à l’interception** et aux attaques cyber. »



<https://www.defense.gouv.fr/portail/actualites2/lancement-reussi-pour-syracuse-4a-un-satellite-militaire-de-derniere-generation>



# Electromagnetic Interference

## ■ EMC JAMMING

“criminals, rogue employees and even otherwise law-abiding citizens are using illegal “jamming” devices to overpower GPS, cellphone and other electronic signals in localized areas.”



<https://interferencetechnology.com/gps-interference-attack/>

# What is EMC ?

## DEFINITION

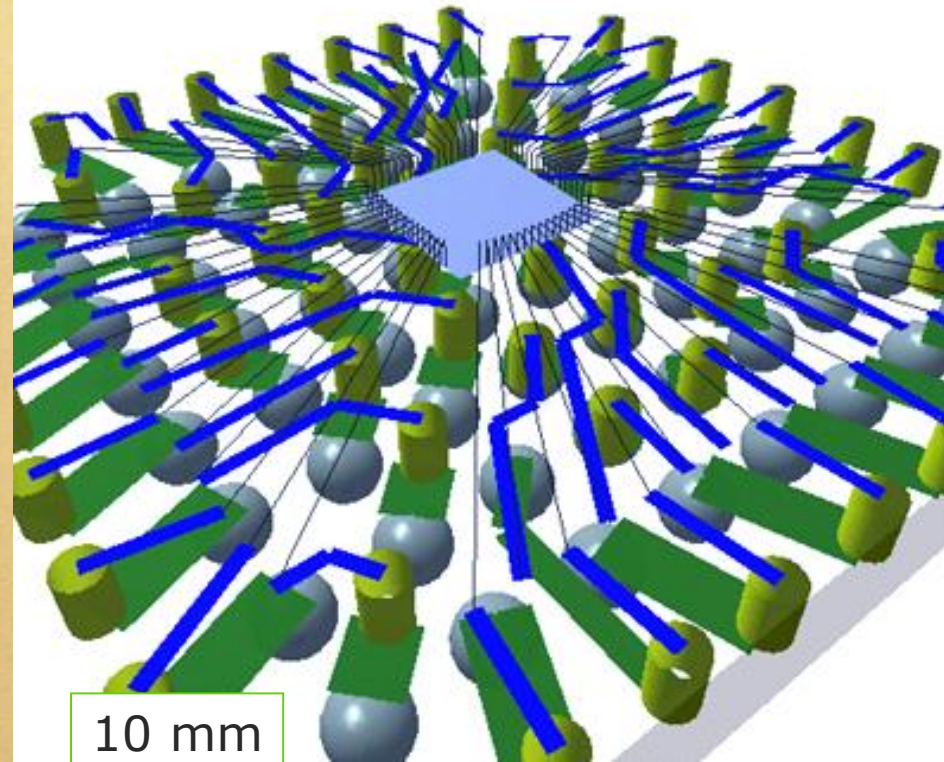
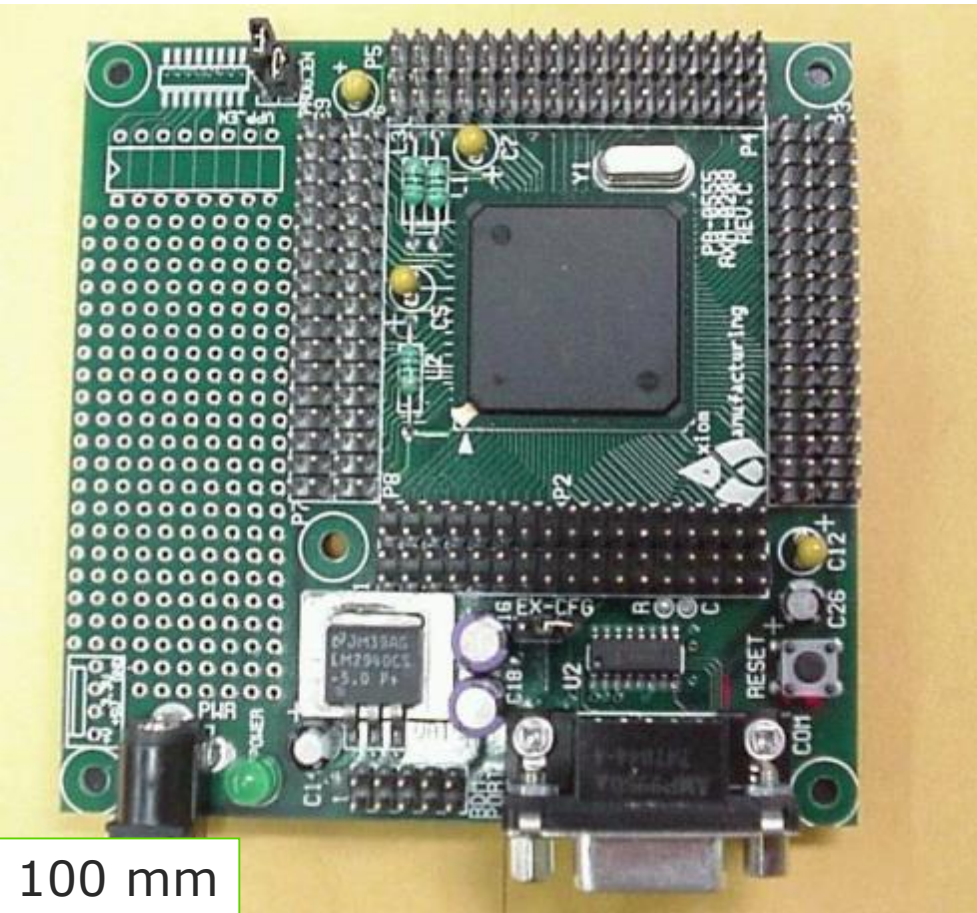
« The ability of a component, equipment or system to operate satisfyingly in a given electromagnetic environment, without introducing any harmful electromagnetic disturbances to all systems placed in this environment. »

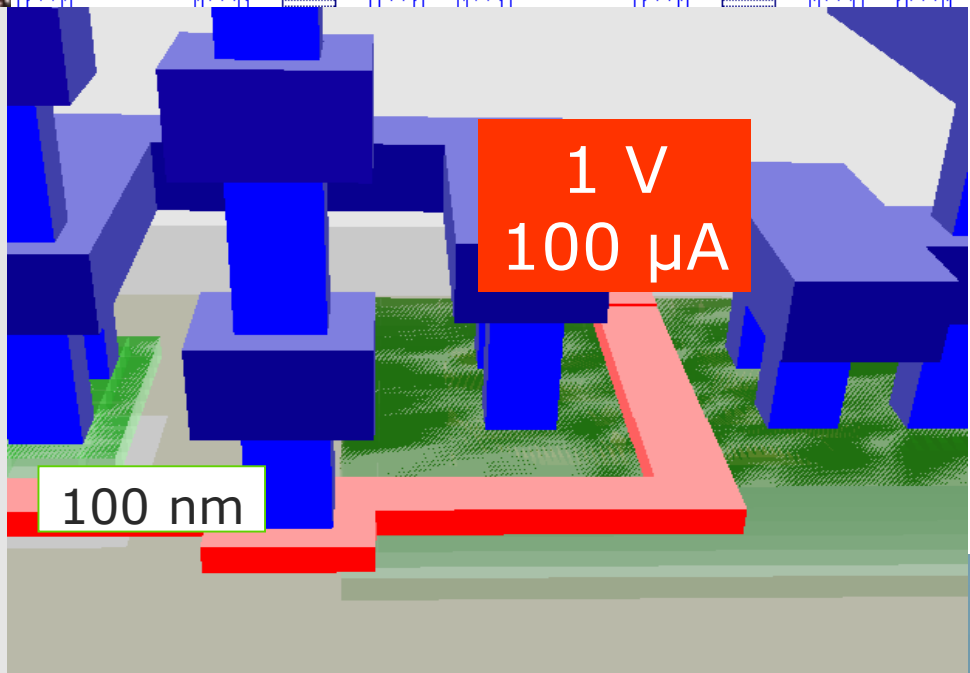
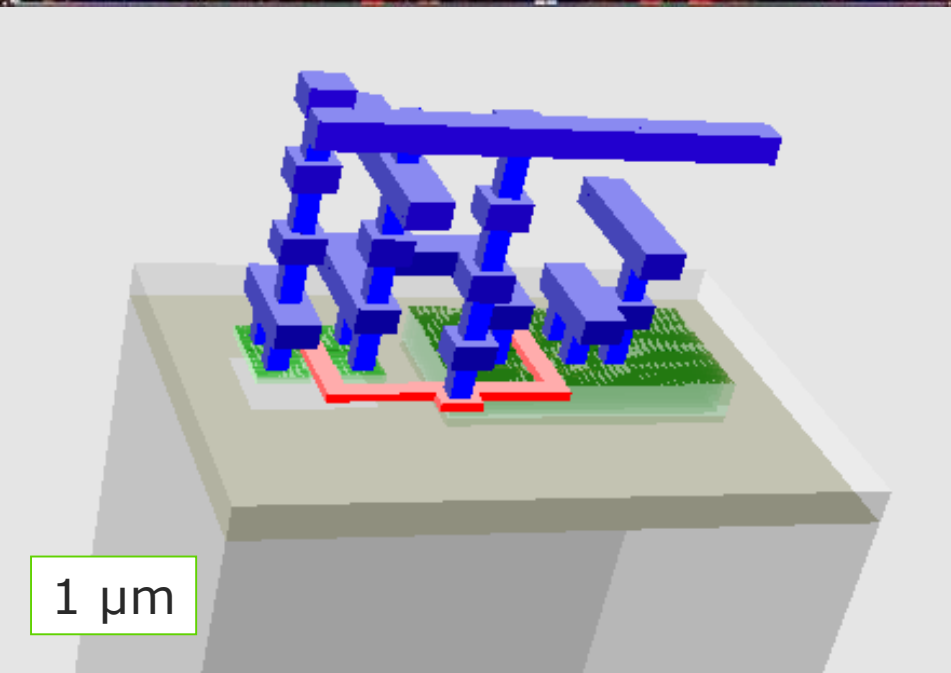
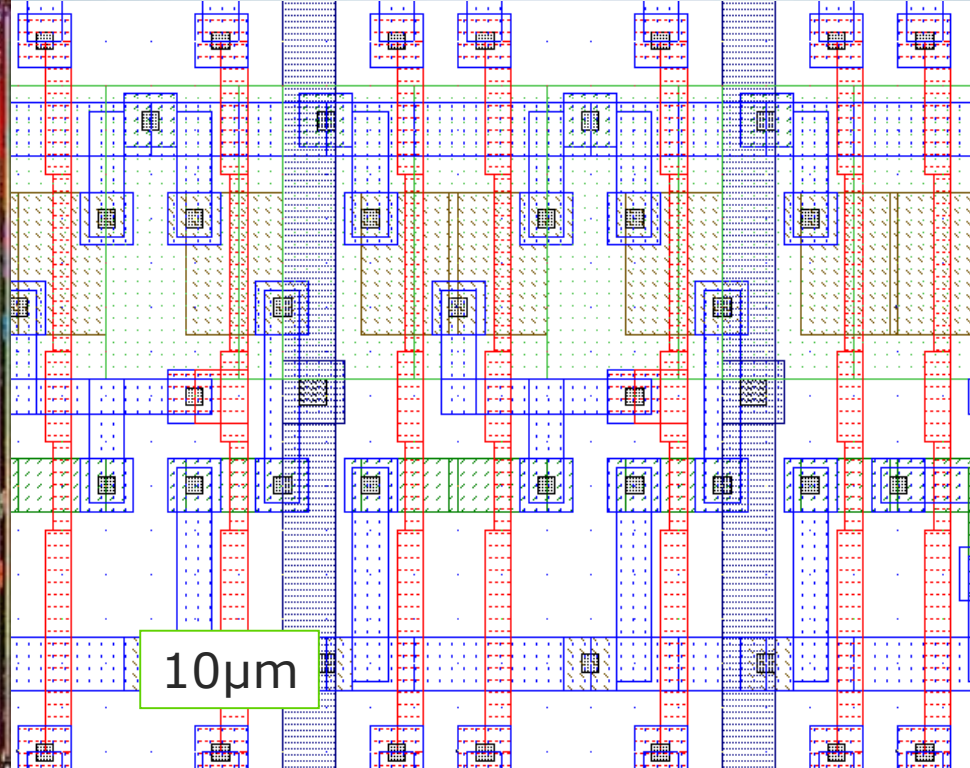
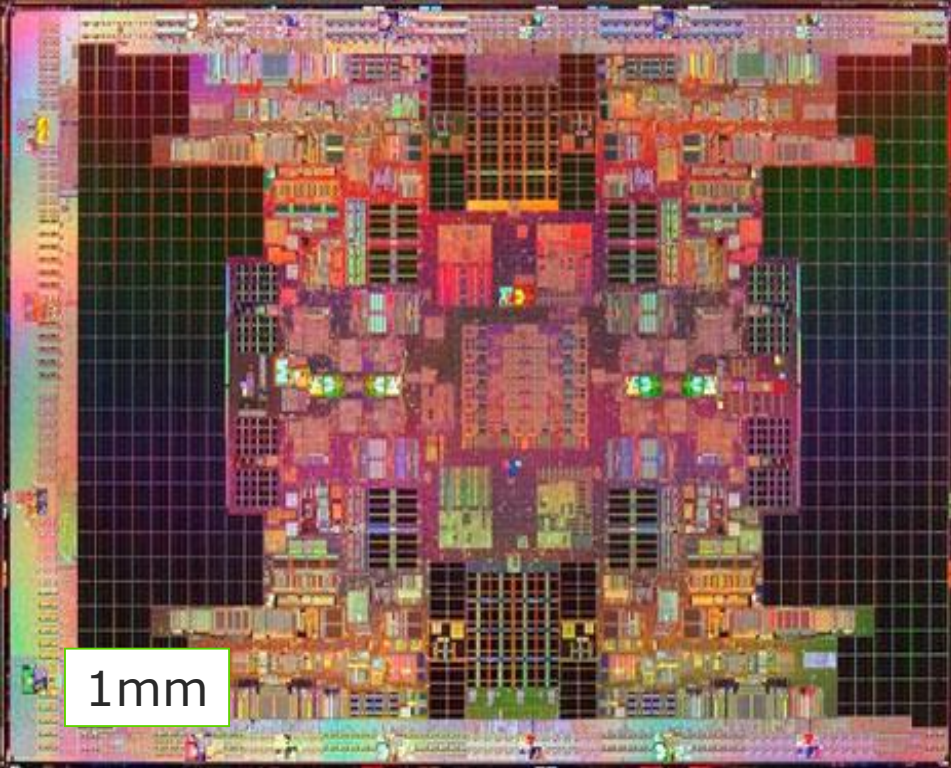
- ✓ Essential constraint to ensure functional safety of electronic or electrical applications
- ✓ Guarantee the simultaneous operation of every electrical or electronic equipment in a given electromagnetic environment
- ✓ Reduce both the parasitic electromagnetic emission and the sensitivity or susceptibility to electromagnetic interferences.



# What is EMC?

## ZOOM AT DEVICES



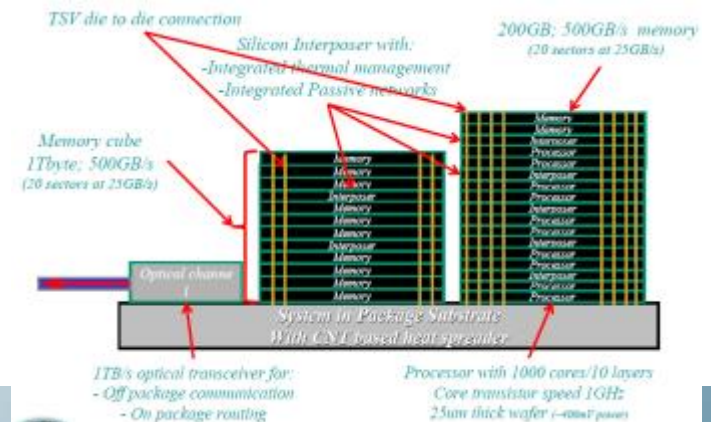
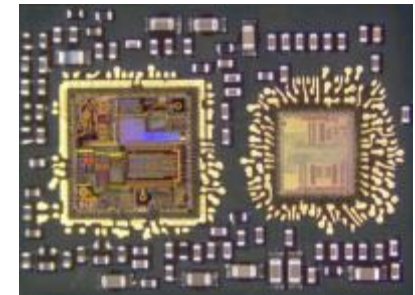
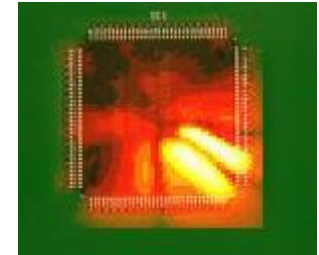




# What is EMC?

## WHY EMC OF IC ?

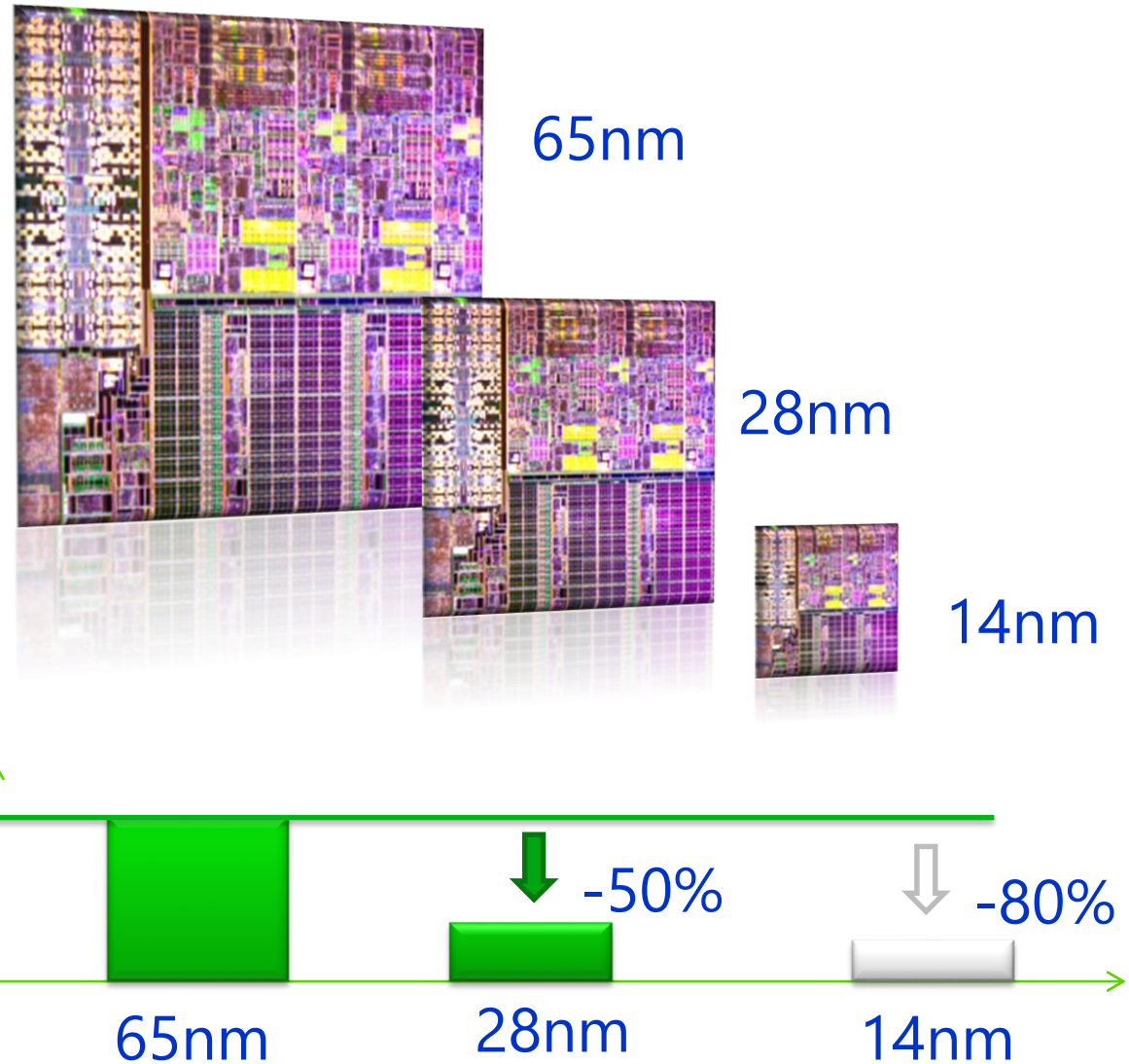
- Until mid 90's, IC designers had no consideration about EMC problems in their design..
- Starting 1996, automotive customers started to select ICs on EMC criteria
- Starting 2005, mobile industry required EMC in System in package
- Massive 3D integration will require careful EMC design



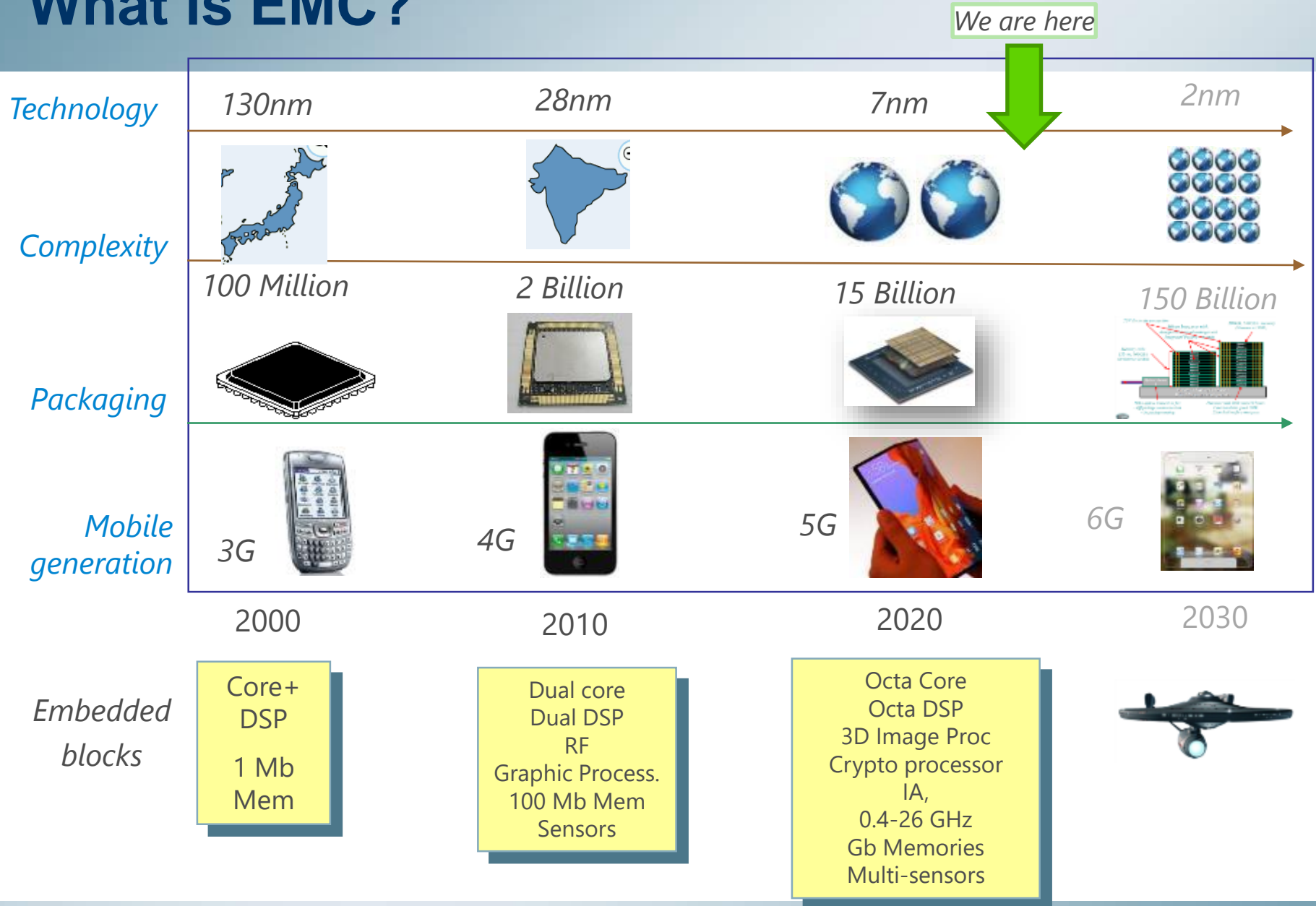
# Technology scale down

## Scale down benefits

- ..
- ...
- ...

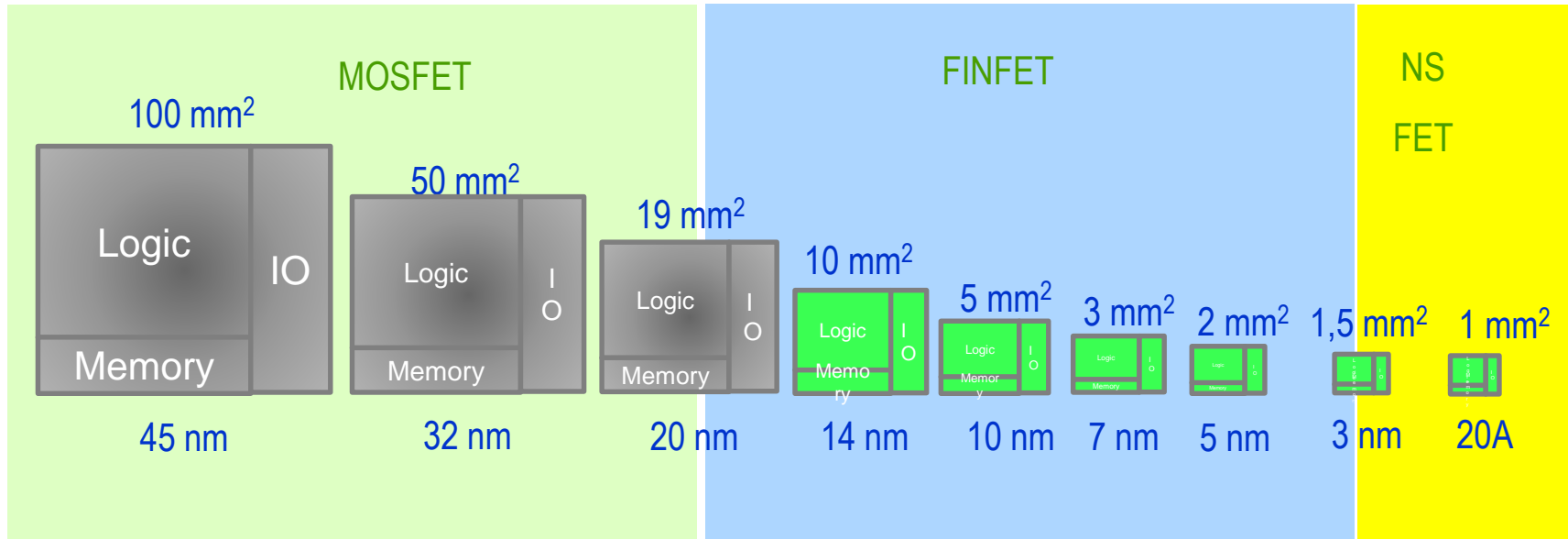


# What is EMC?



# Technology scale down

## ■ Drastic reduction of the silicon area



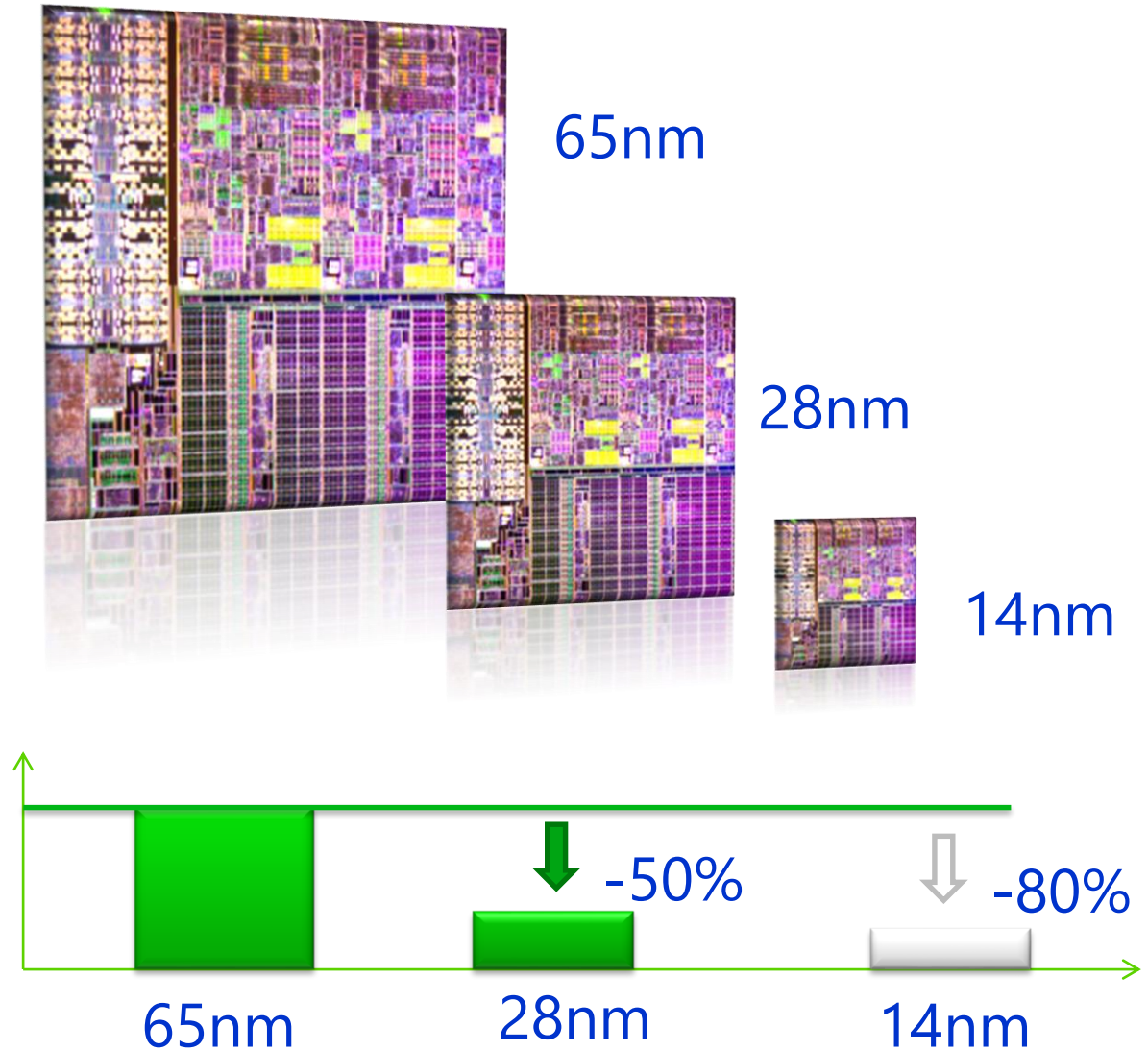
*Adapted from Mistry, K. (2017). 10 nm technology leadership, Technology and Manufacturing Day, Intel. 2017.*



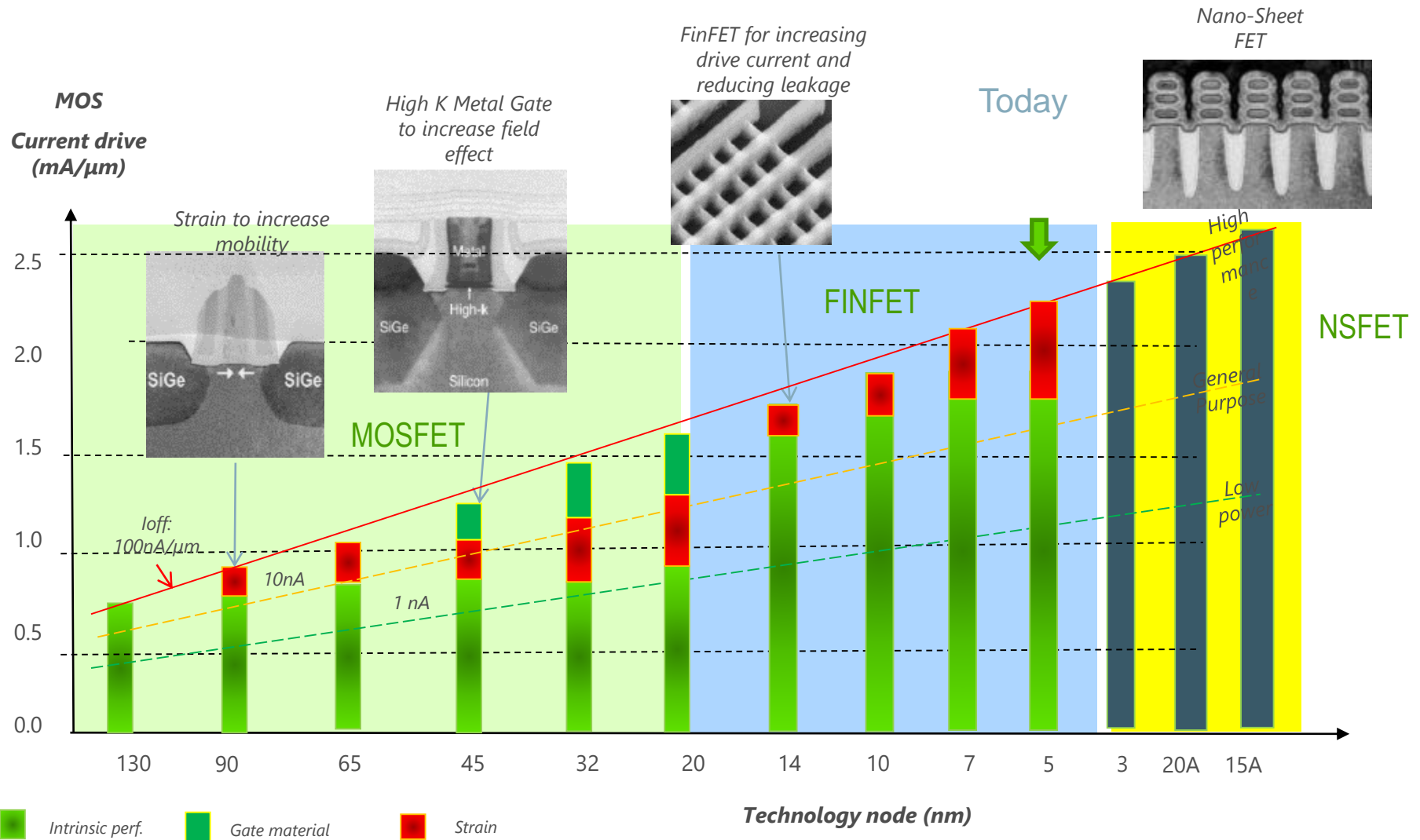
# Technology scale down

## Scale down benefits

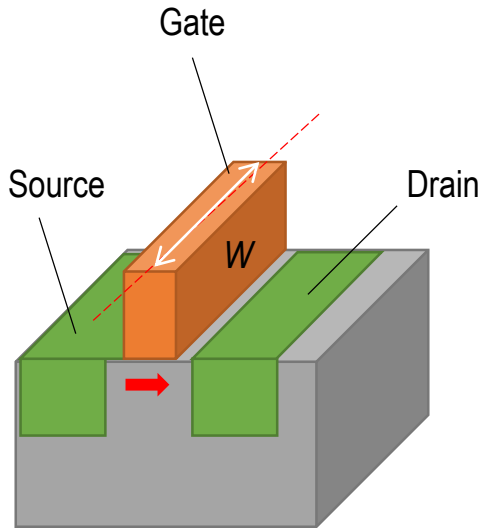
- ..
- ...
- ...



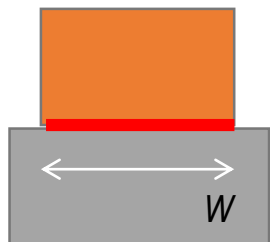
# Technology scale down



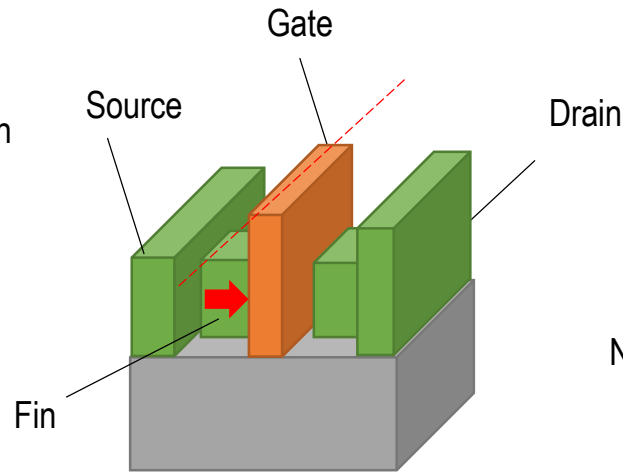
# Technology scale down



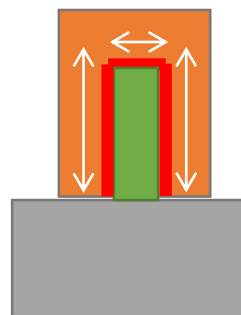
MOS FET



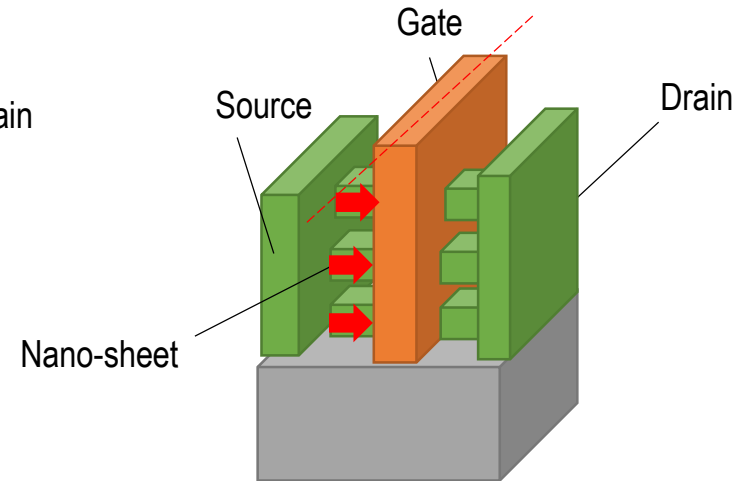
$$W_{eq} = W$$



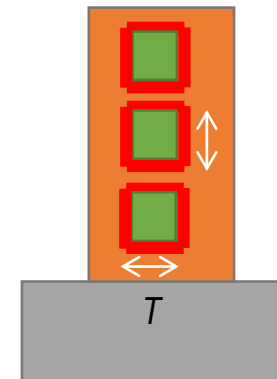
Fin FET



$$W_{eq} = 2H + T$$



Nano-Sheet FET



$$W_{eq} = 6H + 6T$$

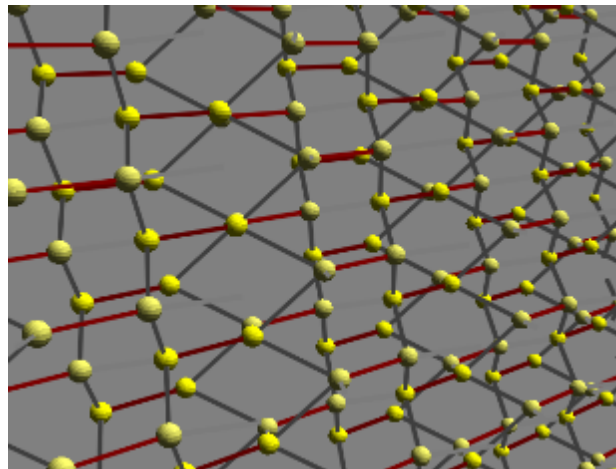
# Technology scale down



*TSMC 3-nm A16 Apple processor*



*Samsung 3-nm Qualcomm  
Snapdragon 898*



Si lattice: \_\_\_\_ nm

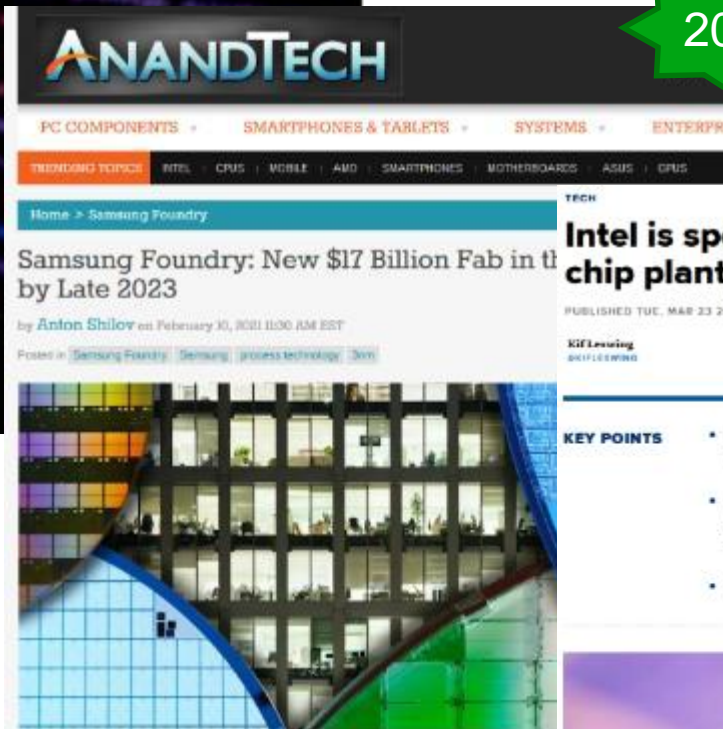


# Technology scale down

## TSMC to build a \$12 billion advanced semiconductor plant in Arizona with US government support

Catherine Shu @catherineshu / 5:22 AM GMT+2 • May 15, 2020

2020



2021

## Intel is spending \$20 billion to build two new chip plants in Arizona

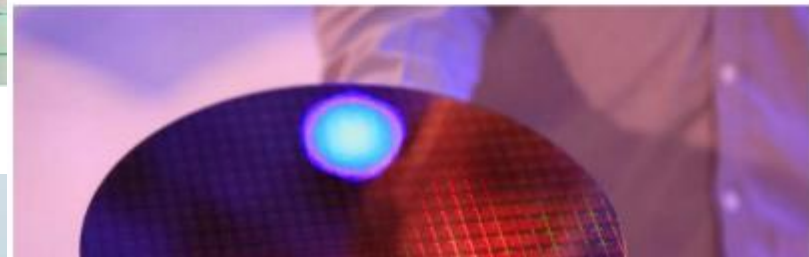
PUBLISHED TUE, MAR 23 2021 4:58 PM EDT | UPDATED WED, MAR 24 2021 7:38 AM EDT

Kyle Newing  
@KYLENEWING

SHARES f t in e

### KEY POINTS

- Intel announced on Tuesday that it will spend \$20 billion to build two major factories in Arizona.
- The news comes amid a worldwide chip shortage that is snarling industries from automobiles to electronics and worries the U.S. is falling behind in semiconductor manufacturing.
- The announcement signals that Intel will continue to focus on manufacturing.

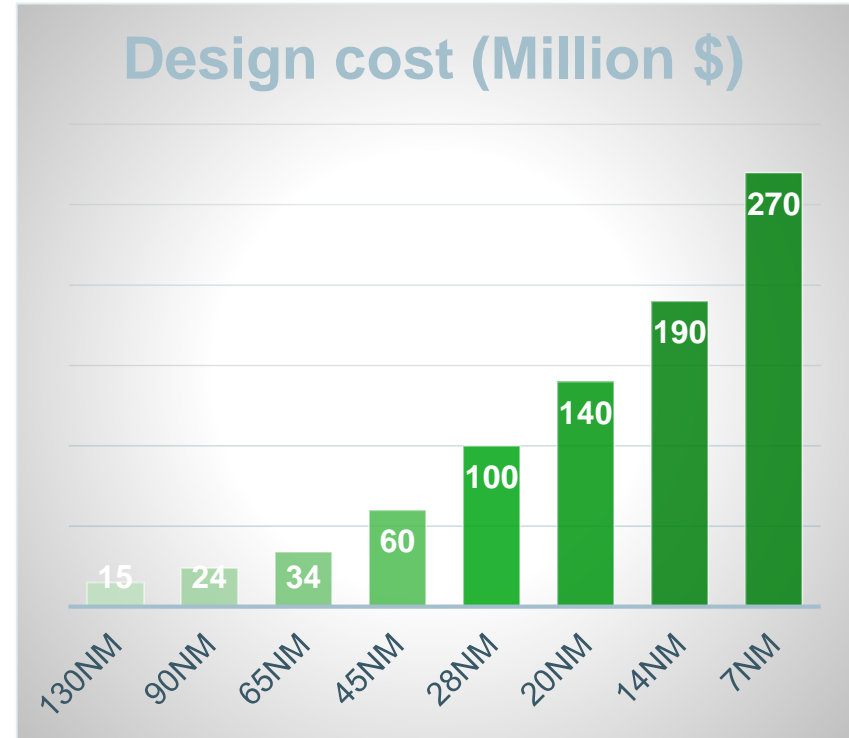
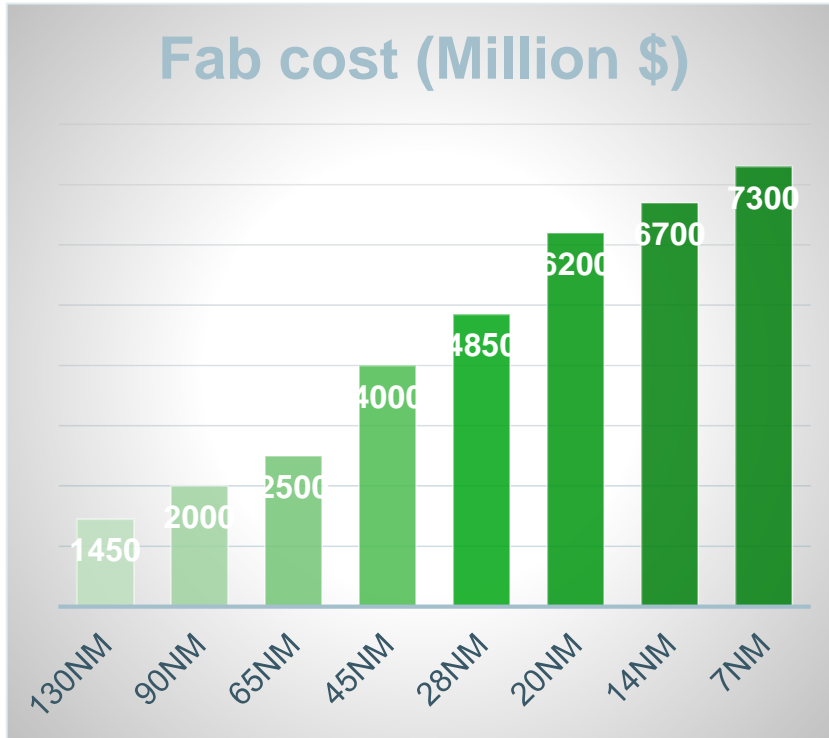


2021



# Technology scale down

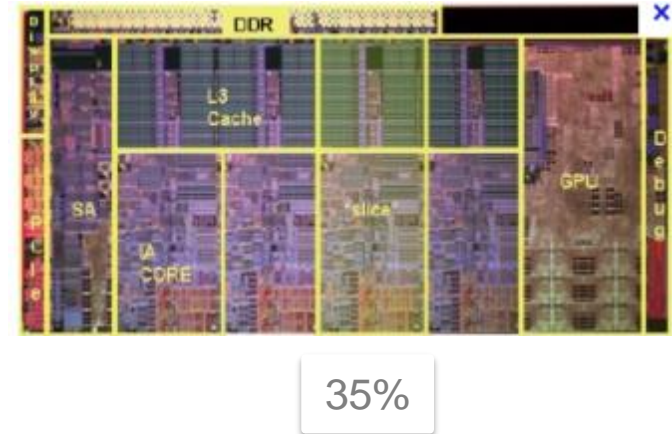
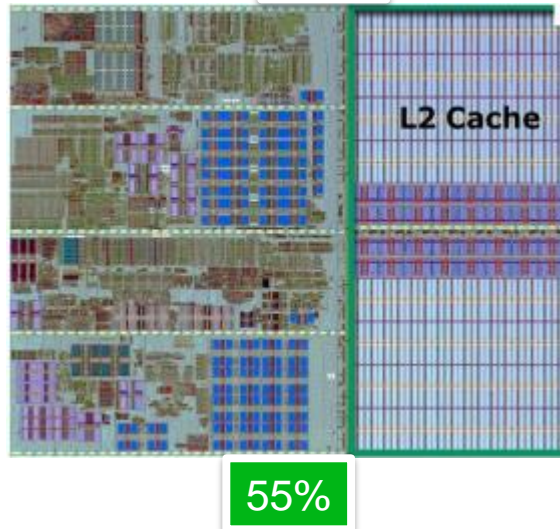
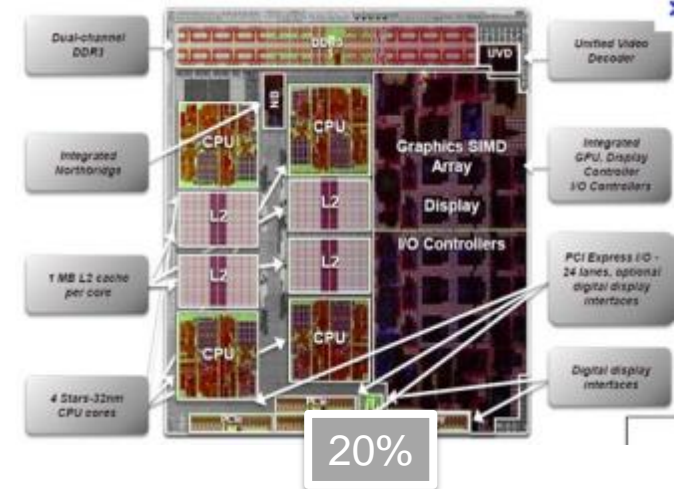
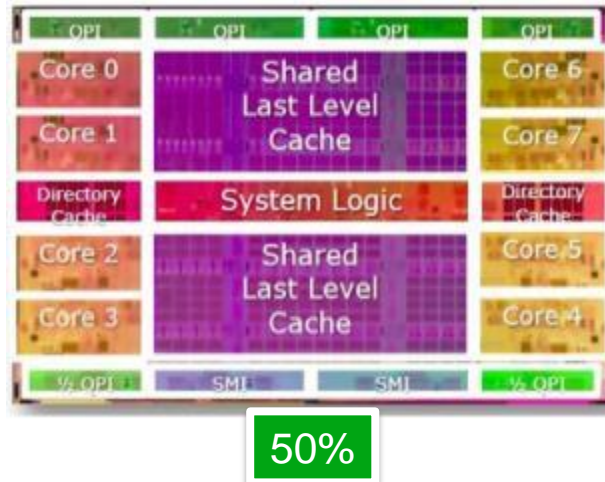
## ■ TECHNOLOGY INNOVATION & COST



- Strain, eSiGe,
- High-K, low-K dielectric, Airgap
- Metal gate
- FinFET/ Gate-All-Around FET
- Double, quad patterning

# Technology scale down

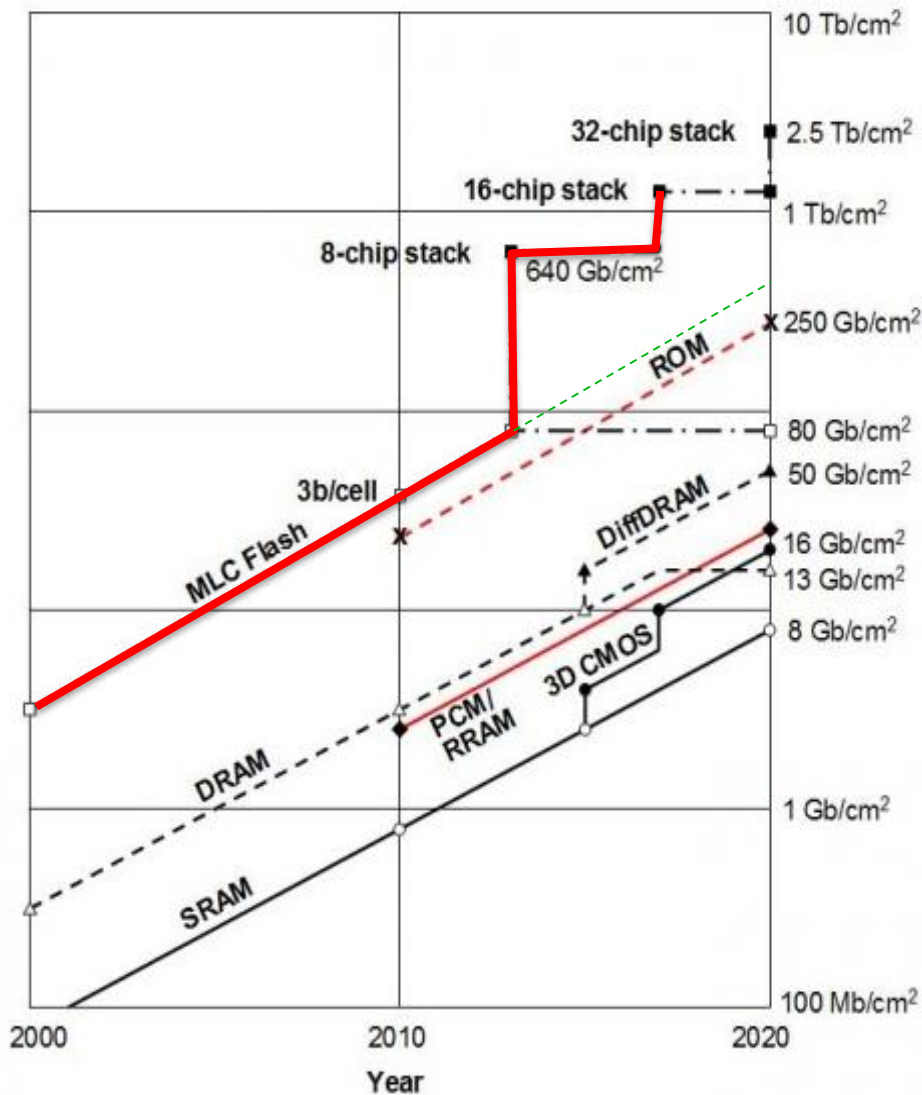
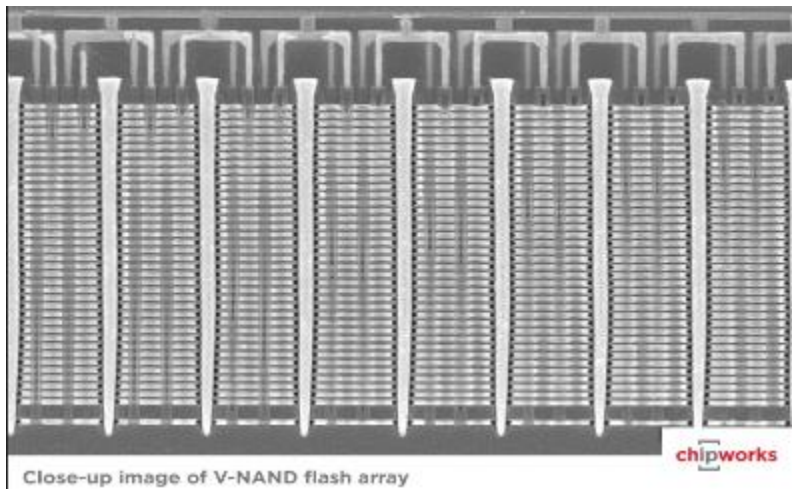
## IMPORTANCE OF MEMORY



# Going 3D

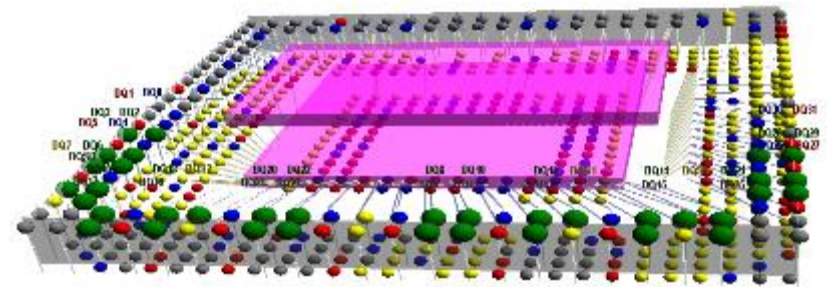
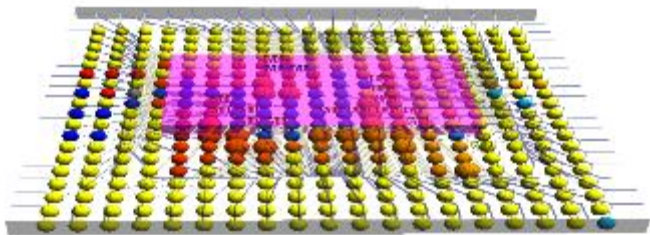
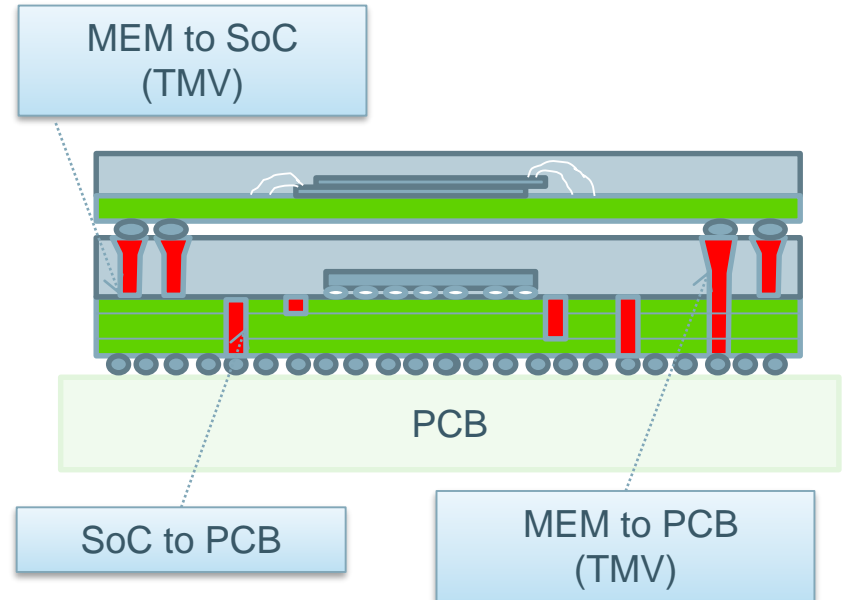
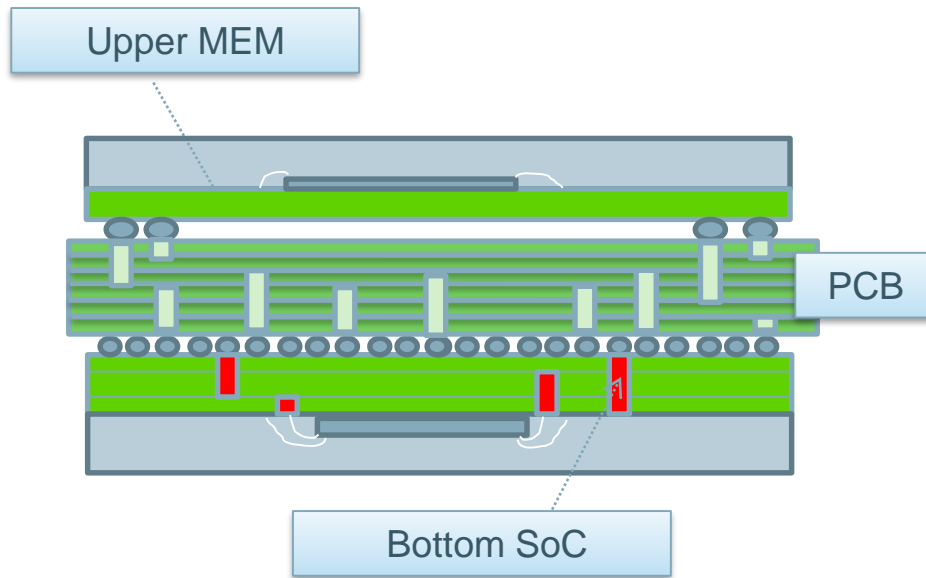
## Stacked process layers

- 8, 16, 32 layers of active devices
- 1 tera-bit/cm<sup>2</sup> achieved 5 years ahead from roadmaps



# Processor to memory

## Package-on-package (PoP)



*E. Sicard, EMC performance analysis of a Processor/Memory System using PCB and Package-On-Package, EMC Compo 2015 Edinburgh*

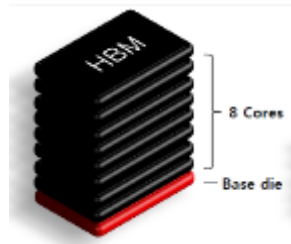


# Processor to memory



## ■ Increased memory/processor bandwidth

- High performance computing & AI
- Mobiles & high resolution games
- Servers & Security



High Performance  
Computing &  
Networking

*High Bandwidth  
Memory*



Mobile

*Low Power DDR5*



Graphics

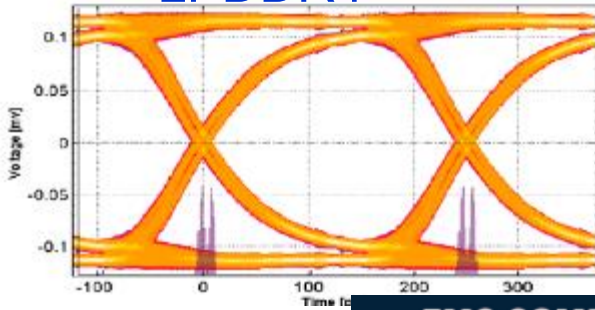
*Graphics DDR6*



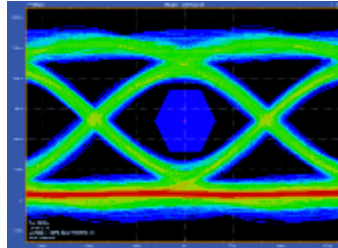


# Processor to memory

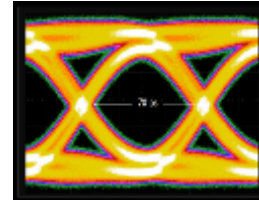
LPDDR4



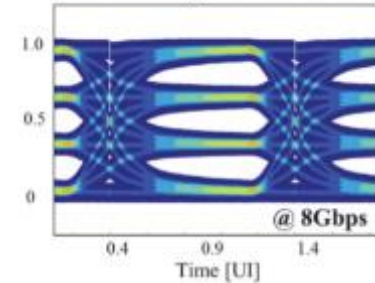
LPDDR5



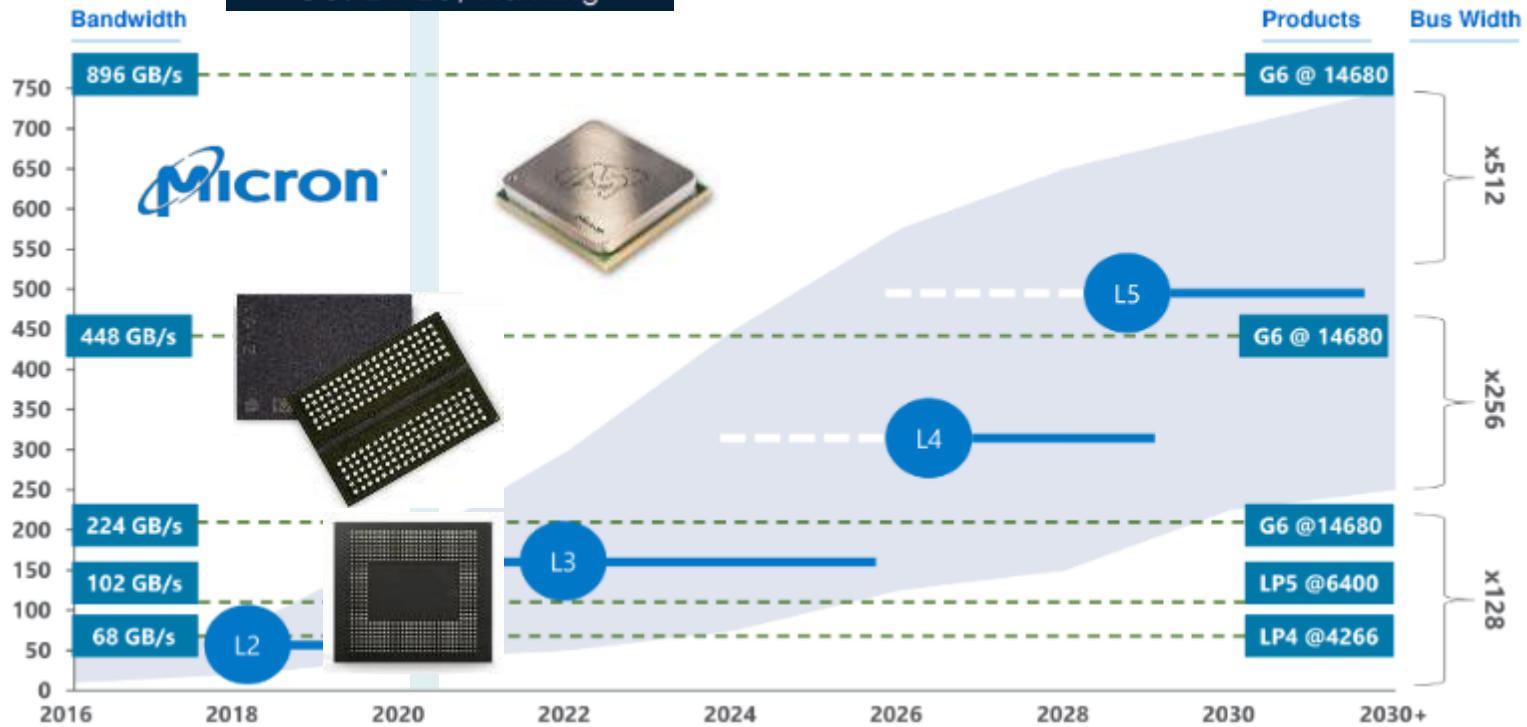
GDDR6



HMC



**EMC COMPO 2019**  
Oct 21-23, Haining

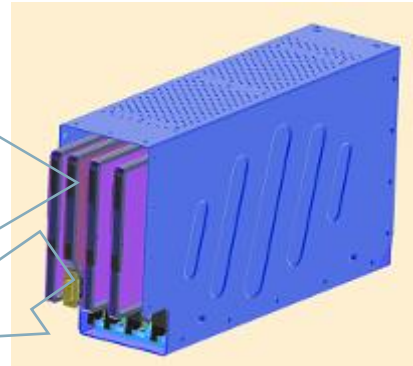


# EMC at IC Level

- SUSCEPTIBILITY**



Equipment



Boards



Radar



Components



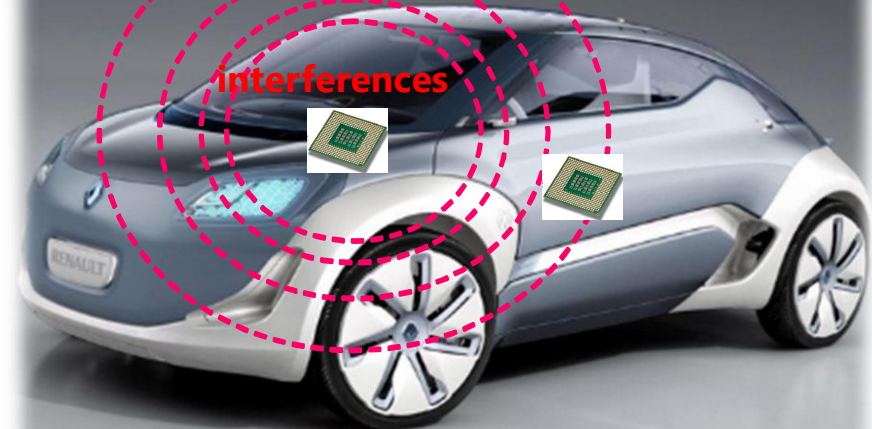
Hardware fault  
Software failure  
Function Loss

- EMISSION**

Personal  
Devices



Interferences

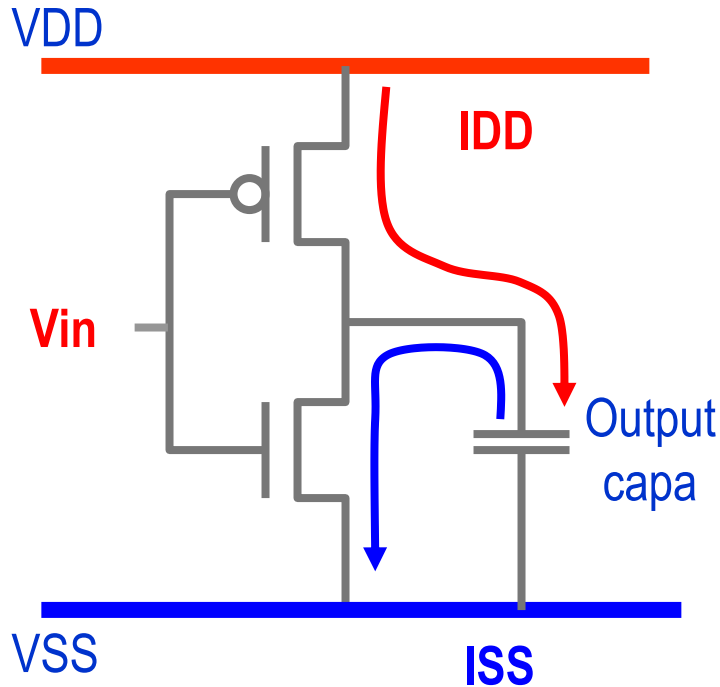


Safety  
systems



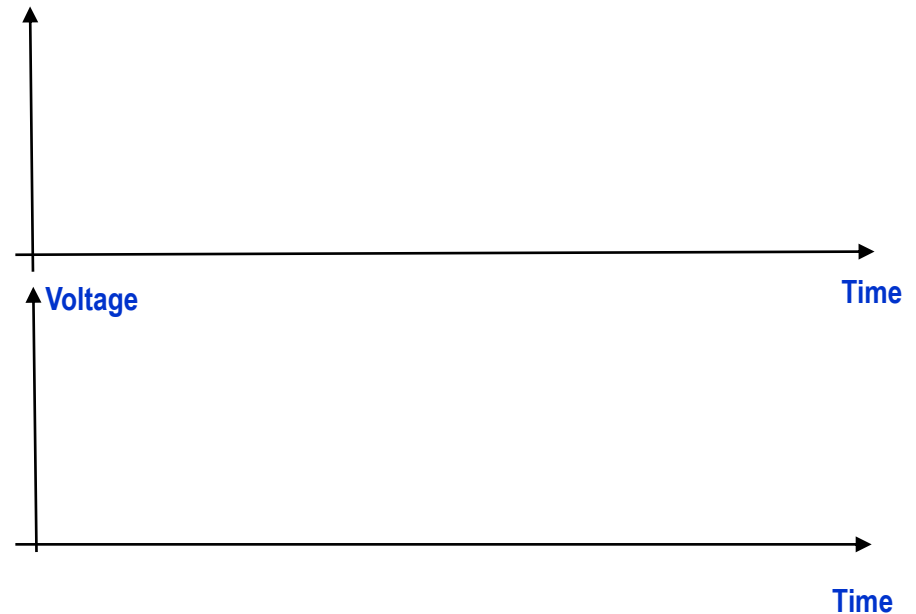
# Origin of Parasitic Emission

## BASIC MECHANISMS FOR CURRENT SWITCHING



CMOS inverter exemple

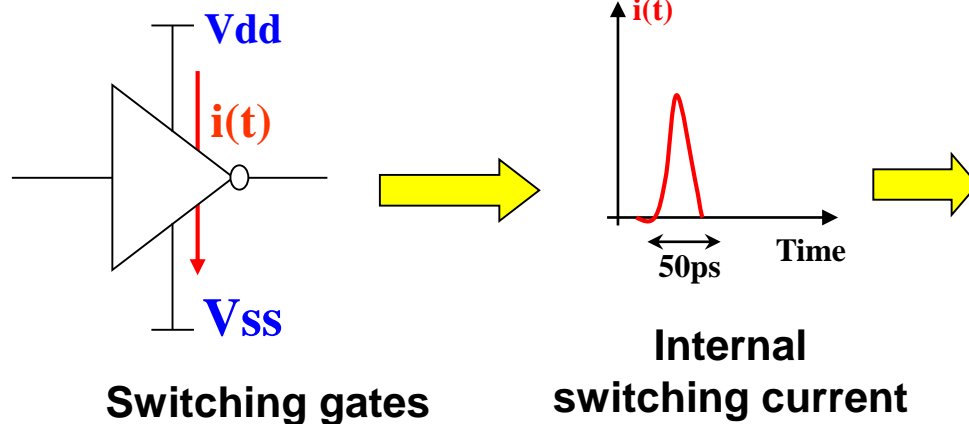
Switching current



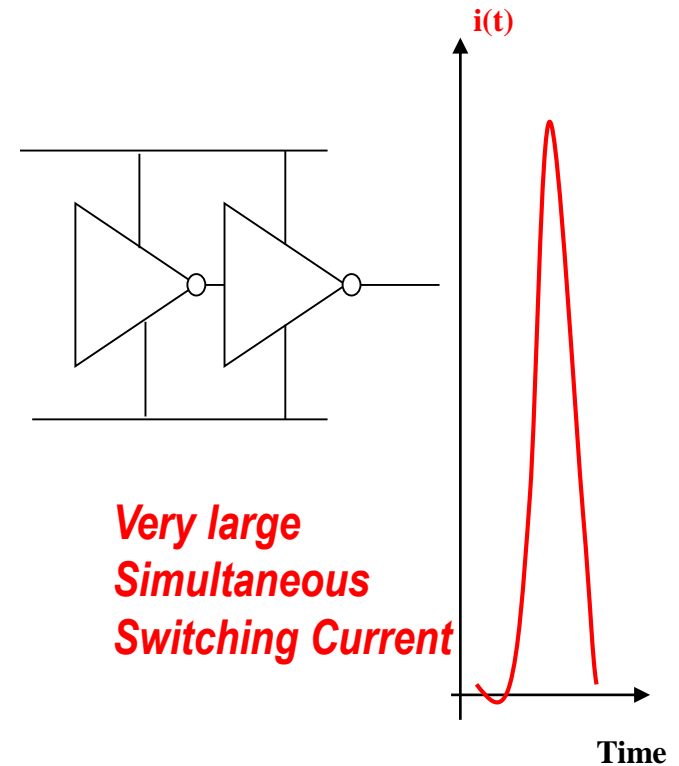
Question: waveform, amplitude?

# Origin of Parasitic Emission

## STRONGER SWITCHING CURRENT:

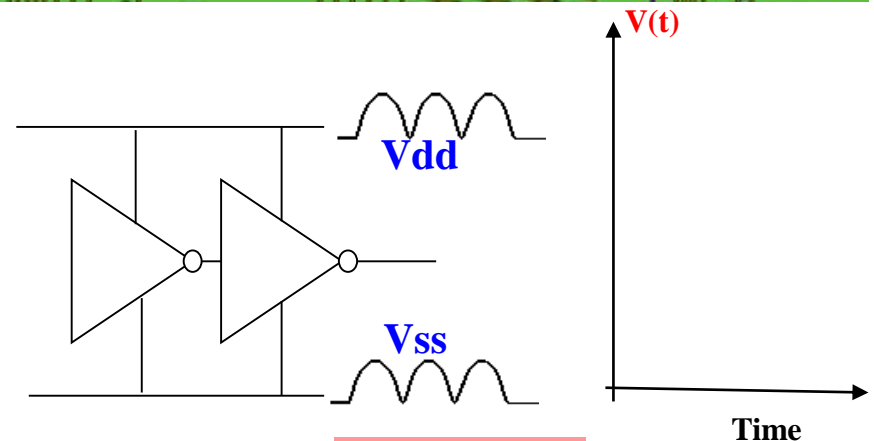
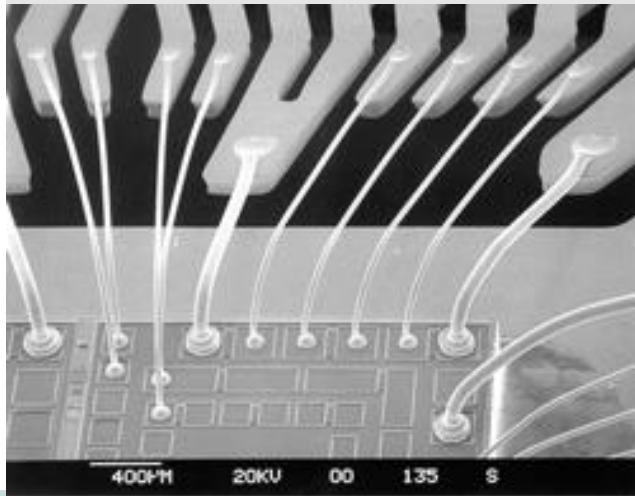
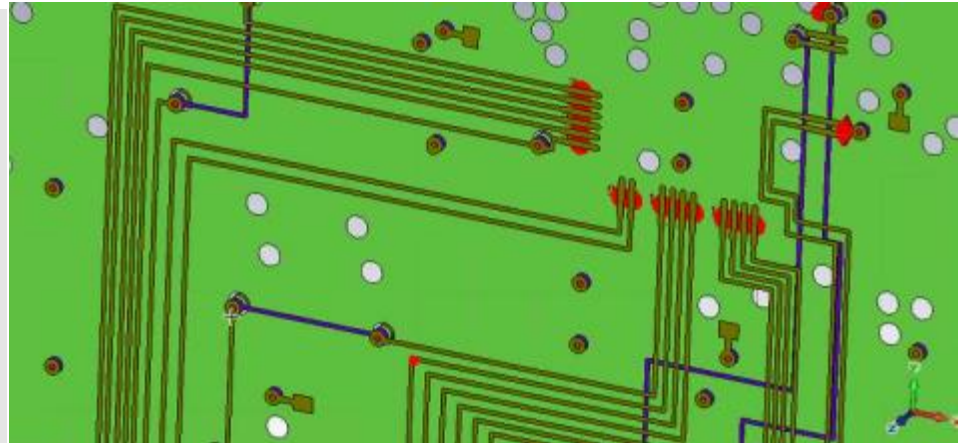
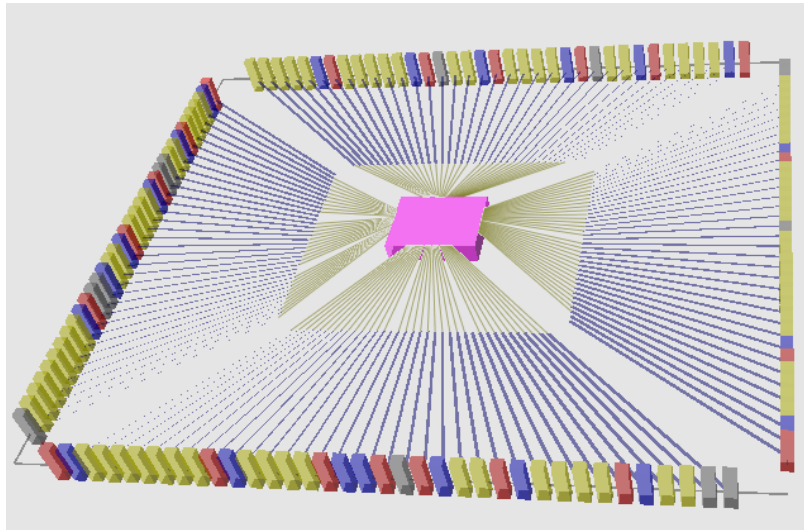


- ✓ Low power processor: 1A @ 100 MHz
- ✓ Medium power processor : 10 A @ 500 MHz
- ✓ High performance processor : 100 A @ 1 GHz



# Origin of Parasitic Emission

## Wires act as antennas



$$L = \_ nH / mm$$

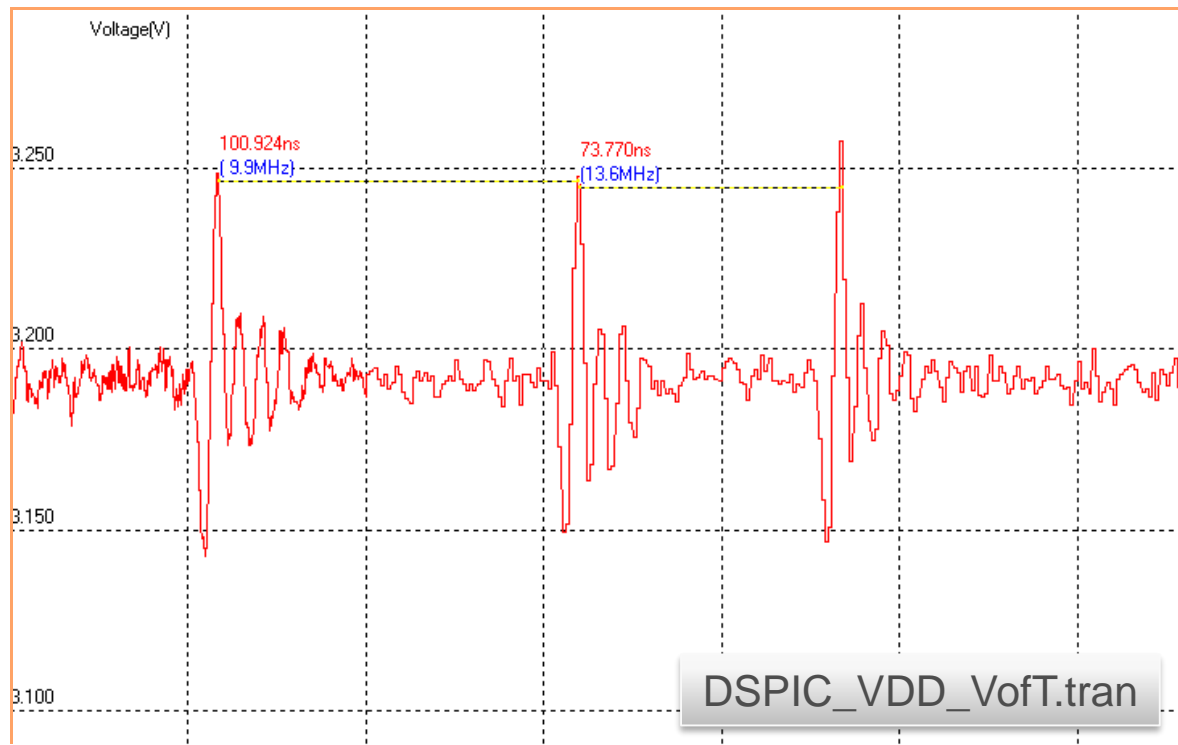
$$\Delta V = \_ -$$



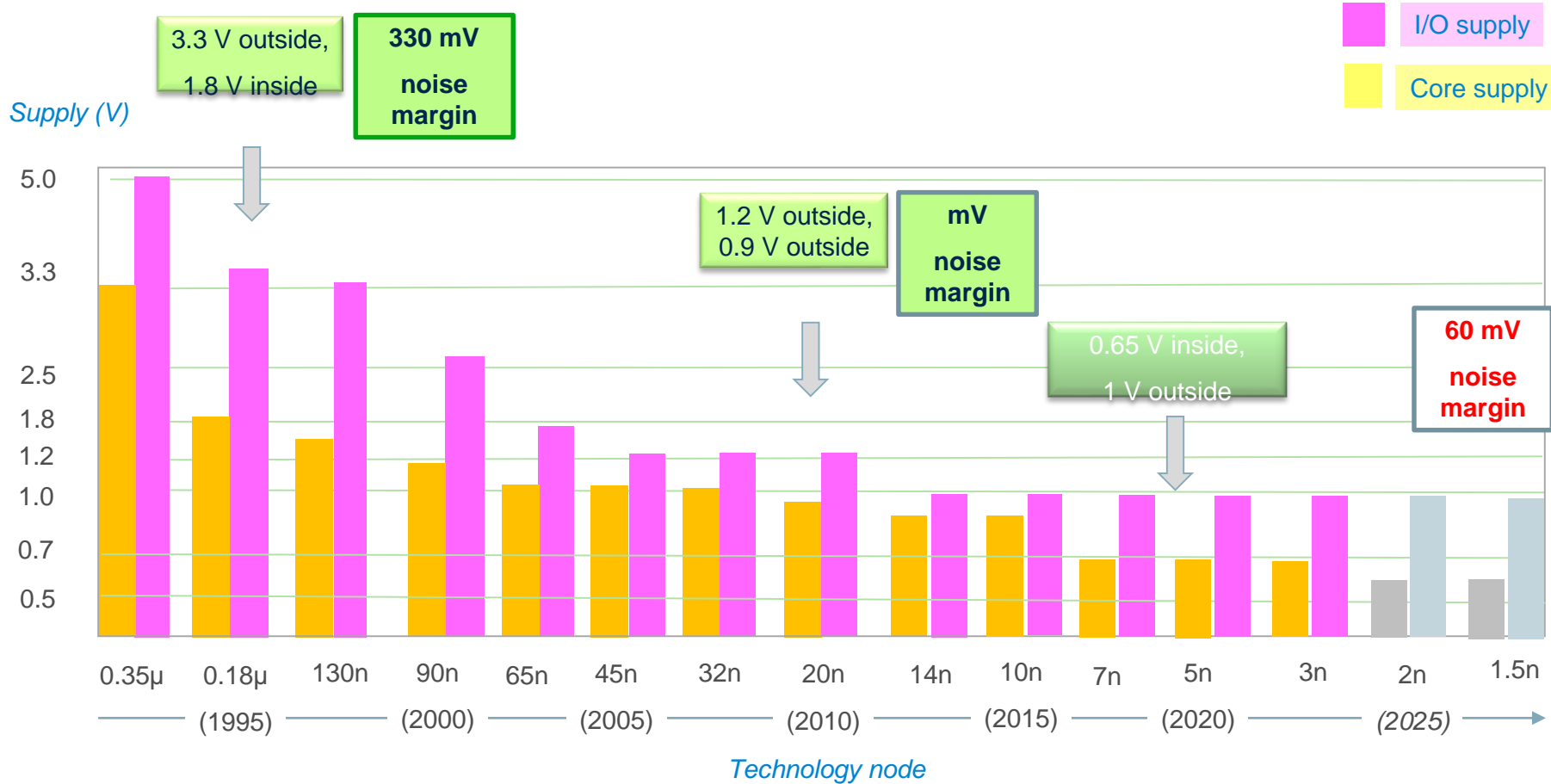
# Origin of Parasitic Emission

## WIRES+CURRENT = NOISE

- DSPIC33F noise measurement with active probe on X10
- Activation of the core by a 40 MHz internal PLL
- Synchronous ADDR0..15 bus switching 0x0000, 0xFFFF

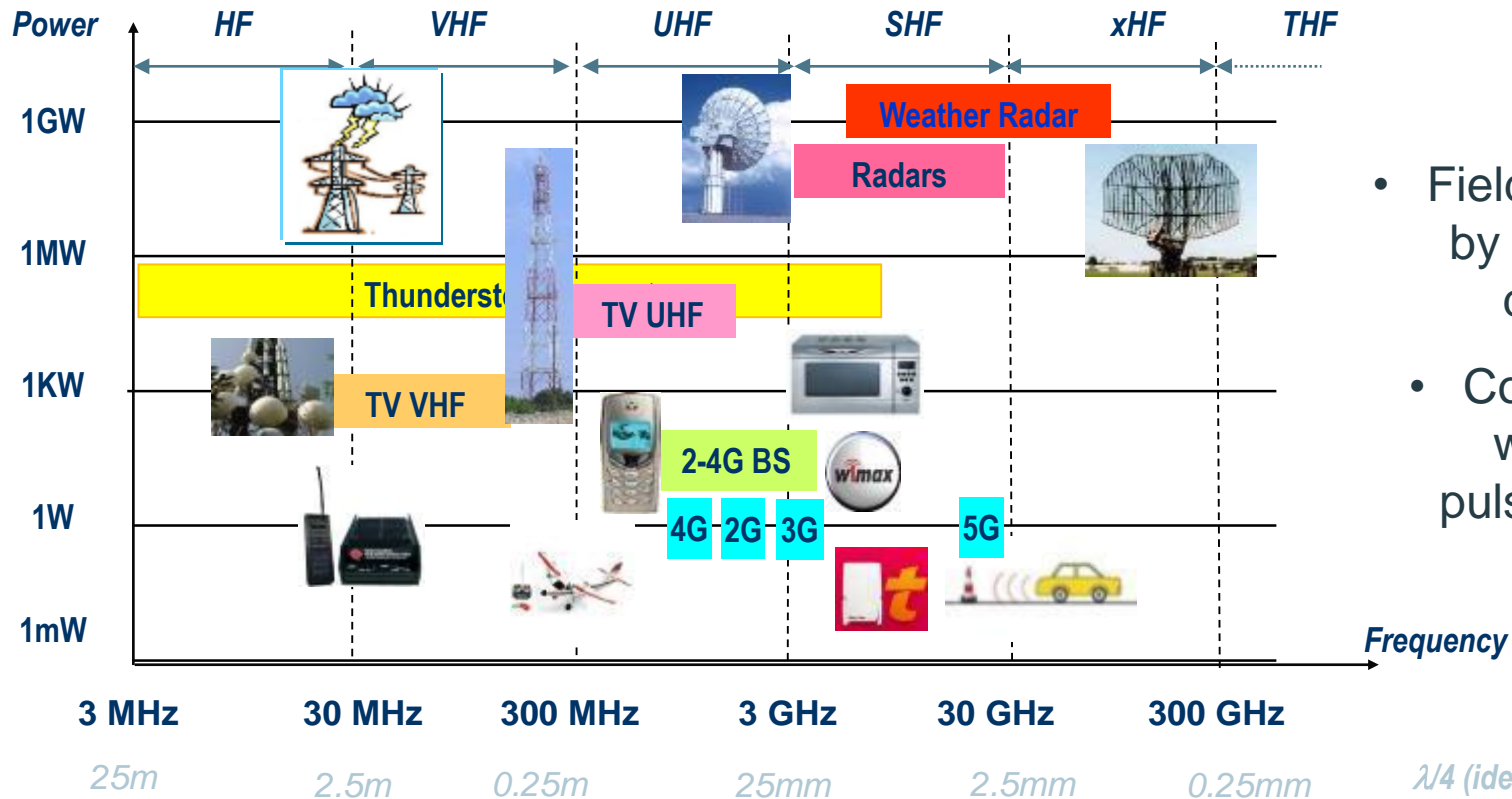


# Susceptibility Issues

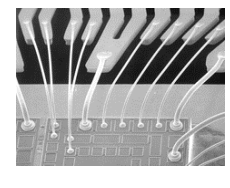
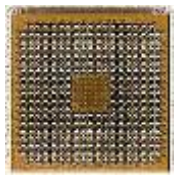


# Susceptibility Issues

## UNINTENTIONAL ELECTROMAGNETIC SOURCES



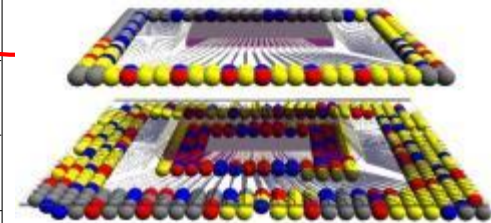
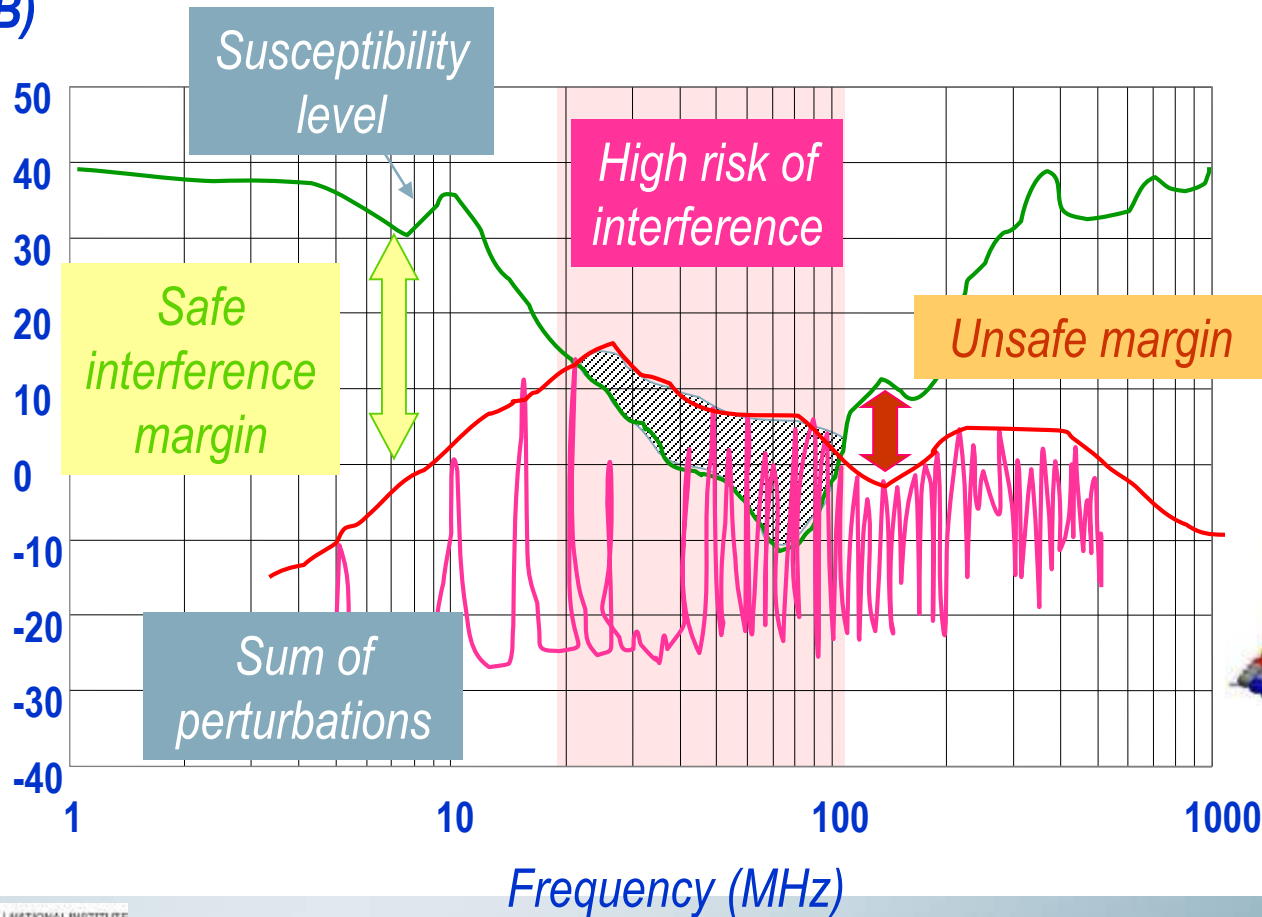
- Fields radiated by electronic devices
- Continuous waves & pulsed waves



# Susceptibility Issues

## SYSTEM-ON-CHIP, 3D STACKING: DANGER

EMC Level  
(dB)



# Susceptibility Issues





# Conclusion

- EMI reported in all kinds of devices
- IC involved in many EMI problems
- IC technology evolution towards higher complexity
- On-chip switching currents in the 10-100 A range
- ICs are good antennas in the GHz range
- Increased switching noise
- Increased emission issues
- Reduced noise margins
- System-on-chips, systems-in-package rise new EMC issues

## 2. EMC Basics

### concepts

---

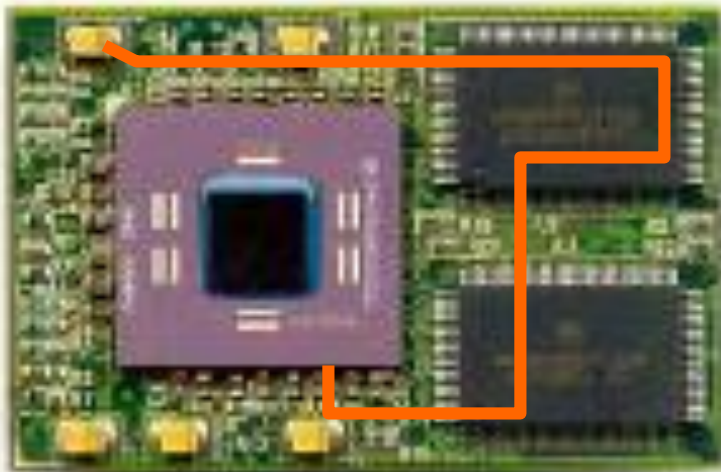
# Summary

1. Basic Principles
2. Specific Units
3. LC Resonance
4. Radiating element
5. Emission Spectrum
6. Susceptibility Spectrum
7. Notion of margin
8. Impedance
9. Conclusion

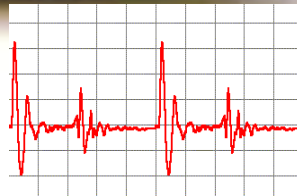
# Basic principles

## CONDUCTED AND RADIATED EMI

### Conducted mode

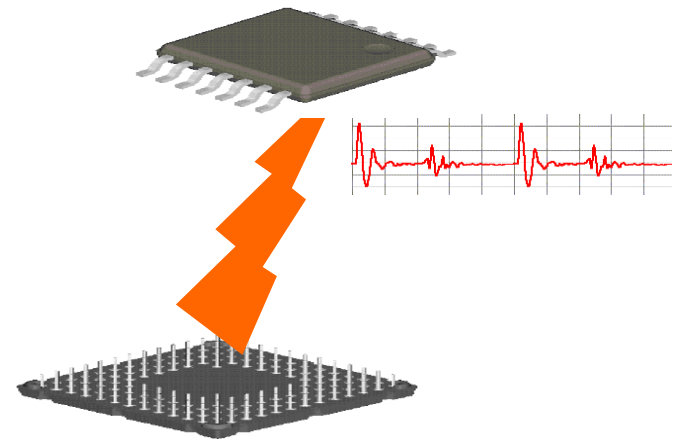


*The VDD supply propagates parasits*



*Power Integrity (PI)*

### Radiated mode



*The EM wave propagates through the air*

*Electromagnetic Interference (EMI)*

# Specific Units

## THE “EMC” WAY OF THINKING

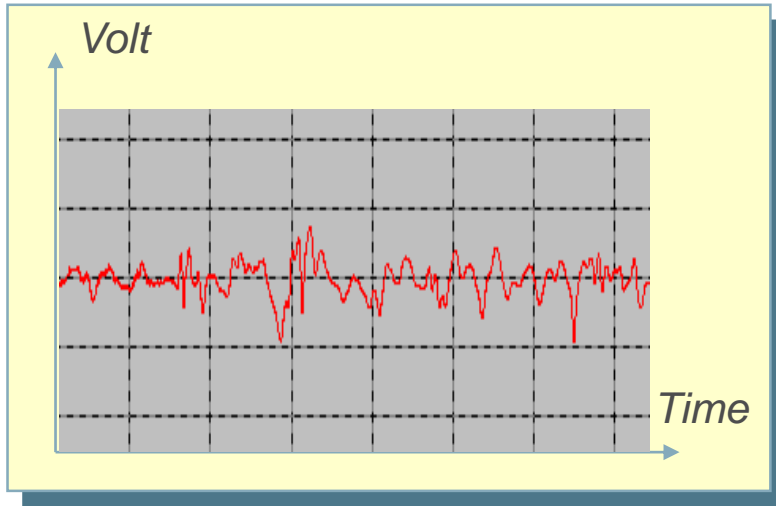
<i>Electrical domain</i>	<i>Electromagnetic domain</i>
Voltage V (Volt)	
Current I (Amp)	
Impedance Z (Ohm)	
$Z=V/I$	
$P=I^2 \times R$ (watts)	



# Specific units

## AMPLITUDE IN DB VS. FREQUENCY IN LOG

*Distinguish contributions of small harmonics*

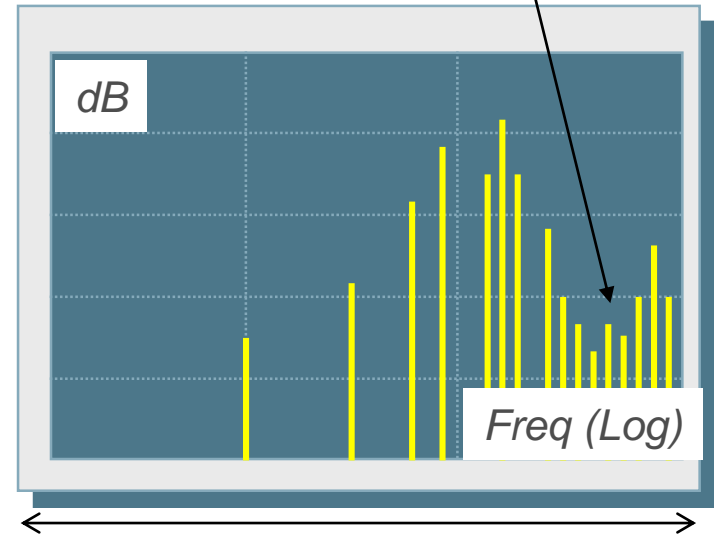


Time domain measurement



Oscilloscope

*Fourier transform*



*Cover very large bandwidth*

Frequency measurement



Spectrum analyser

# Specific units

## EMISSION AND SUSCEPTIBILITY LEVEL UNITS

### Voltage Units

Wide dynamic range of signals in EMC → use of dB (decibel)

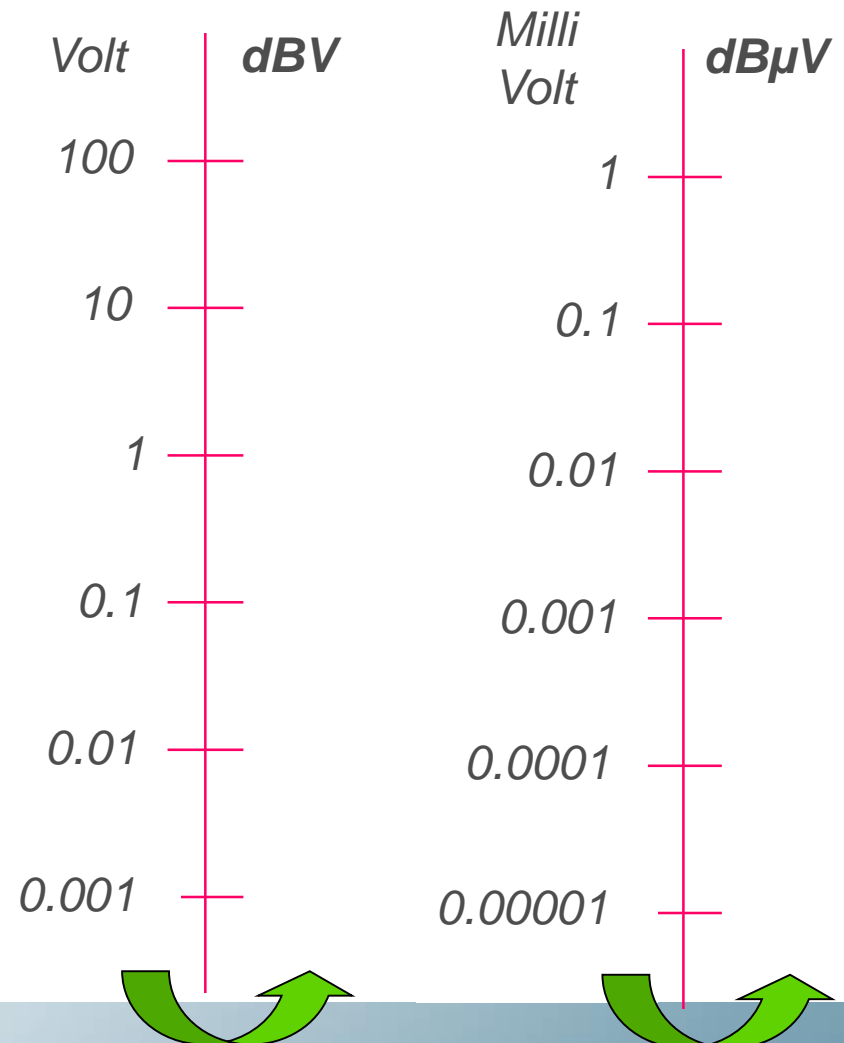
For example dBV, dBA :

$$dBV = 20 \times \log(V)$$

$$dBA = 20 \times \log(A)$$

Extensive use of dB $\mu$ V

$$V_{dB\mu V} = 20 \times \log\left(\frac{V}{1\mu V}\right) = 20 \times \log(V) + 120$$



# Specific units

## EMISSION AND SUSCEPTIBILITY LEVEL UNITS

### Power Units

The most common power unit is the “dBm”  
(dB milli-Watt)

$$P_{dBmW} = 10 \times \log\left(\frac{P_W}{1mW}\right) = 10 \times \log(P_W) + 30$$

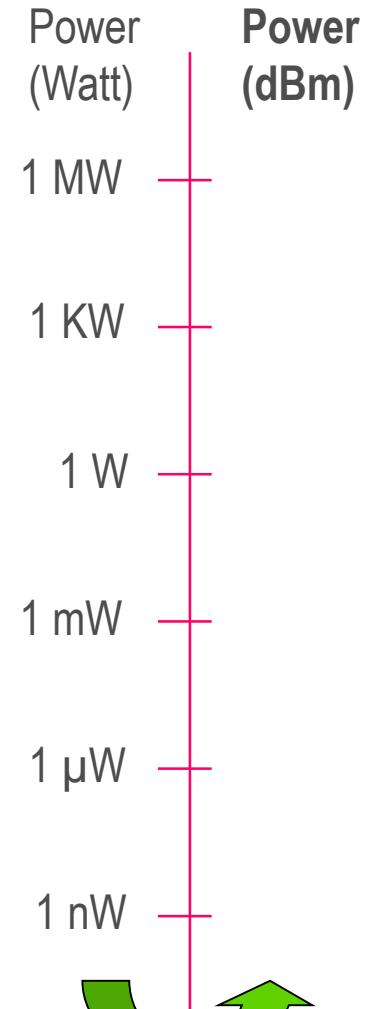
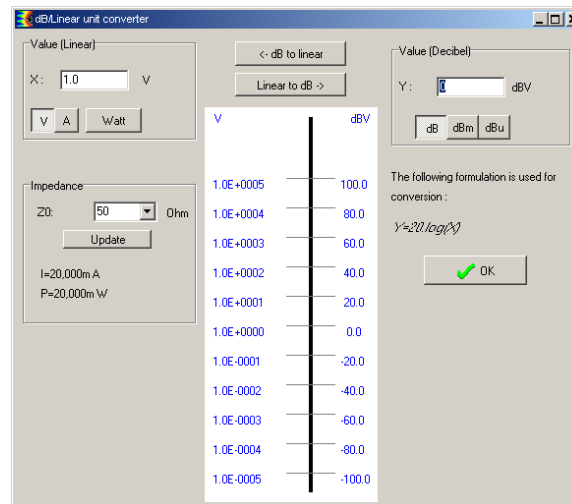
Exercise: Specific units

1 mV = \_\_\_\_ dBμV

1 W = \_\_\_\_ dBm

IC-EMC: 0dbm in 50 Ω

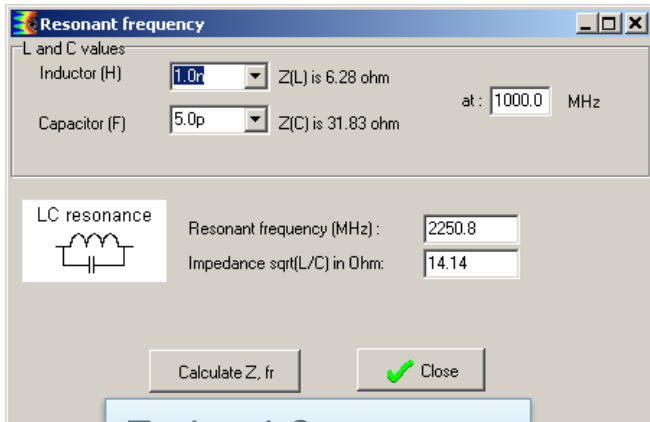
Tools > dB/Unit converter



# LC Resonance

## THE CHIP IS A LC RESONATOR

### ■ DSPIC33F DIE ALONE

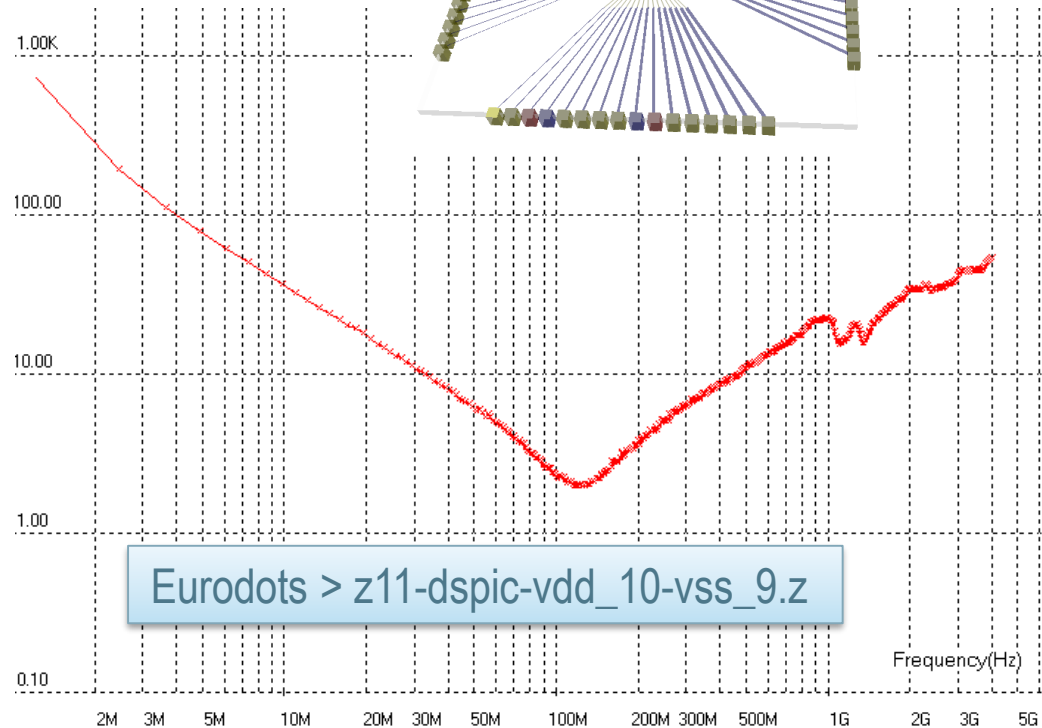


Tools > LC resonance

*Impedance measurement  
between Vdd and Vss*

$f = \underline{\hspace{2cm}}$

Impedance ( $\Omega$ )

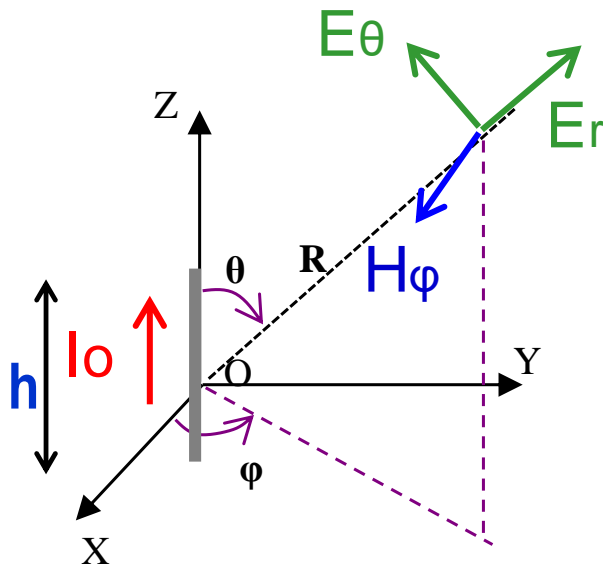
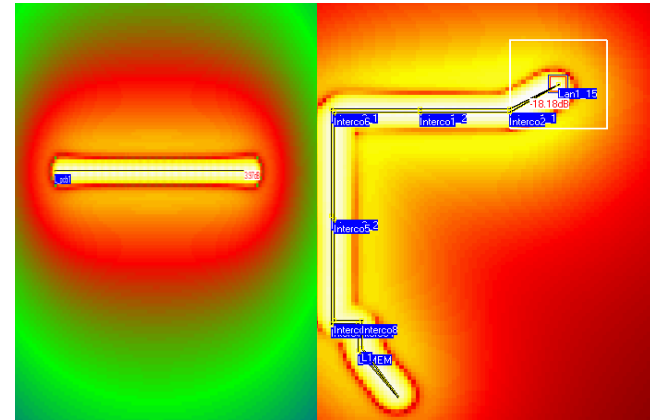


Frequency (Hz)

# Radiating Element

## RADIATED EMISSION

- Elementary “Hertz” current dipole.
- Short wire with a length  $\ll \lambda$ , crossed by a sinusoidal current with a constant amplitude  $I_0$



$$\vec{E}_r = 2 \frac{\eta \beta^2 I_0 h}{4\pi} \cos \theta \left( \frac{1}{\beta^2 r^2} - \frac{j}{\beta^3 r^3} \right) e^{-j\beta r}$$

$$\vec{E}_\theta = \frac{\eta \beta^2 I_0 h}{4\pi} \sin \theta \left( \frac{1}{\beta^2 r^2} + \frac{j}{\beta r} - \frac{j}{\beta^3 r^3} \right) e^{-j\beta r}$$

$$\vec{H}_\phi = \frac{\beta^2 I_0 h}{4\pi} \sin \theta \left( \frac{1}{\beta^2 r^2} + j \frac{1}{\beta r} \right) e^{-j\beta r}$$

$$\vec{E}_\phi = \vec{H}_r = \vec{H}_\theta = \vec{0}$$



# Radiating Element

## NEAR FIELD/FAR FIELD

- Close to the antenna

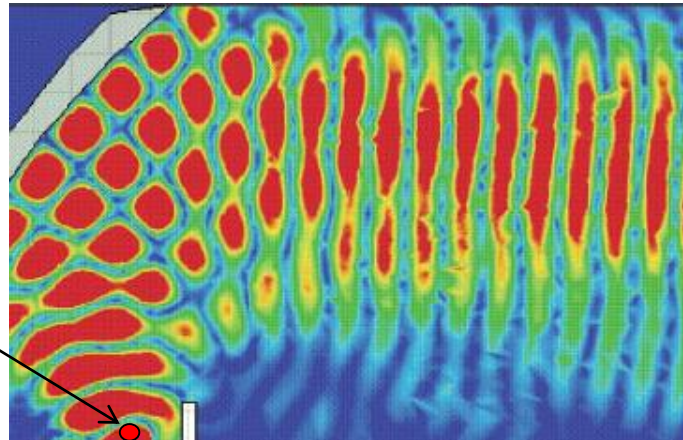
$$\beta R \ll 1 \Rightarrow R \ll \frac{\lambda}{2\pi}$$

$$R_{\text{limit}} = \frac{\lambda}{2\pi}$$

- Far from the antenna

$$\beta R \gg 1 \Rightarrow R \gg \frac{\lambda}{2\pi}$$

Near-field  
region



Far-field  
region

- ✓ Non radiating field (non TEM wave)
- ✓ E and H decreases rapidly in  $1/r^3$

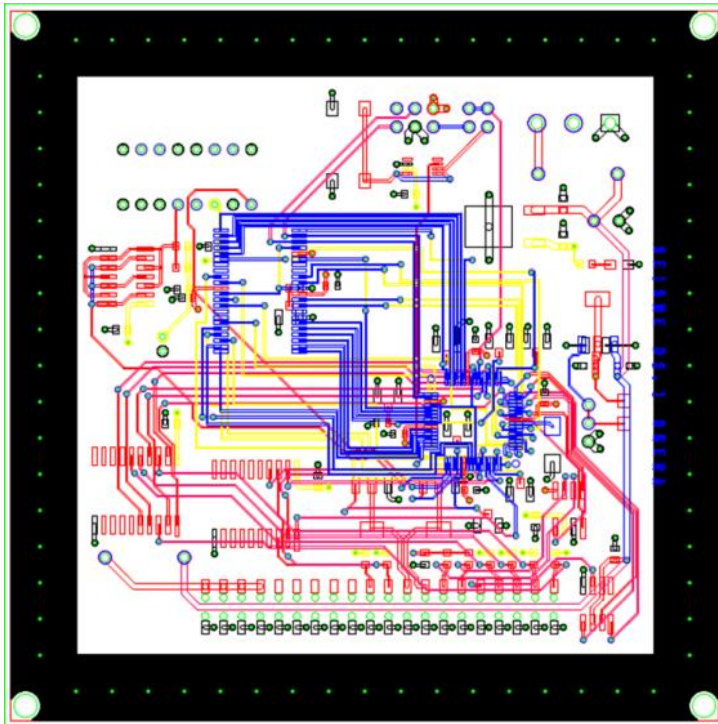
- ✓ Radiating field (TEM wave)
- ✓ E and H decreases in  $1/r$

100 MHz :  $R_{\text{limit}} = \underline{\hspace{2cm}}$

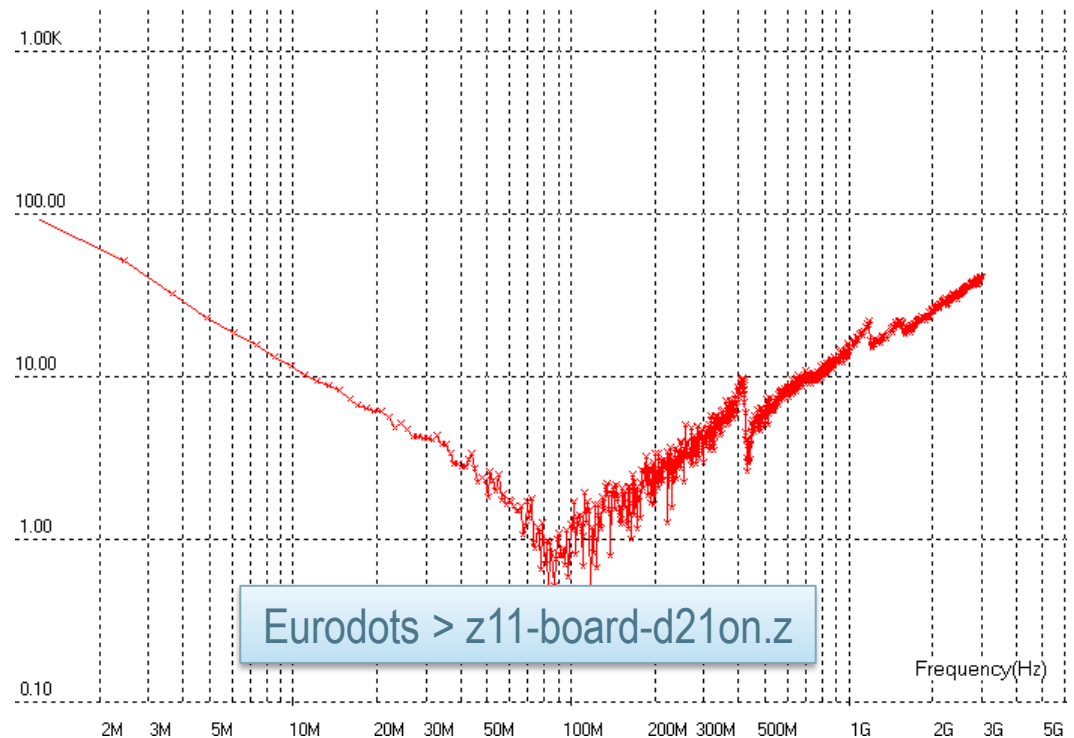
# LC Resonance

## THE BOARD IS A RESONATOR

- The VDD/VSS plate acts as a capacitor



Impedance ( $\Omega$ )



Frequency (Hz)

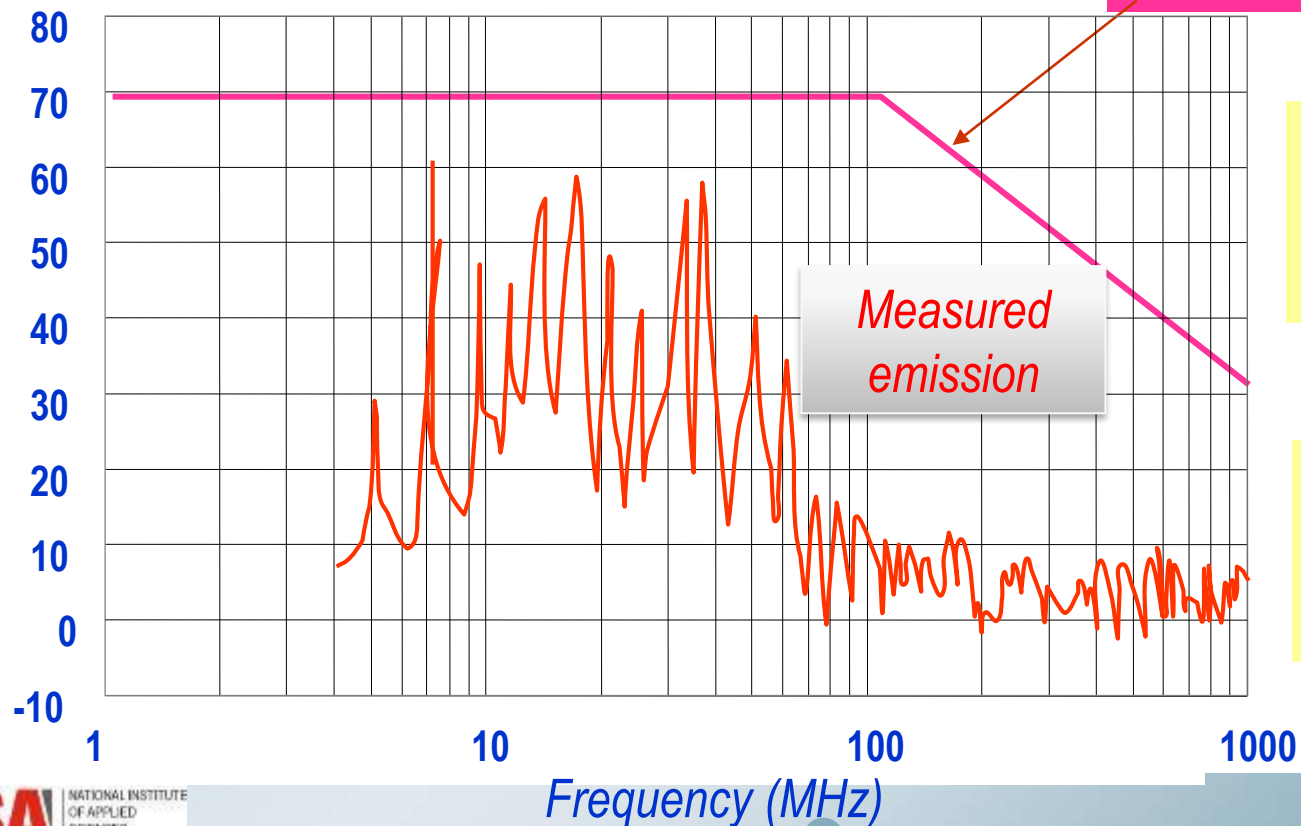
# Emission spectrum

## EMISSION LEVEL VS. CUSTOMER SPECIFICATION

Parasitic emission  
(dB $\mu$ V)

EMC compatible

Specification  
example for an IC  
emission



IC-EMC: load

Emission > d60 >  
d60\_vde.tab

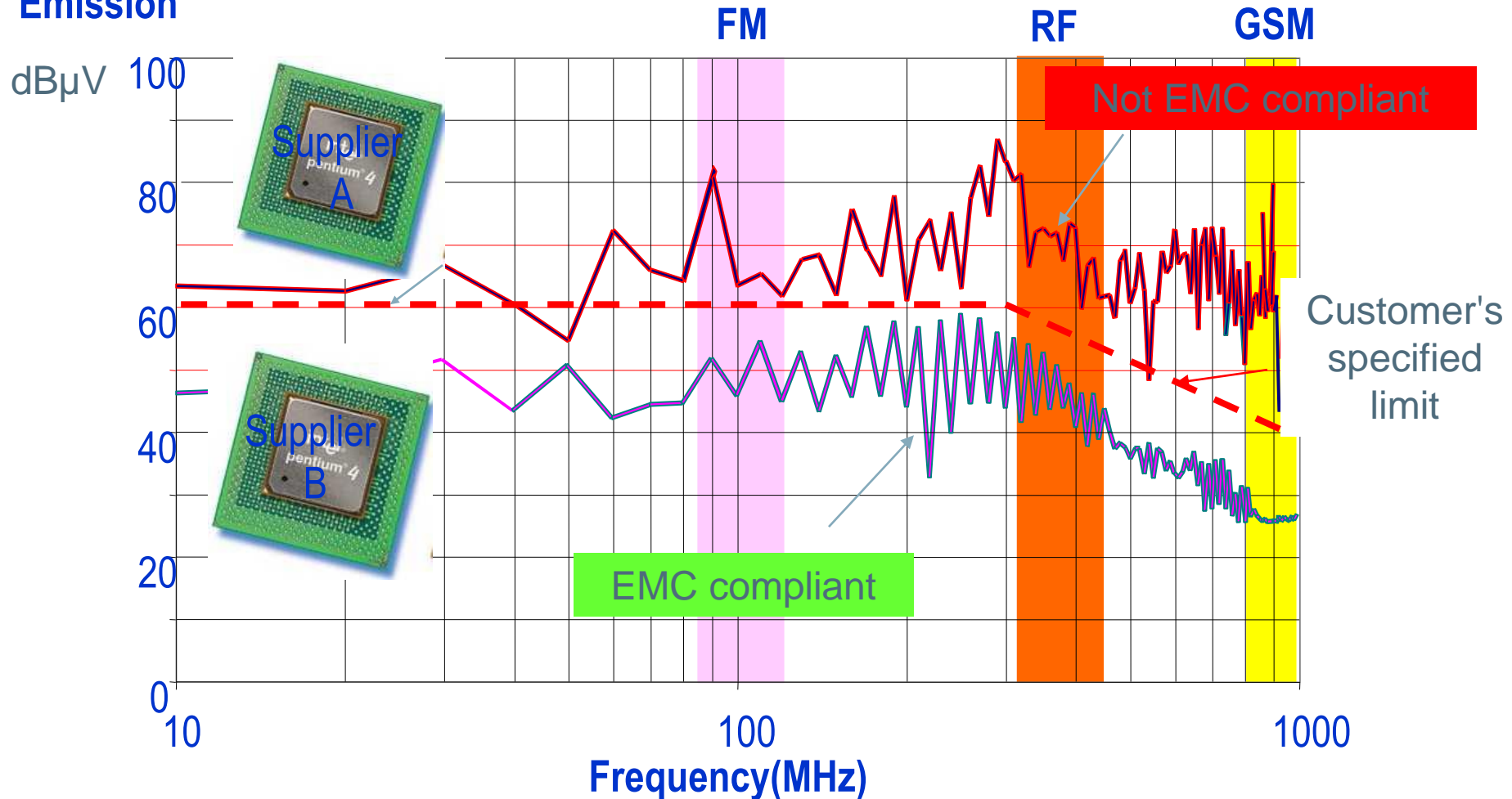
IC-EMC: load

Getting started > mpc >  
mpc\_vde.tab

# Emission spectrum

## LOW PARASITIC EMISSION IS A KEY COMMERCIAL ARGUMENT

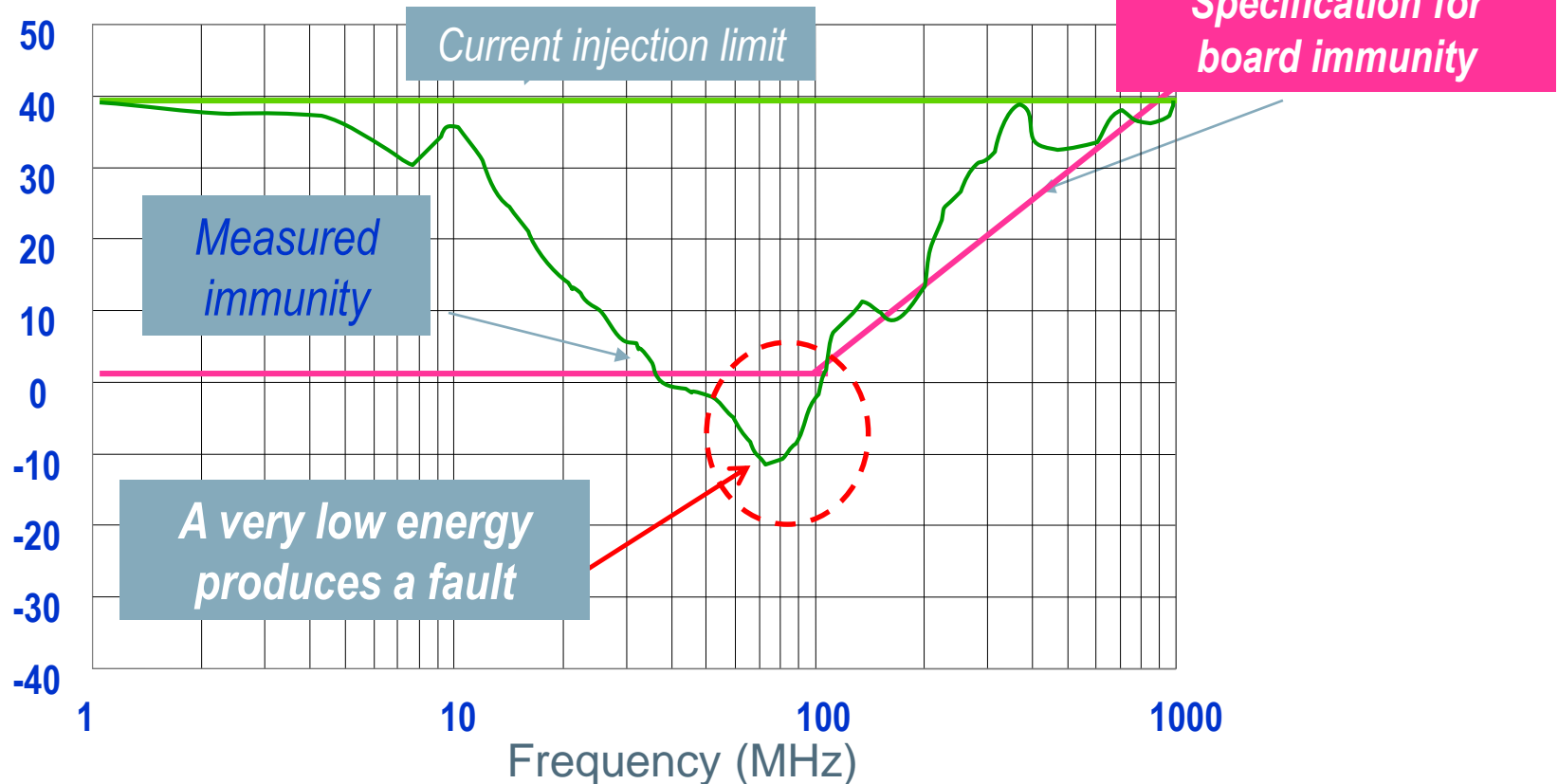
### Emission



# Susceptibility spectrum

IMMUNITY LEVEL HAS TO BE HIGHER THAN CUSTOMER SPECIFICATION

Immunity  
level (dBmA)

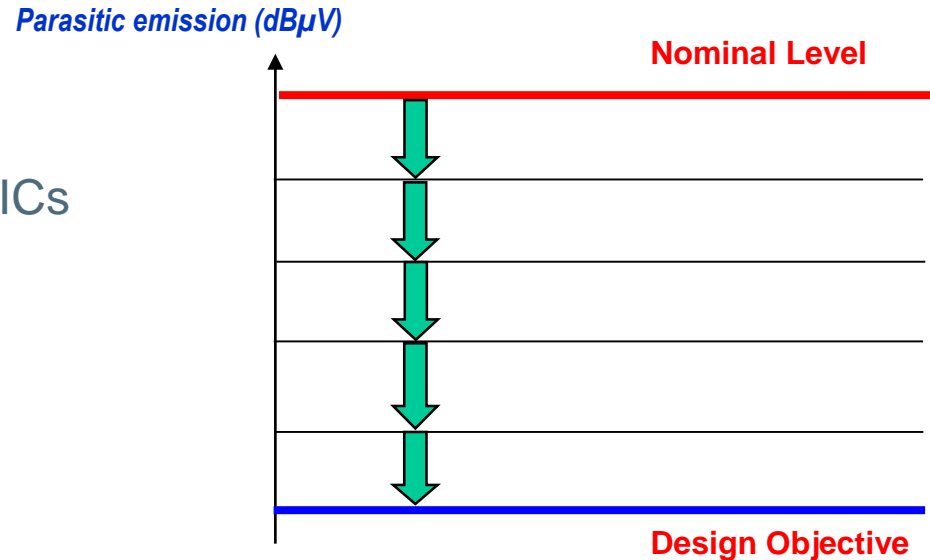




# Notion of margin

## WHY A MARGIN ?

- To ensure low parasitic emission ICs supplier has to adopt margins
- Margin depends on the application domain

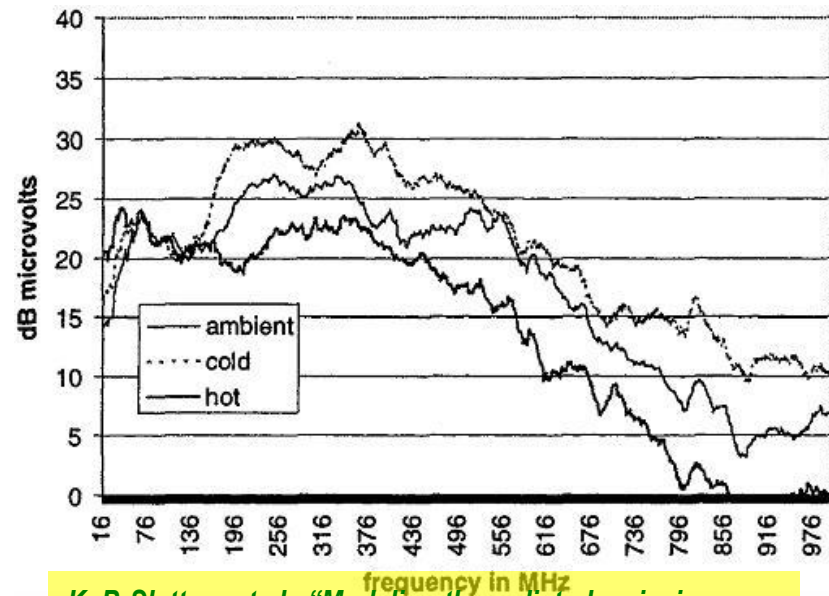


Domain	Lifetime	Margin
<b>Aeronautics</b>		
<b>Automotive</b>		
<b>Consumer</b>		

# Notion of margin

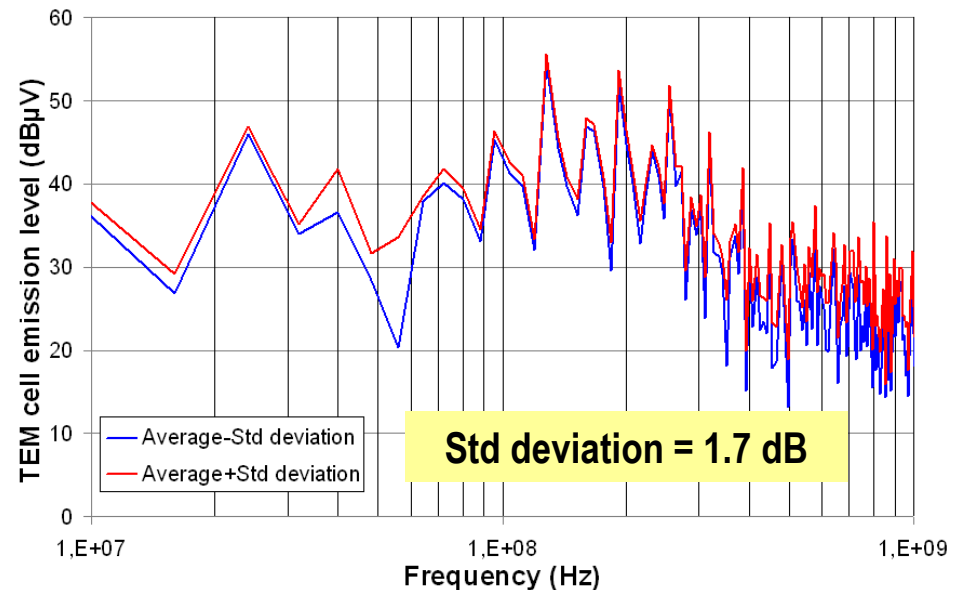
## INFLUENT PARAMETERS ON IC EMC

- The temperature of a circuit has a direct impact on the switching time of internal devices. When temperature increases, the high frequency content of the emission spectrum tends to be reduced.



K. P. Slattery et al., "Modeling the radiated emissions from microprocessors and other VLSI devices", IEEE Symp. on EMC, 2000.

- The variability between components induce a dispersion of emission and susceptibility level. Radiated emission in TEM cell of a 16 bit microcontroller PIC18F2480. Measurement of 12 samples and extraction of emission level dispersion.

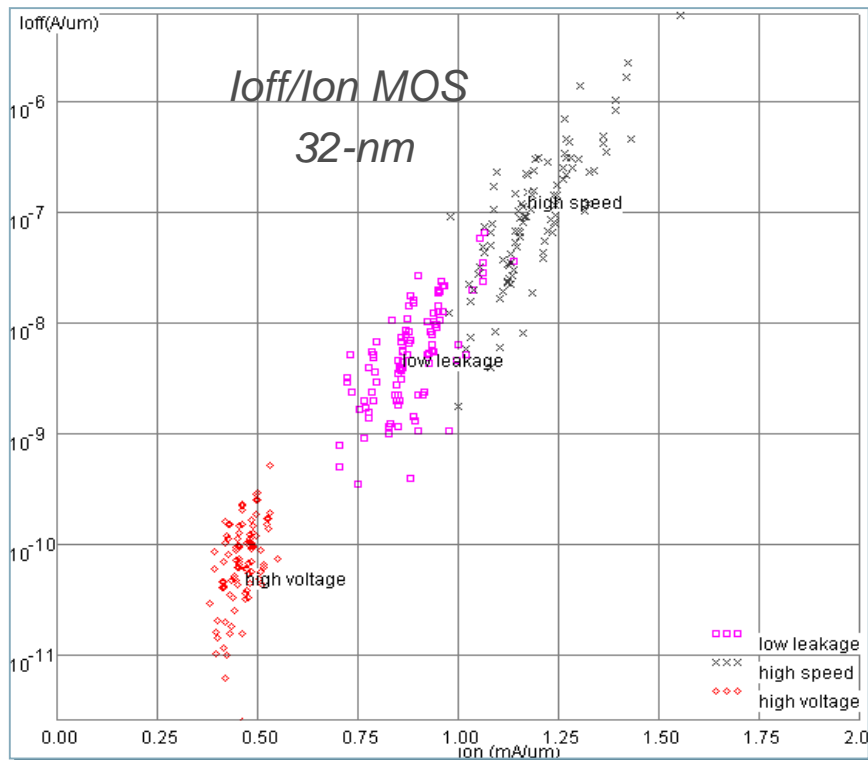


H. Huang and A. Boyer (LAAS-CNRS)

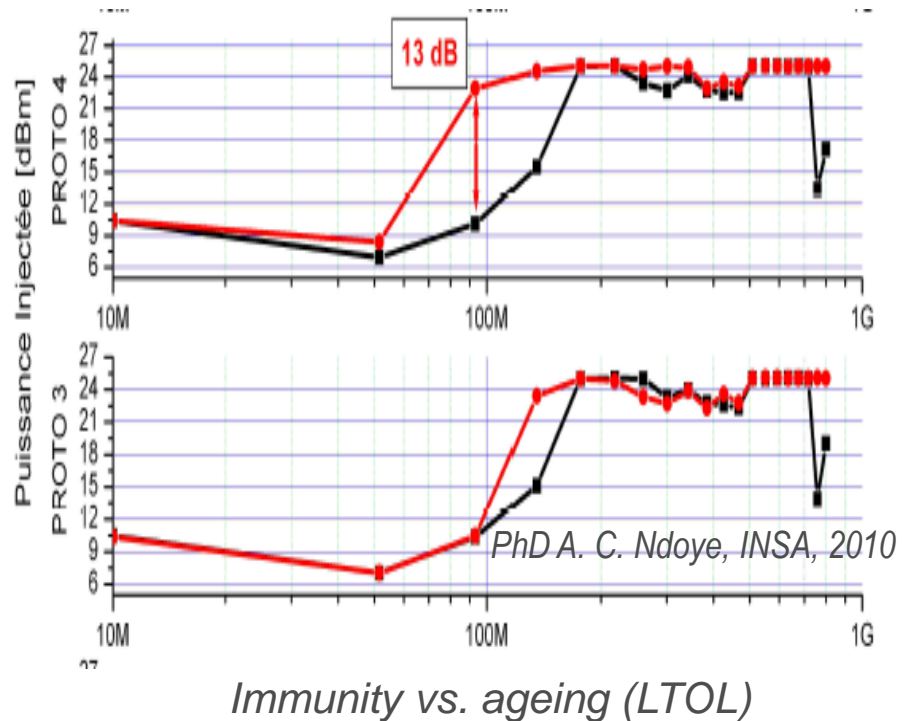
# Notion of margin

## INFLUENT PARAMETERS ON IC EMC

- MOS device characteristics fluctuate by  $\pm 30\%$



- Ageing may significantly alter EMC performances



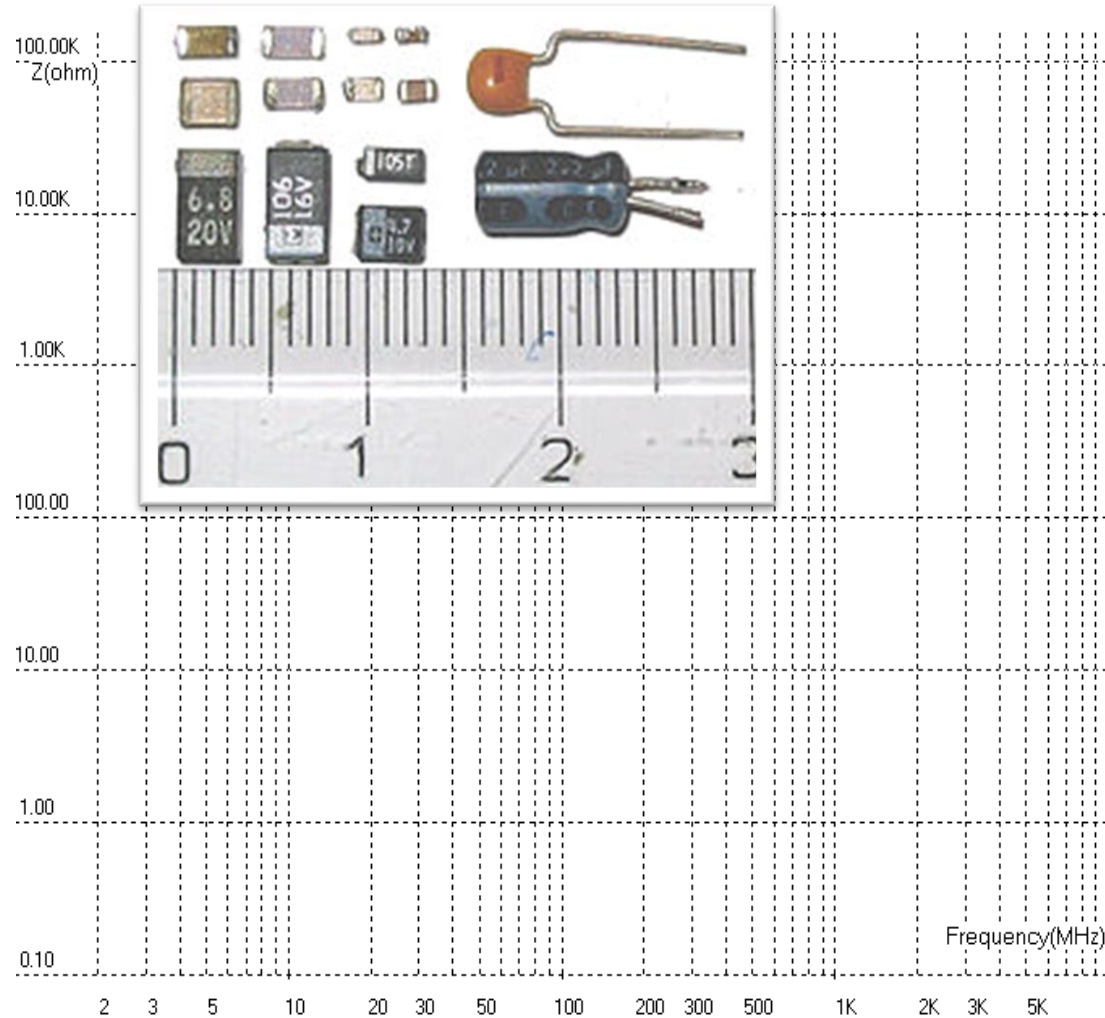
# Impedance

## R,L,C VS. FREQUENCY

### Impedance profile of:

- 1  $\Omega$  resistor (z11-1Ohm\_0603.z)
- 0603 = 1.6 x 0.8 mm

comparison	Metric code	Imperial code	comparison
0.1x0.1 mm	0402	01005	0.01x0.01 in (10x10 mils)
	0603	0201	
	1005	0402	
	1608	0603	
1x1mm	2012	0805	0.1x0.1 in (100x100 mils)
	2520	1008	
	3216	1206	
	3225	1210	
	4516	1806	
	4532	1812	
	5025	2010	
1x1 cm	6332	2512	0.5x0.5in (500x500 mils)
	Actual size		



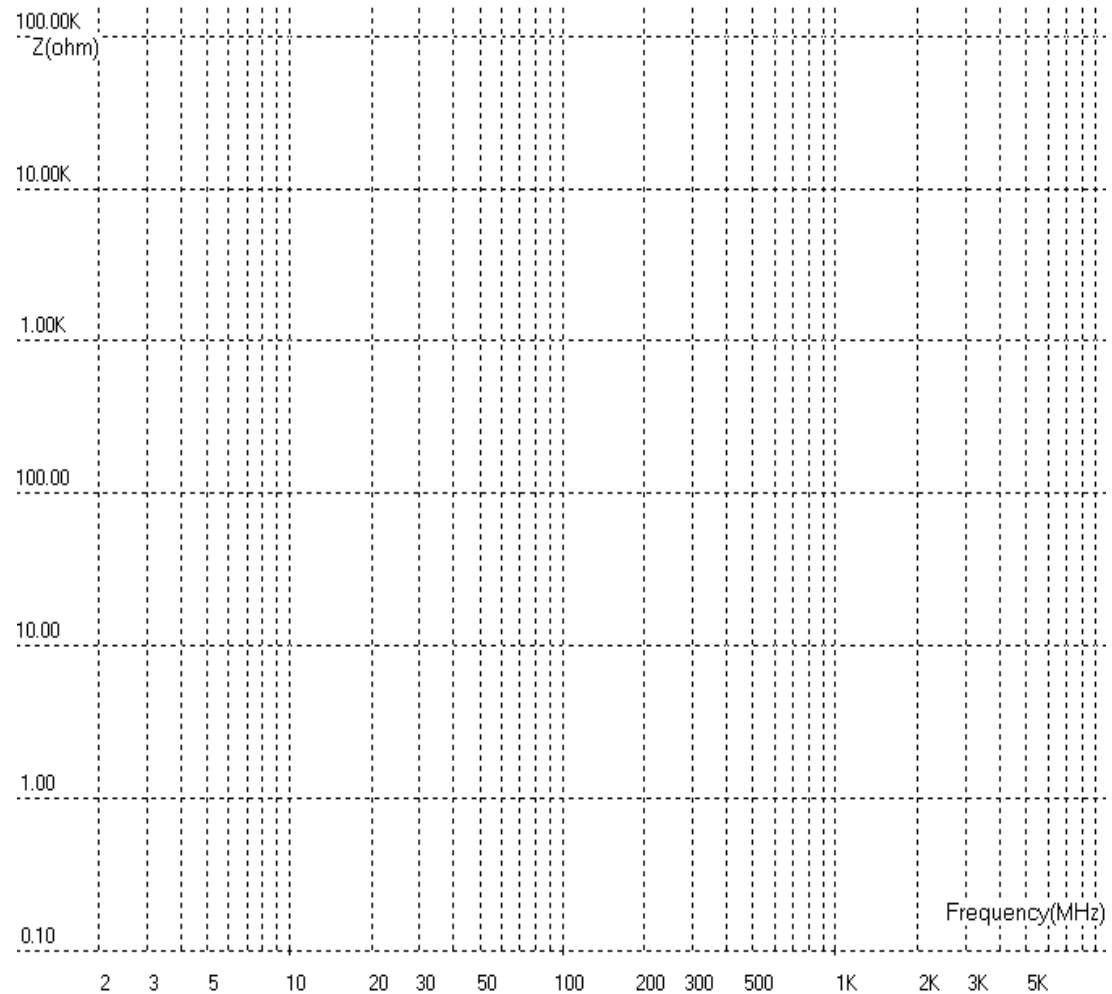
# Impedance

## R,L,C VS. FREQUENCY

Impedance profile of:

- 1 nF capacitor (z11-C1nF\_0603.z)

Schematic diagram:





# Impedance

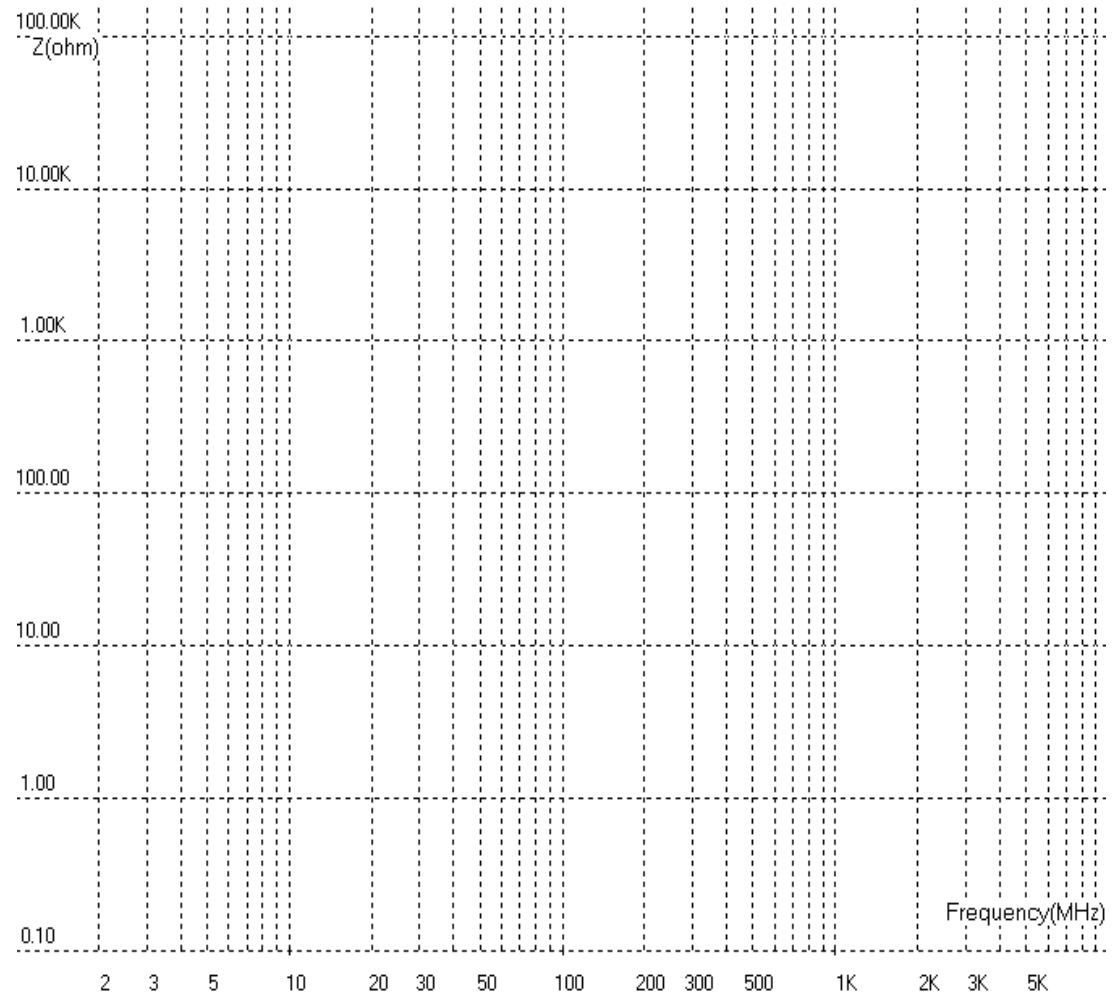
## R,L,C VS. FREQUENCY

Impedance profile of:

- Inductance 47  $\mu\text{H}$   
(Zin\_L47u.s50)



Schematic diagram:

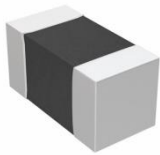


# Impedance

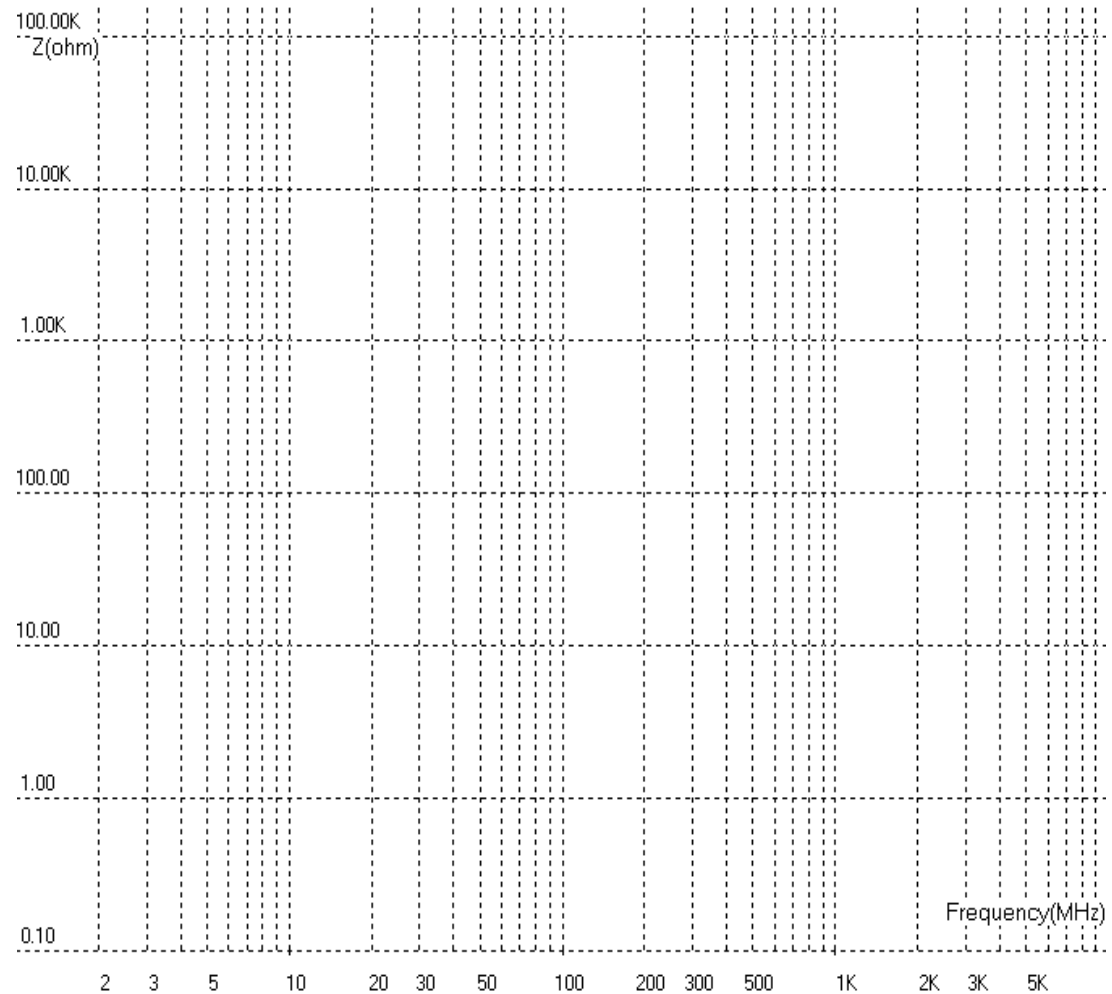
## R,L,C VS. FREQUENCY

Impedance profile of:

- Ferrite  
(Zin\_FerriteBLM18HK102  
SN1.s50)



Schematic diagram:



# Characteristic Impedance

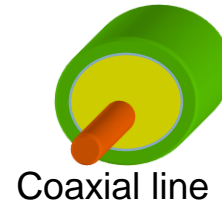
## CONDUCTOR IMPEDANCE OR CHARACTERISTIC IMPEDANCE $Z_0$ :

- From the electromagnetic point of view:

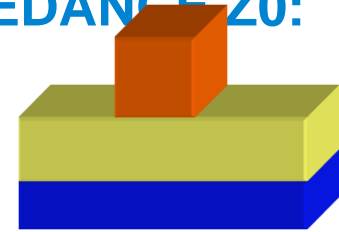
$$Z_0 = \frac{E}{H}$$



Link to conductor geometry and material properties



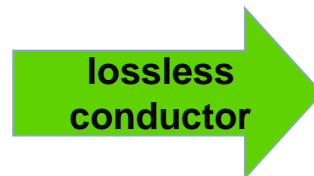
Coaxial line



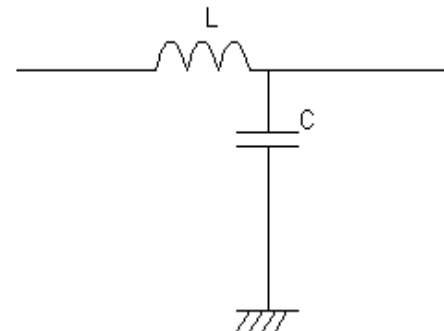
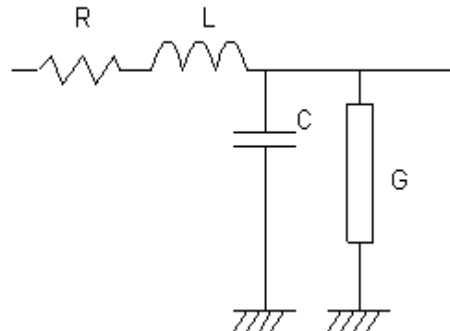
Microstrip line

- From the electric point of view :

$$Z_0 = \sqrt{\frac{R + jL\omega}{G + jC\omega}}$$



$$Z_0 \approx \sqrt{\frac{L}{C}}$$

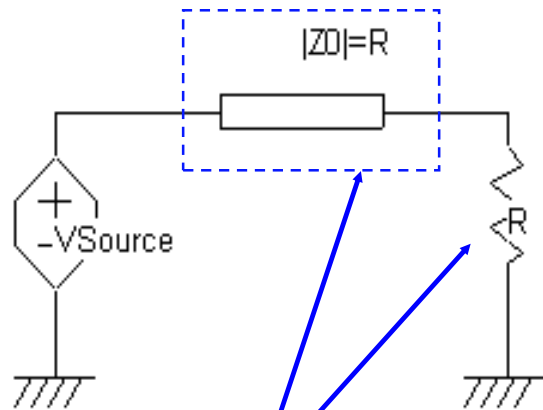
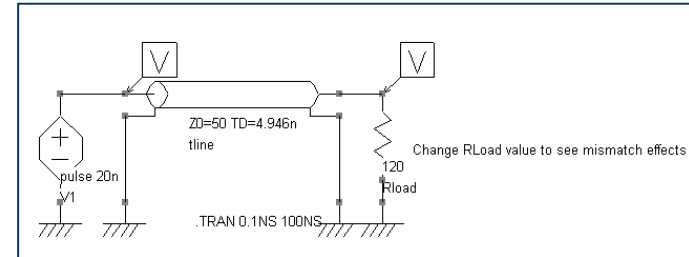


*Equivalent electrical schematic*

# Characteristic Impedance

## IMPEDANCE MATCHING

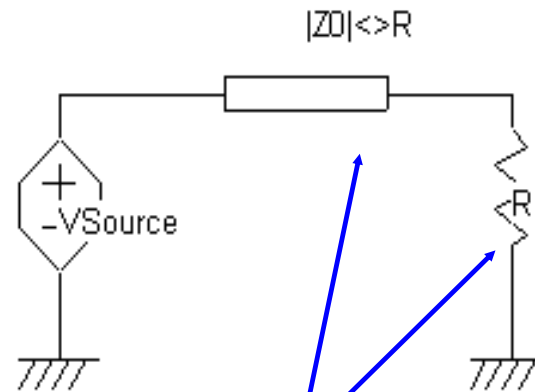
Why impedance matching is fundamental ?



Adapted:

Voltage

time



Not adapted:

Voltage

time

IC-EMC

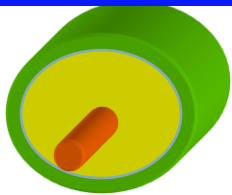
Impedance>

impedance\_mismatch.sch

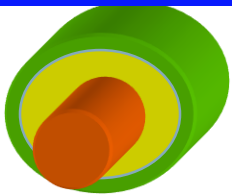
# Characteristic Impedance

## CHARACTERISTIC IMPEDANCE $Z_0$ : Small conductor

What is the optimum characteristic impedance for a coaxial cable ?



## Large conductor



Or ?

	Small conductor	Large conductor
Power handling		
Bending		
weight		
Low loss		
Small capacitance		
Small inductance		
Low Impedance		

*Ideal values:*

- Maximum power :  $Z_0 = \_\_\_\Omega$
- Minimum loss:  $Z_0 = \_\_\_\Omega$

*Cable examples:*

- EMC cable (compromise between power and loss) :  $Z_0 = \_\_\_\Omega$
- TV cable :  $Z_0 = \_\_\_\Omega$
- Base station cable :  $Z_0 = \_\_\_\Omega$



# Characteristic Impedance

## 50 OHM ADAPTED SYSTEMS

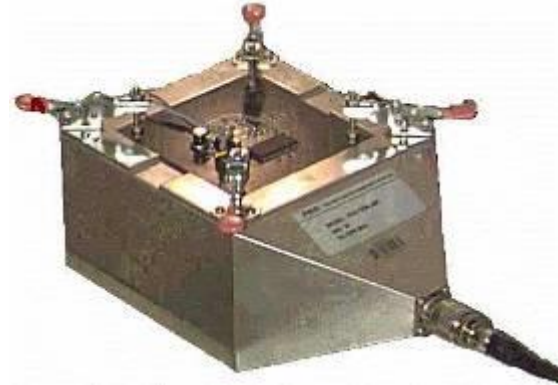
Spectrum analyzer



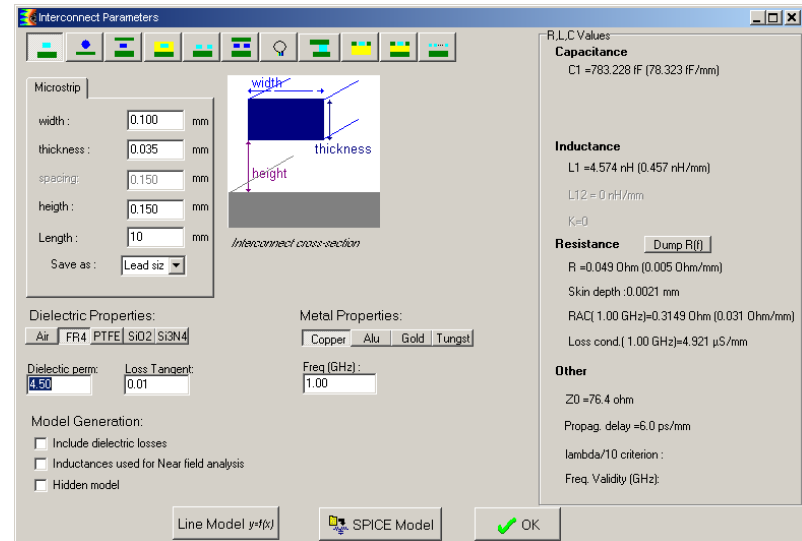
Waveform generator



Amplifier



Tem cell



Tools > Interconnect parameters

# Conclusion

- Specific units used in EMC have been detailed
- The current dipole is the base for radiated emission
- The Emission Spectrum has been described
- Susceptibility Threshold, margins have been discussed
- The notion of impedance has been introduced
- Characteristic impedance of cables lead to specific values
- Discrete components used in the experimental board have been modeled up to 1 GHz

# Classroom experiments

- EMC issues

---

# Purpose

- 1. Clarify basic concepts for EMC by hands-on experiments**
- 2. Present some measurement equipments for EMC of electronic devices and equipments**
- 3. Provide simple tools to evaluate EMC issues**

# Summary

- 1. Susceptibility of circuits to electromagnetic disturbances**
- 2. Spectrum analyzer – Spectral content evaluation**
- 3. Observing typical antenna at PCB/IC level**
- 4. Crosstalk**
- 5. DM vs CM current – radiation from cables**

## Susceptibility of circuits to electromagnetic disturbances – An example



# Susceptibility of circuits

## *Effect of IC malfunction due to EM disturbance – Real examples*

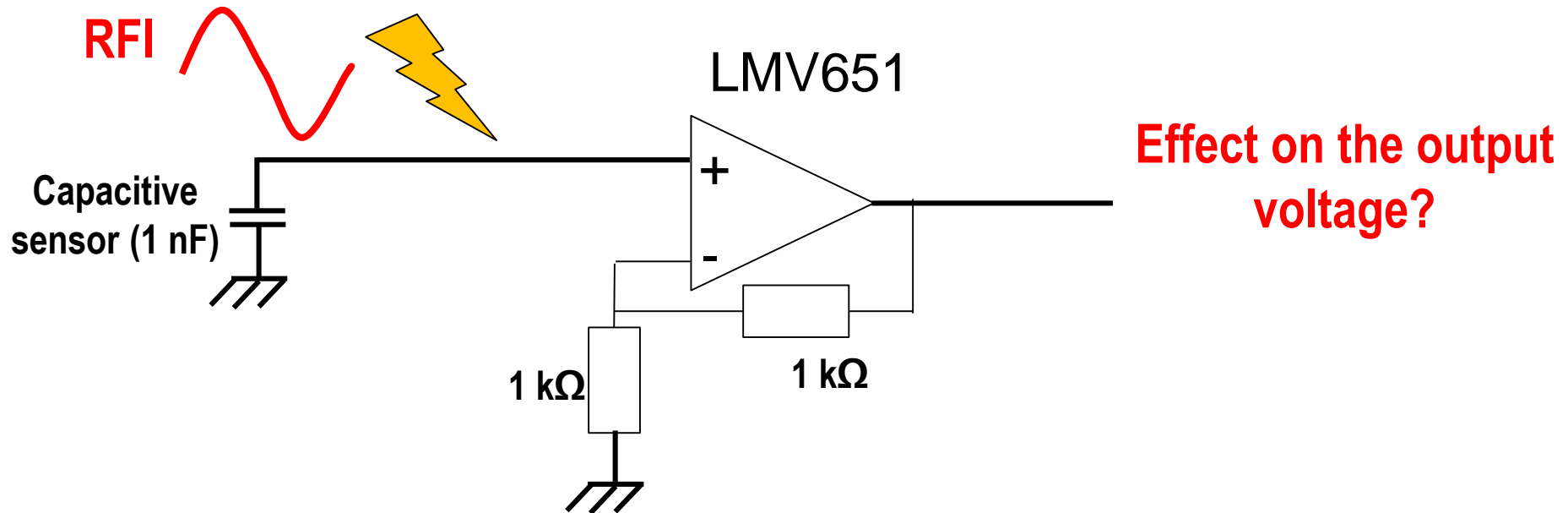
- Striking of berth by Coastal Inspiration, 20<sup>th</sup> dec 2011, Nanaimo, British Columbia, Canada.
- A problem of an amplifier, due to EM disturbances, leads to a failure in speed reduction command.



- Other example: Cell phone interference with speaker

# Susceptibility of circuits

## Susceptibility of op-amp

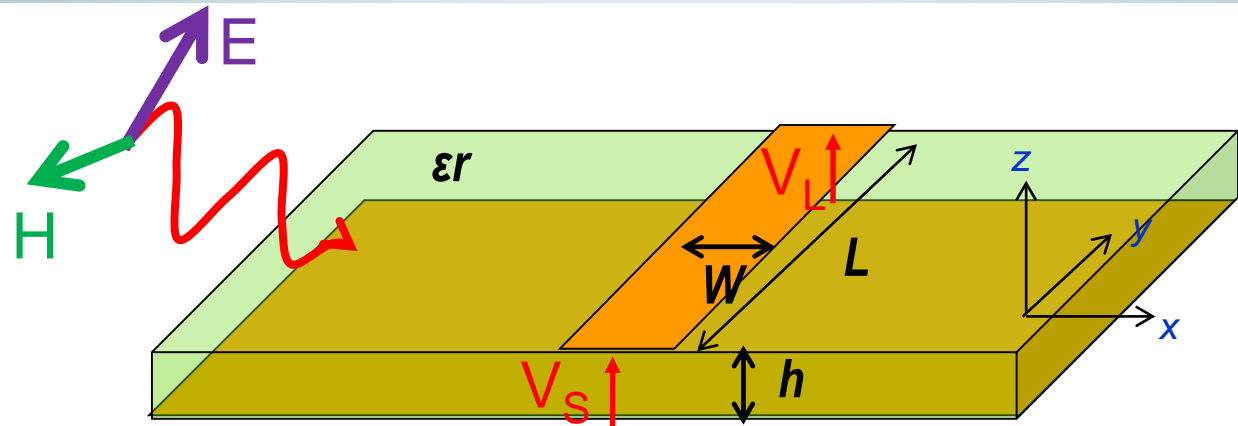


- Couple on the circuit a sine wave electromagnetic disturbance
- Observe the effect on the output voltage

# Simple radiated emission/susceptibility model

## Far-field coupling

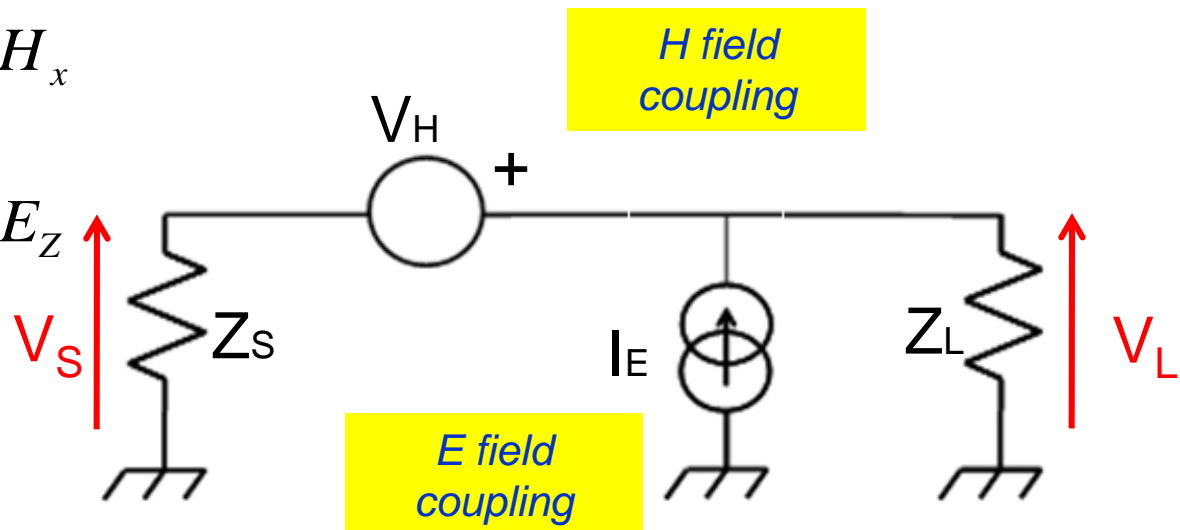
- Illumination of a microstrip line by an uniform plane wave



- Worst-case model (transmission line effect neglected)

$$V_H(\omega) = j\omega\mu_0 h \cdot \min\left(L, \frac{\lambda}{4}\right) \cdot H_x$$

$$I_E(\omega) = j\omega c_{line} h \cdot \min\left(L, \frac{\lambda}{4}\right) \cdot E_z$$



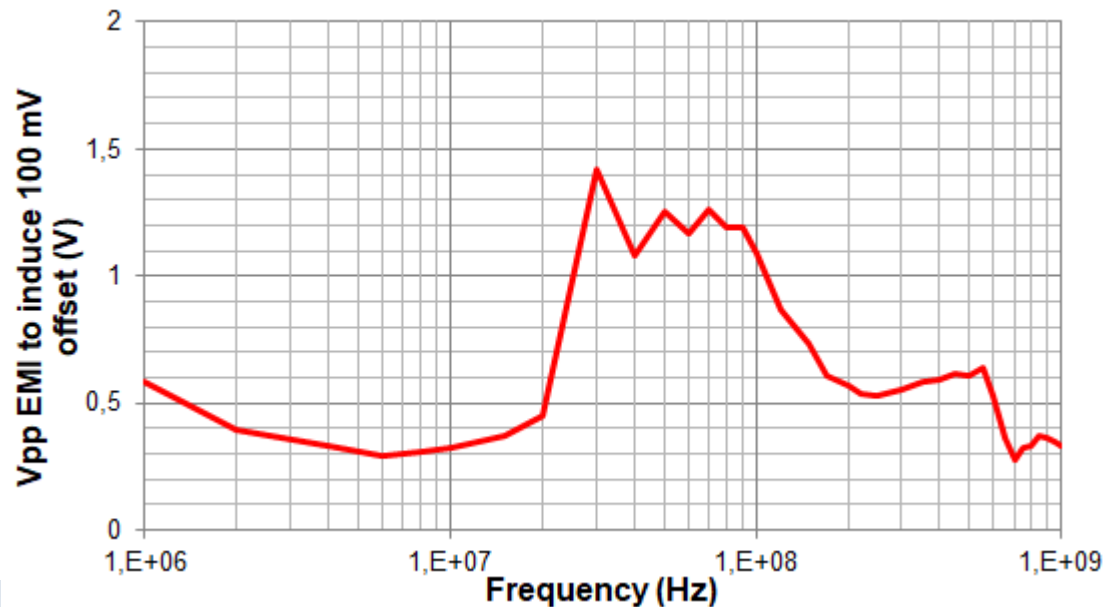
# Susceptibility of circuits

## *Estimation of the radiated susceptibility of op-amp*

### ■ Radiated susceptibility at 900 MHz ?

### ■ Let consider:

- LMV651 connected to a high-Z sensor by a 50 mm long trace routed at 1.6 mm above a ground plane.
- Let consider identical load on each termination of the line.
- Peak-to-peak voltage applied on V+ to induce 100 mV offset:



# Susceptibility of circuits

## *Estimation of the radiated susceptibility of op-amp*

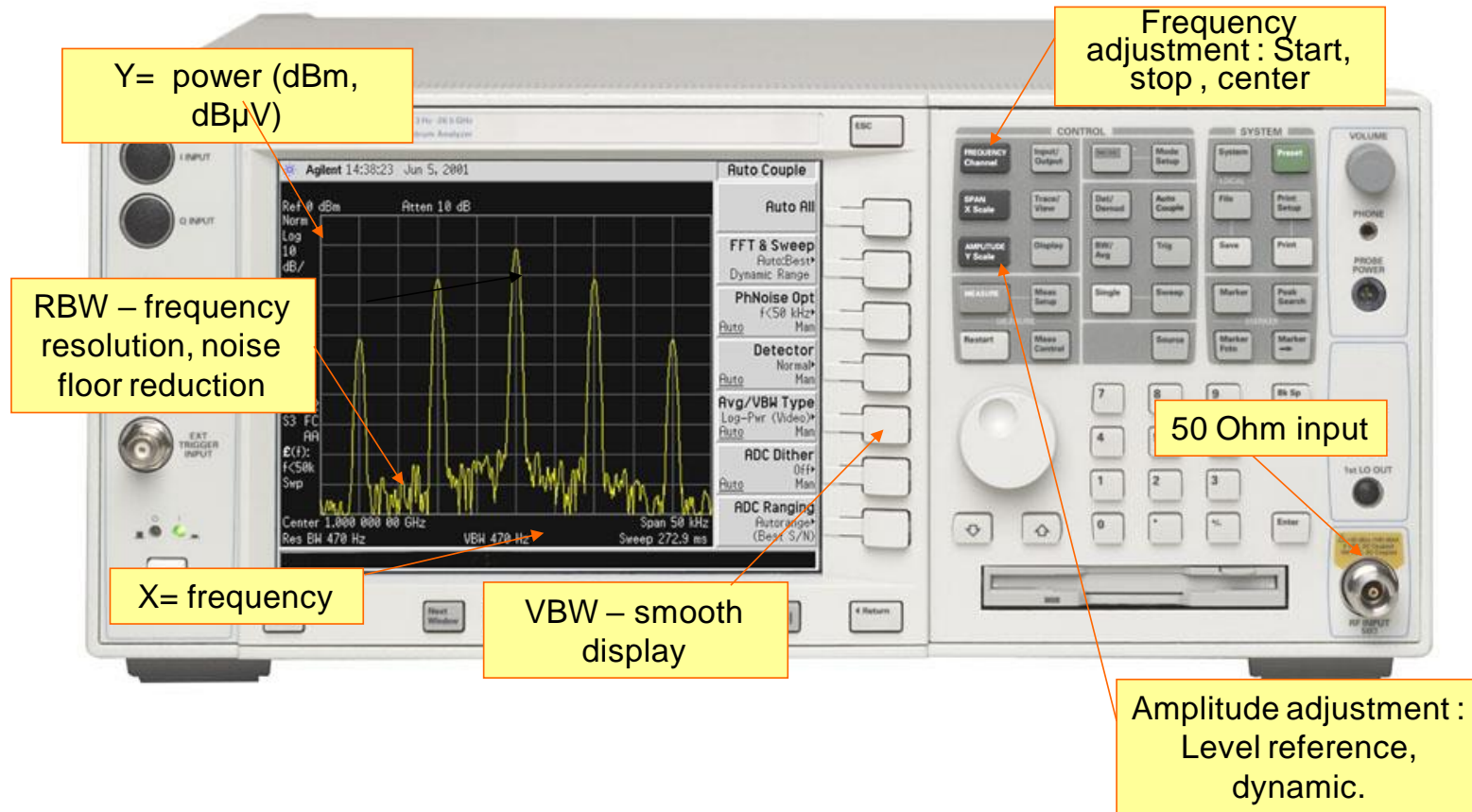
### ■ Solutions ?

## Spectrum analyzer – Spectral content evaluation



# Spectrum analyzer

## Spectrum Analyser (EMI receiver)

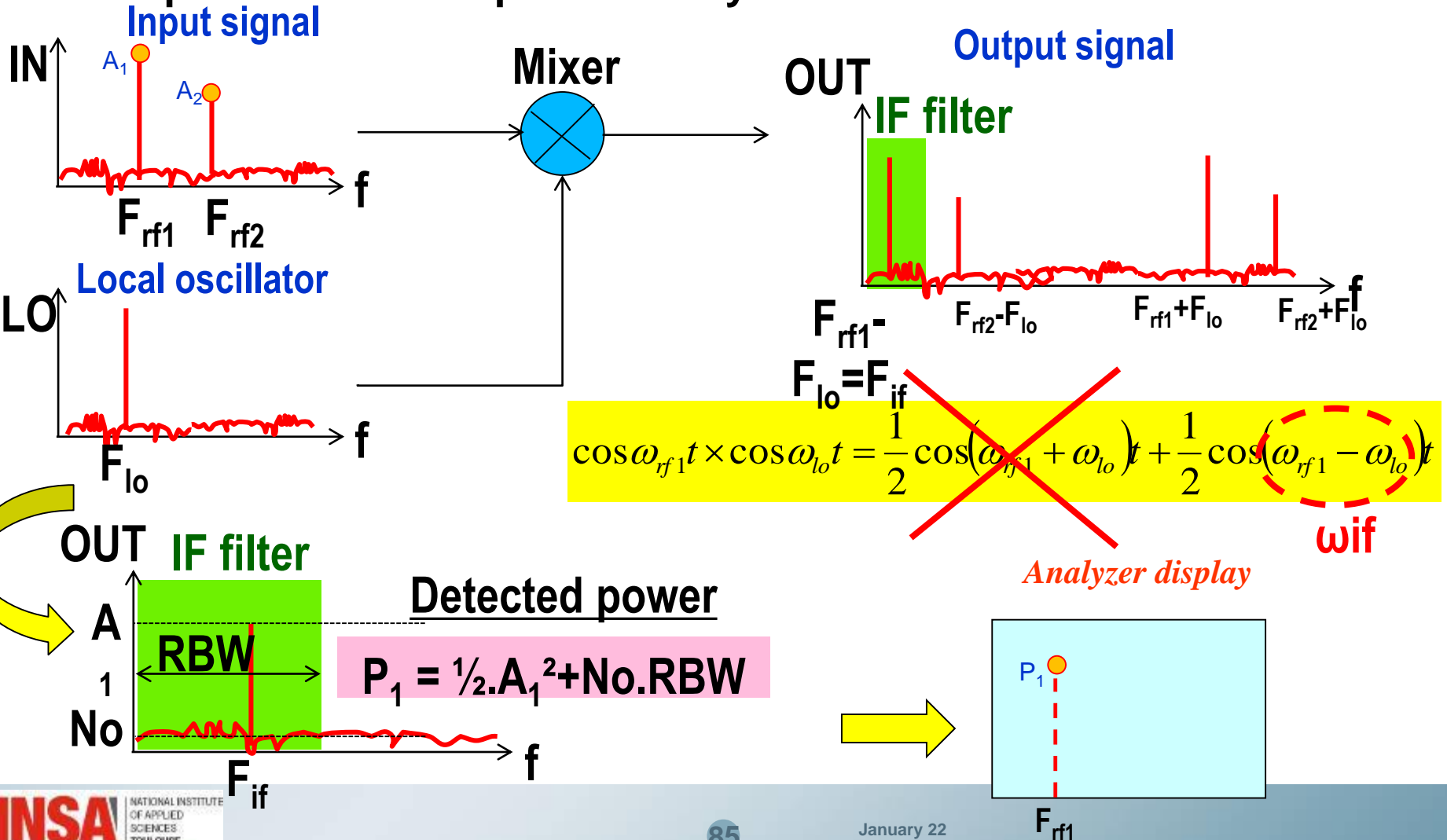


- Main measurement equipments for emission test
- Emission tests require large bandwidth (> 1 GHz) and high sensitivity (typ. 10 dBμV)

# Spectrum analyzer

## Spectrum Analyser (EMI receiver)

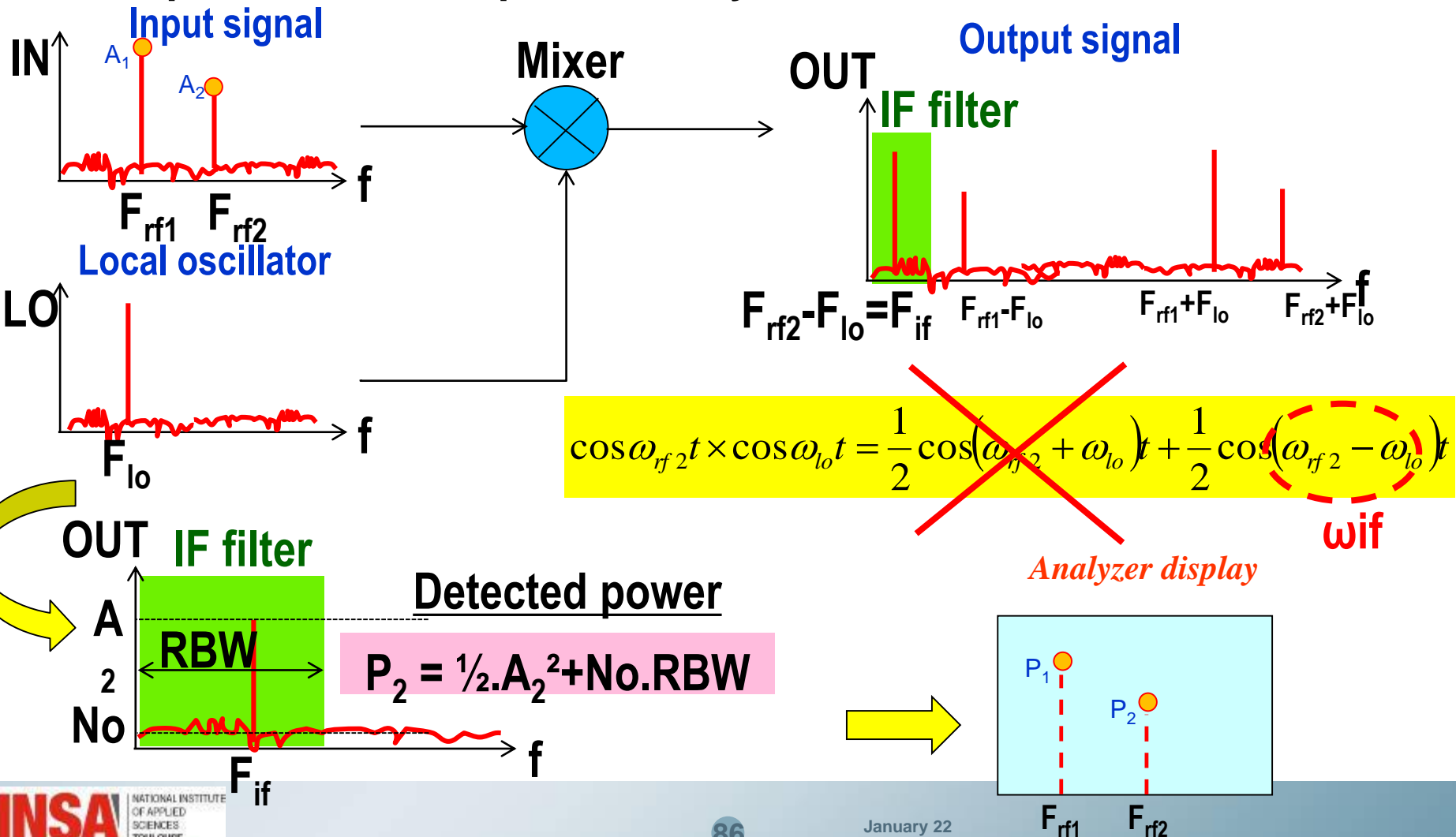
- Principle: based on super heterodyne receiver



# Spectrum analyzer

## Spectrum Analyser (EMI receiver)

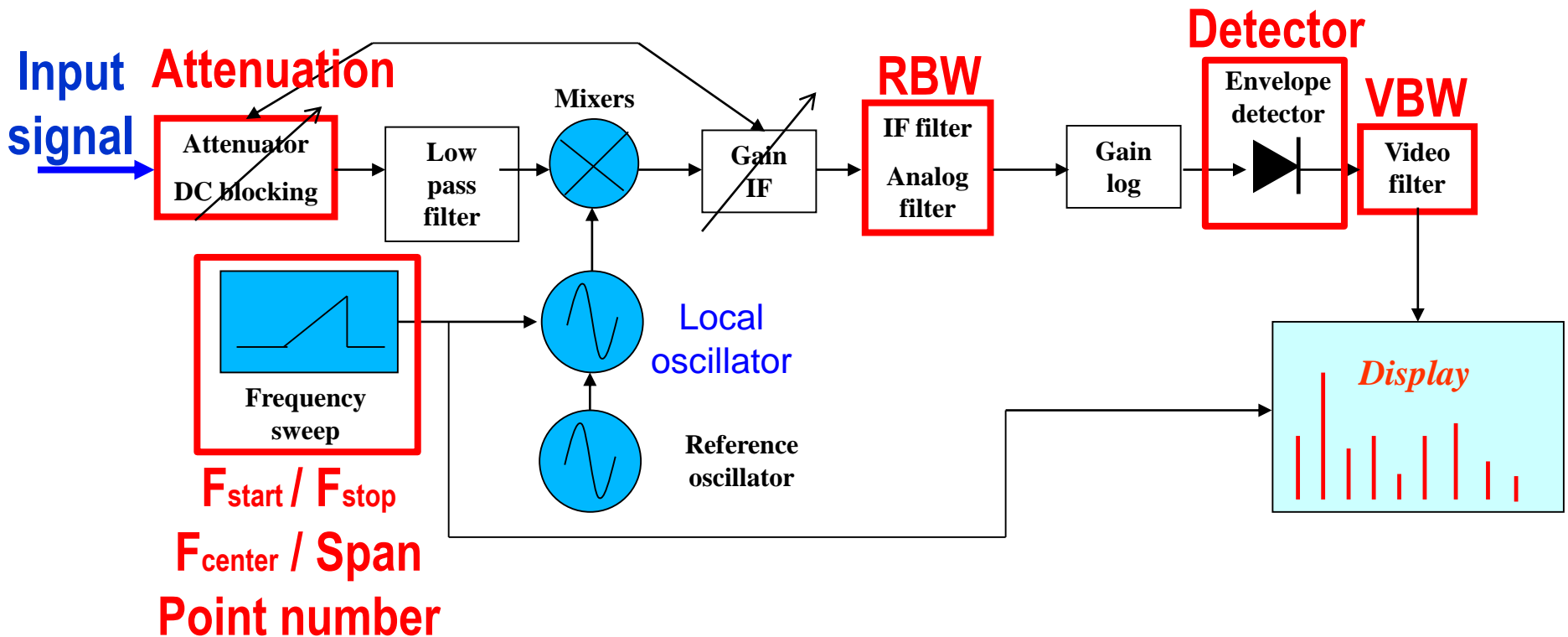
- Principle: based on super heterodyne receiver



# Spectrum analyzer

## Spectrum Analyser (EMI receiver)

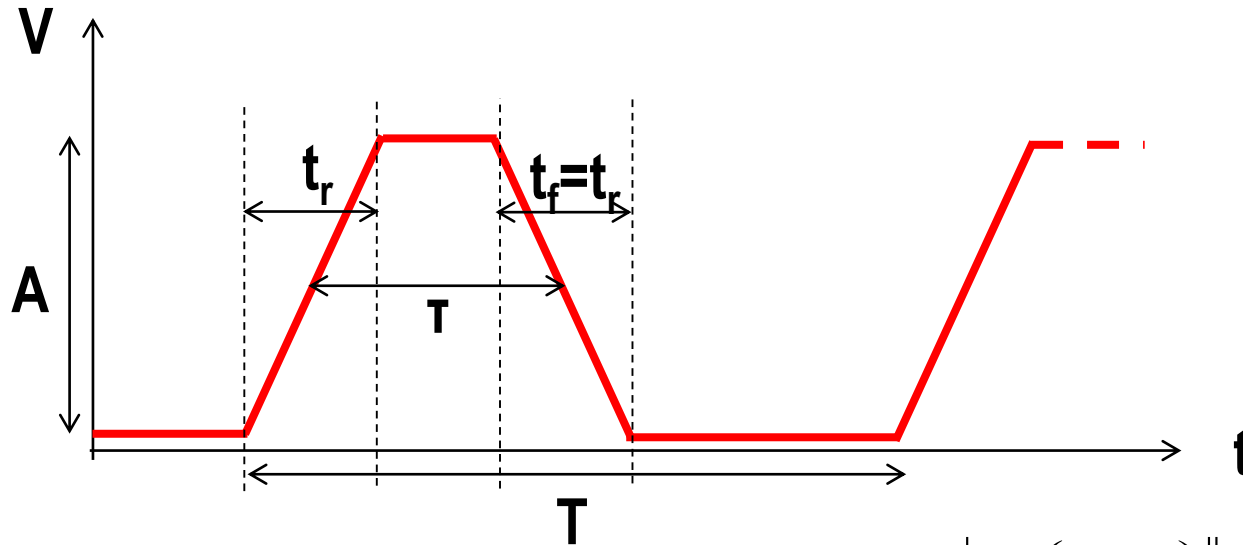
- Building blocks and adjustable elements:



# Spectral content evaluation

## *Spectral contents from unintentional emission of electronic devices*

### ■ Periodical pulse series:



Frequency content ?  
Fourier coefficient  $n$ :

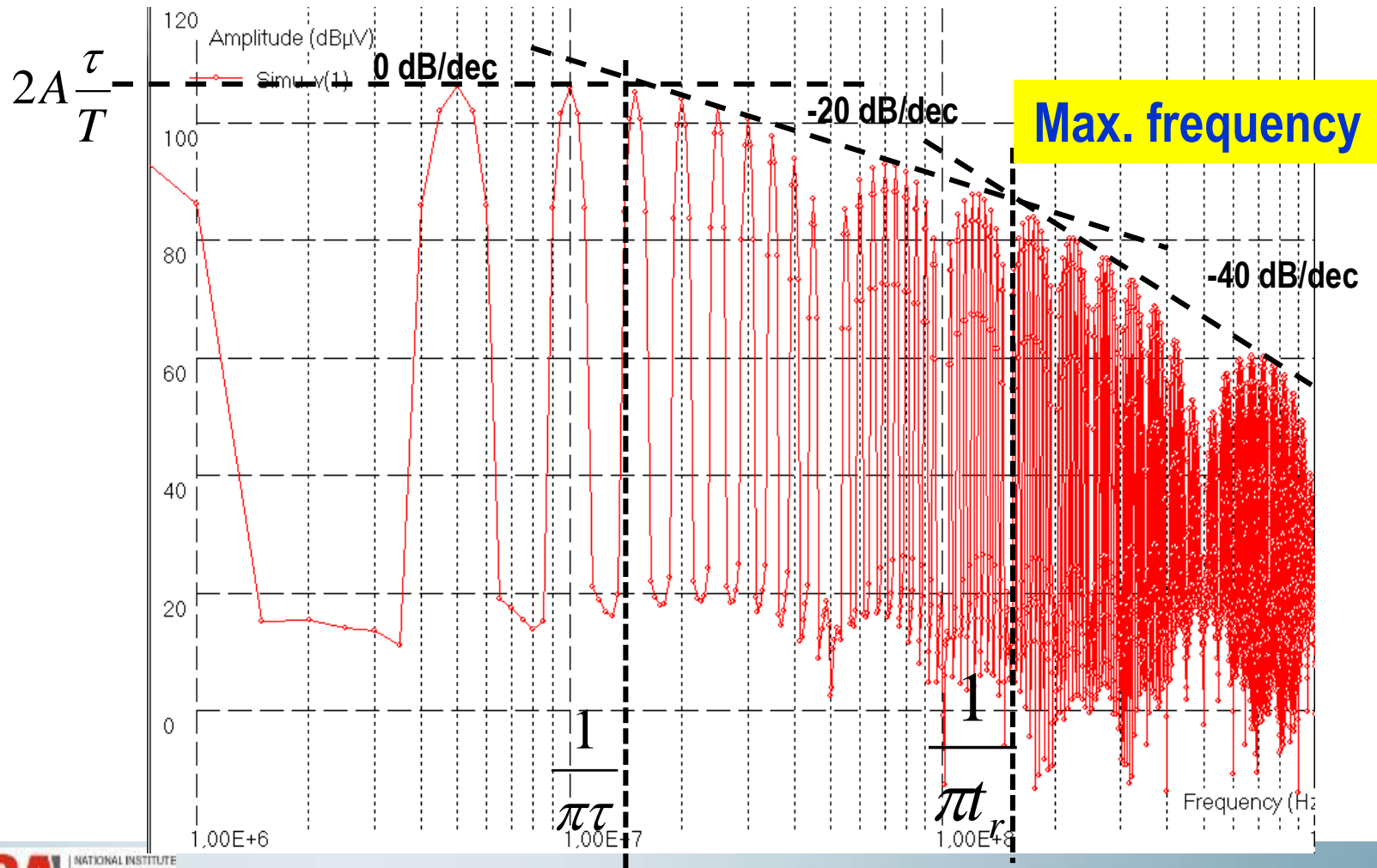
$$|c_n^+| = \frac{2A\tau}{T} \left| \frac{\sin\left(n\pi \frac{\tau}{T}\right)}{n\pi \frac{\tau}{T}} \right| \left| \frac{\sin\left(n\pi \frac{t_r}{T}\right)}{n\pi \frac{t_r}{T}} \right|, n > 0$$

$$c_0 = \frac{A\tau}{T}$$

# Spectral content evaluation

## Spectral contents from unintentional emission of electronic devices

- **Example:  $A = 1$  V,  $T = 200$  ns,  $\tau = 20$  ns,  $t_r = t_f = 2$  ns**

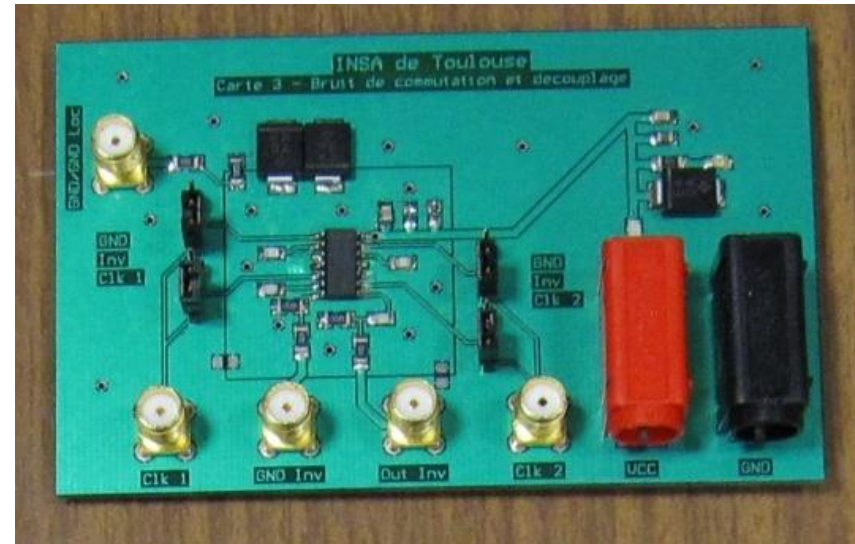
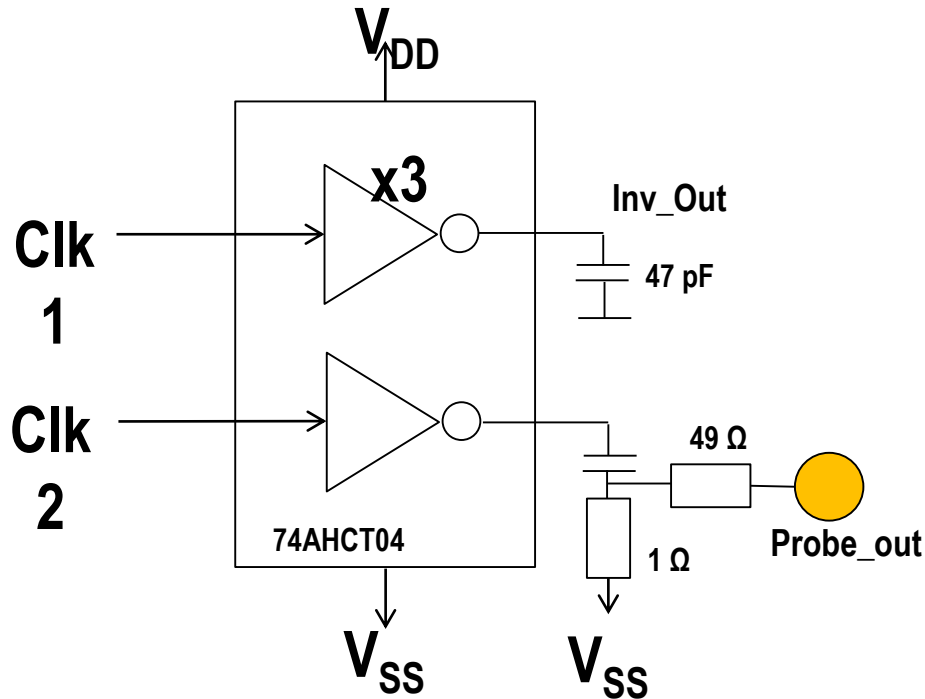




# Spectral content evaluation

## Spectral contents from unintentional emission of electronic devices

- Example: Hex inverter 74AHCT04



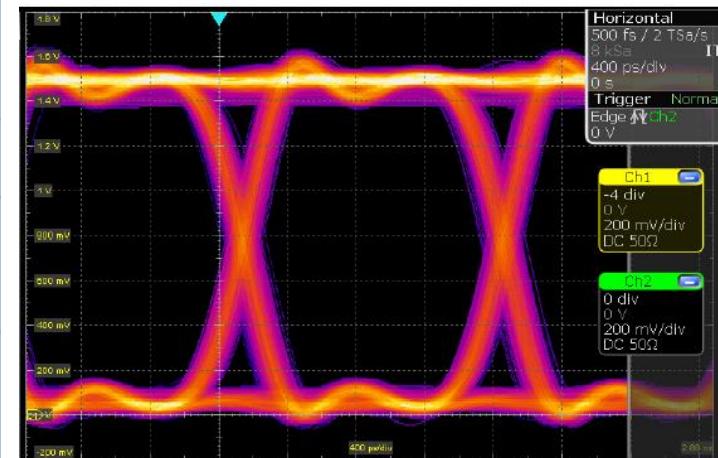
- What is measured on Probe\_Out ?
  - With oscilloscope, observe Probe\_Out and Inv\_Out.
  - Measure transition times of Inv\_Out signal.
- 
- Connect Probe\_out to the spectrum analyzer and observe the spectrum
  - Is there a relationship between transition time and spectral occupancy ?

# Spectral content evaluation

## *Spectral contents from unintentional emission of electronic devices*

- Maximum frequency of emission from the following interfaces:

Technology	Typ. Rise time	Max. freq
High speed CMOS	1.5 ns	
Ethernet 1000 base-t	400 ps	
USB 2.0 high speed	800 ps	
USB 3.0	80 ps	
DDR3	300 ps	

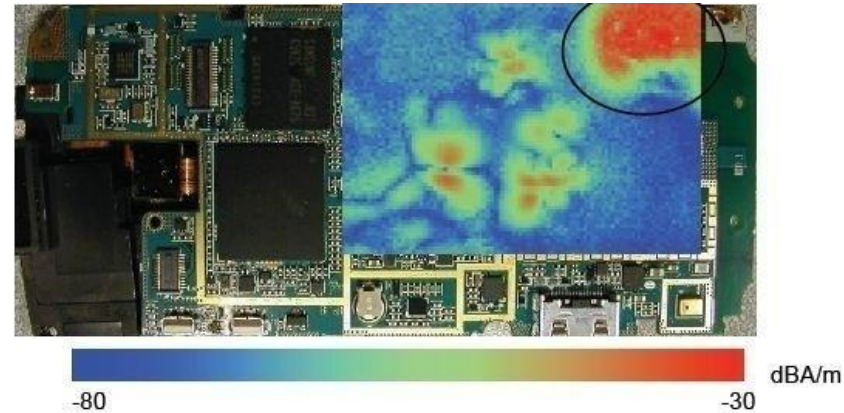


## Observing typical antenna at PCB/IC level

# Antenna at PCB/IC level

## Radiation

- Any conductor crossed by a transient current or excited by a transient voltage can produce electromagnetic fields and radiation.
- Field distribution is determined by Maxwell equations.
- Any IC conductor, PCB traces, connectors, ... may be a « parasitic antenna ».
- Radiation depends on excitation source and characteristics of the parasitic antenna.



And God said

$$\nabla \cdot \mathbf{E} = \frac{\rho}{\epsilon_0}$$

$$\nabla \cdot \mathbf{B} = 0$$

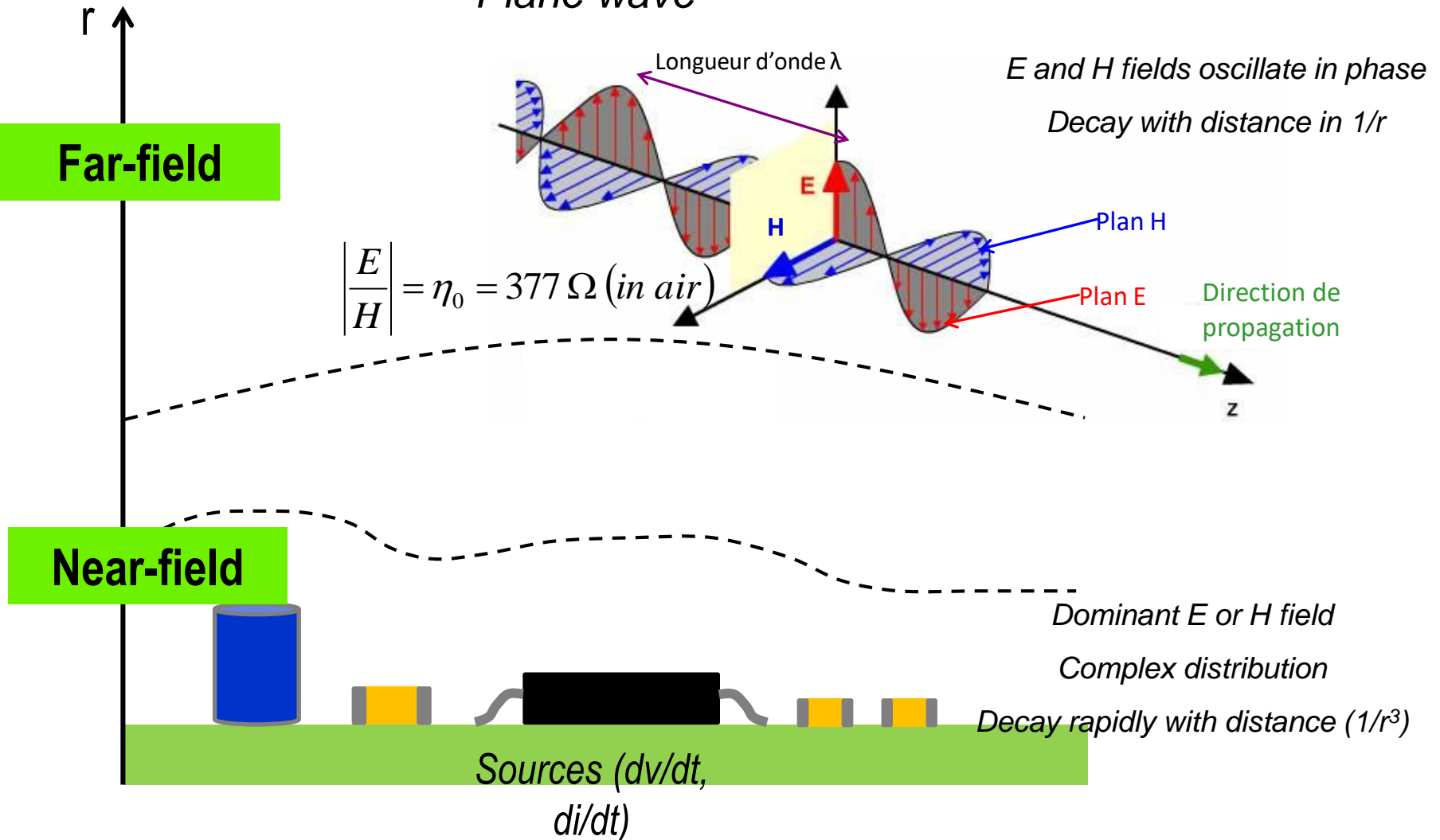
$$\nabla \times \mathbf{E} = -\frac{\partial \mathbf{B}}{\partial t}$$

$$\nabla \times \mathbf{B} = \mu_0 \mathbf{J} + \mu_0 \epsilon_0 \frac{\partial \mathbf{E}}{\partial t}$$

and then there was  
"Light"

# Antenna at PCB/IC level

## Radiation

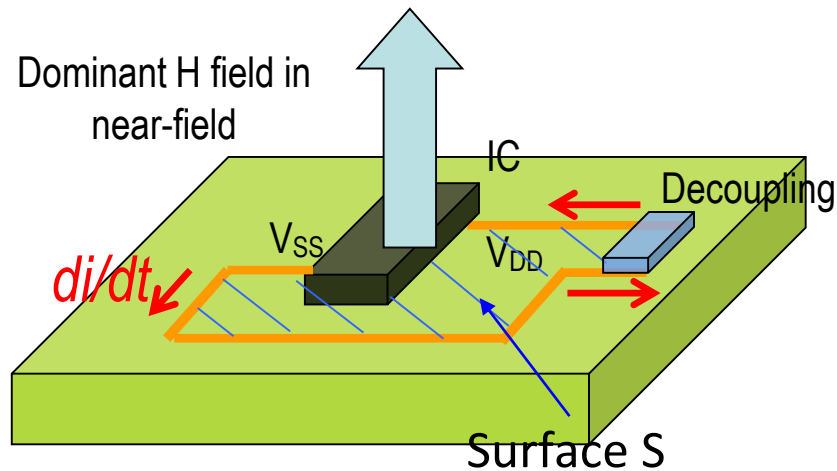


# Antenna at PCB/IC level

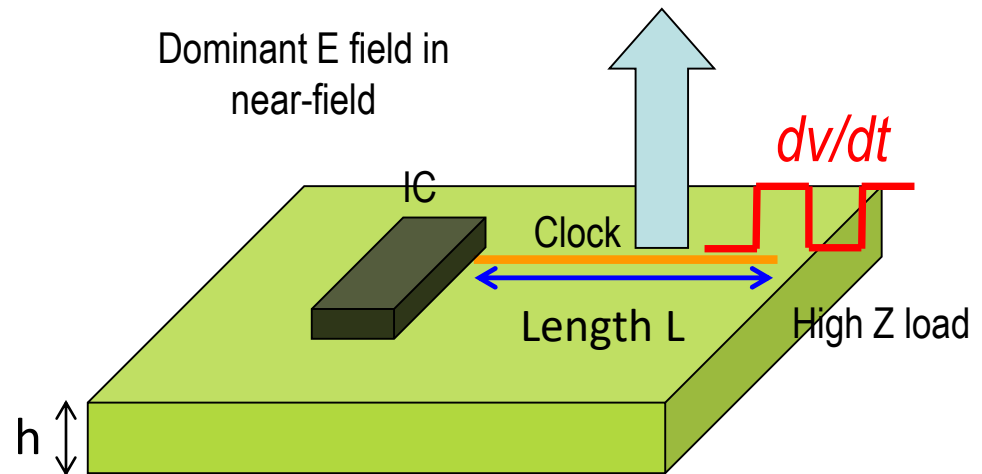
## Electric vs. magnetic antenna

- At IC or PCB level, two types of basic antenna can be distinguished:

### Magnetic antenna (low impedance loop)



### Electric antenna (High impedance trace)



In far-field:

$$E_{\max} = \frac{1.32 \cdot 10^{-14} f^2 SI}{r}$$

In far-field:

$$E_{\max} = 8.27 \cdot 10^{-14} \frac{VLhC_{line}f^3}{r}$$

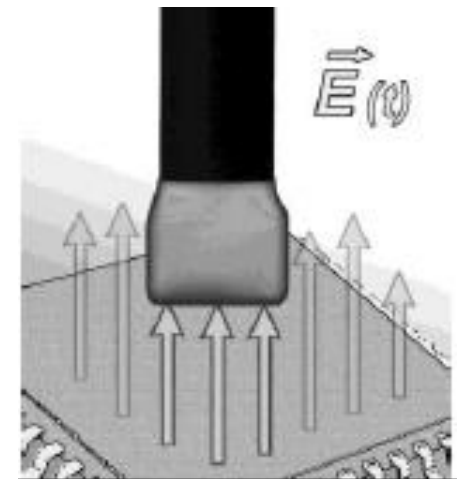
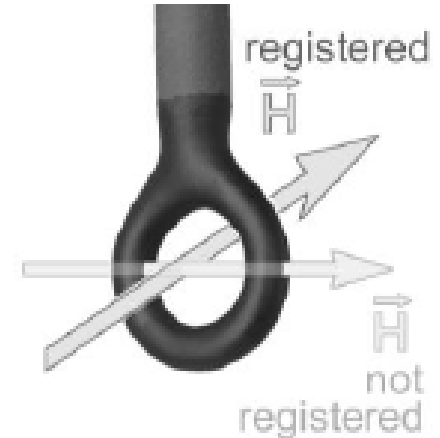
$$L = \frac{\lambda}{4} \text{ si } f > \frac{c}{4L}$$



# Antenna at PCB/IC level

## *Electric vs. magnetic antenna*

- Near-field probes use to sense local electric or magnetic fields
- Excite a microstrip line with a square waveform and connect various types of electrical load (short, open, 50  $\Omega$ )
- With near-field probes, observe the distribution of E and H field around the trace. Determine the orientation of H field.
- What is the influence of the trace load on the dominant field around the trace ?



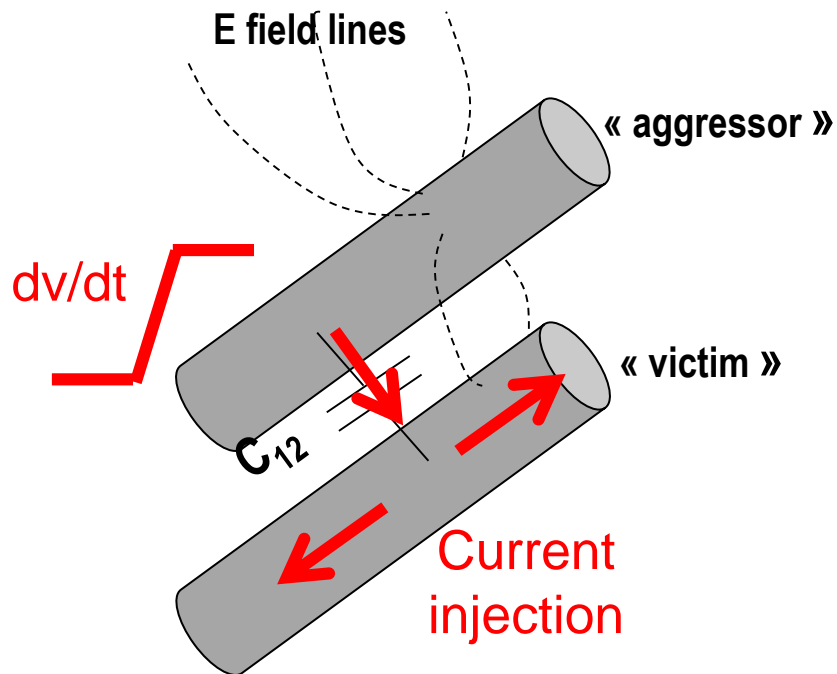
## Crosstalk between two nearby traces

# Crosstalk

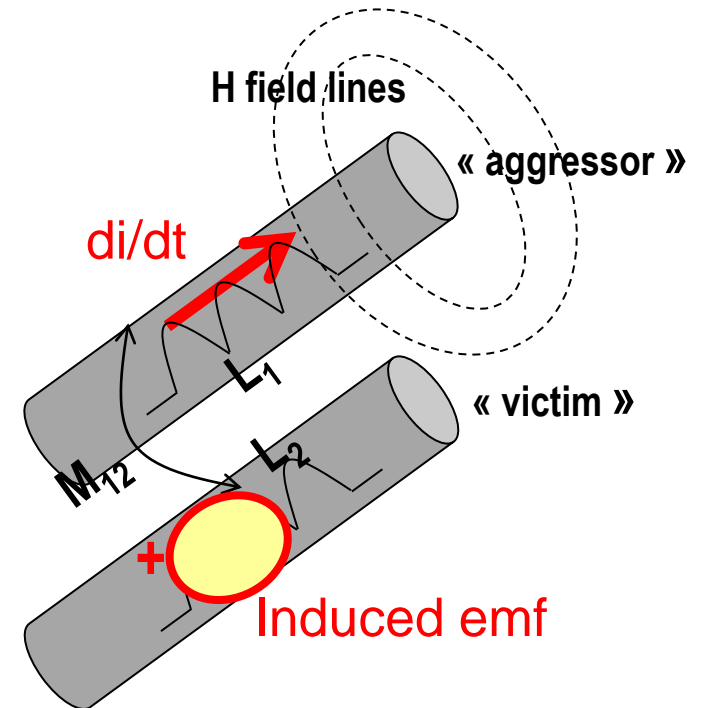
## Electric vs. magnetic coupling

- Two types of coupling between two nearby lines:

### Electric coupling



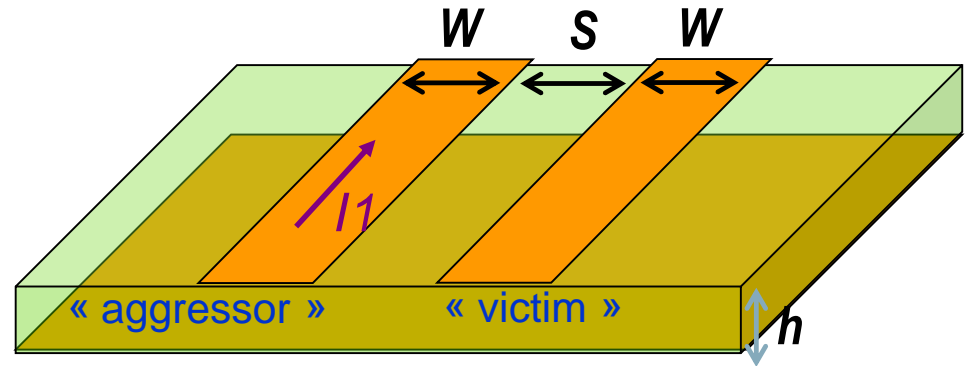
### Magnetic coupling



# Crosstalk

## *Electric vs. magnetic coupling*

- Two nearby microstripl ines:
  - $W = 0.65 \text{ mm}$
  - Separation =  $0.15 \text{ mm}$  ou  $1.65 \text{ mm}$  ( $3W$ )



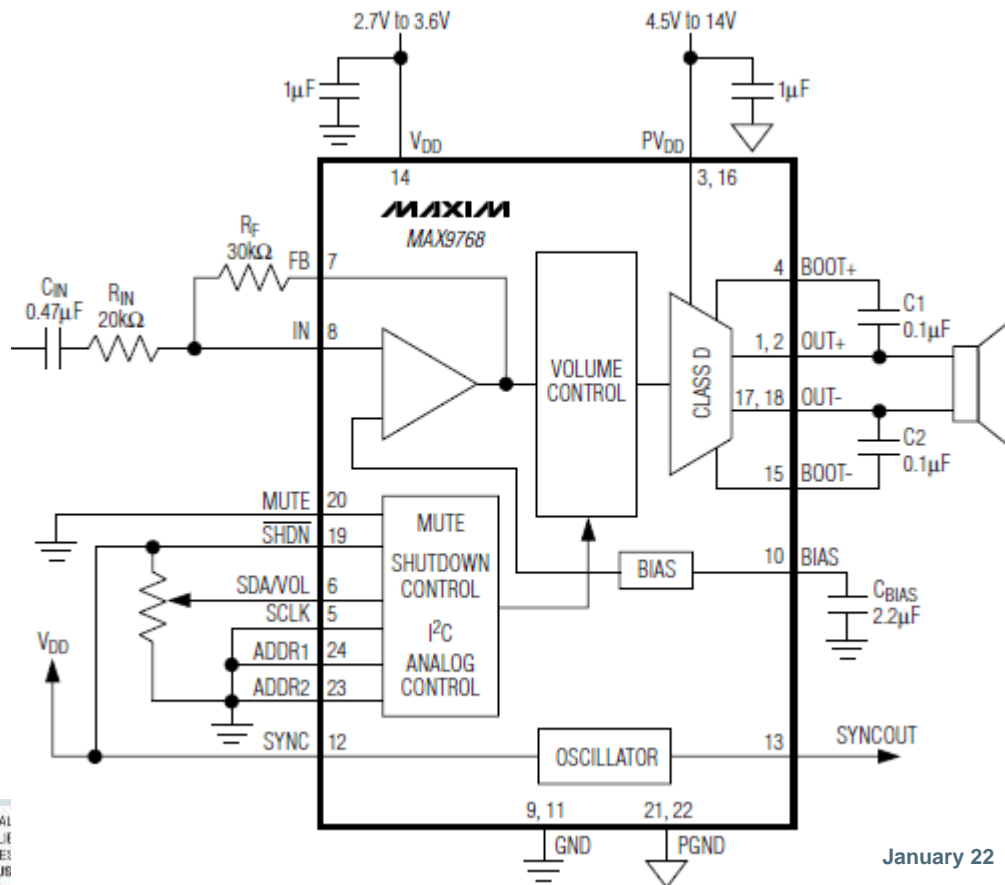
- Apply a square waveform on the input of « aggressor » line. Observe the voltage induced on both terminals of « victim » line (near and far ends).
- Observe the effect of « agressor » line termination (short, open and  $50 \Omega$ ).
- Propose a basic electrical model to explain observations.
- 3W rule: what is the effect of trace separation ?

## CM vs DM current – Cable radiation

# CM vs DM current – Cable radiation

## *Electromagnetic emission from a class-D amplifier*

- MAX9768 – 10 W mono class D speaker amplifier, EN55022 class B compliant.
- Applications: low power portable application (notebook computer, Multimedia monitor, GPS navigation system...)



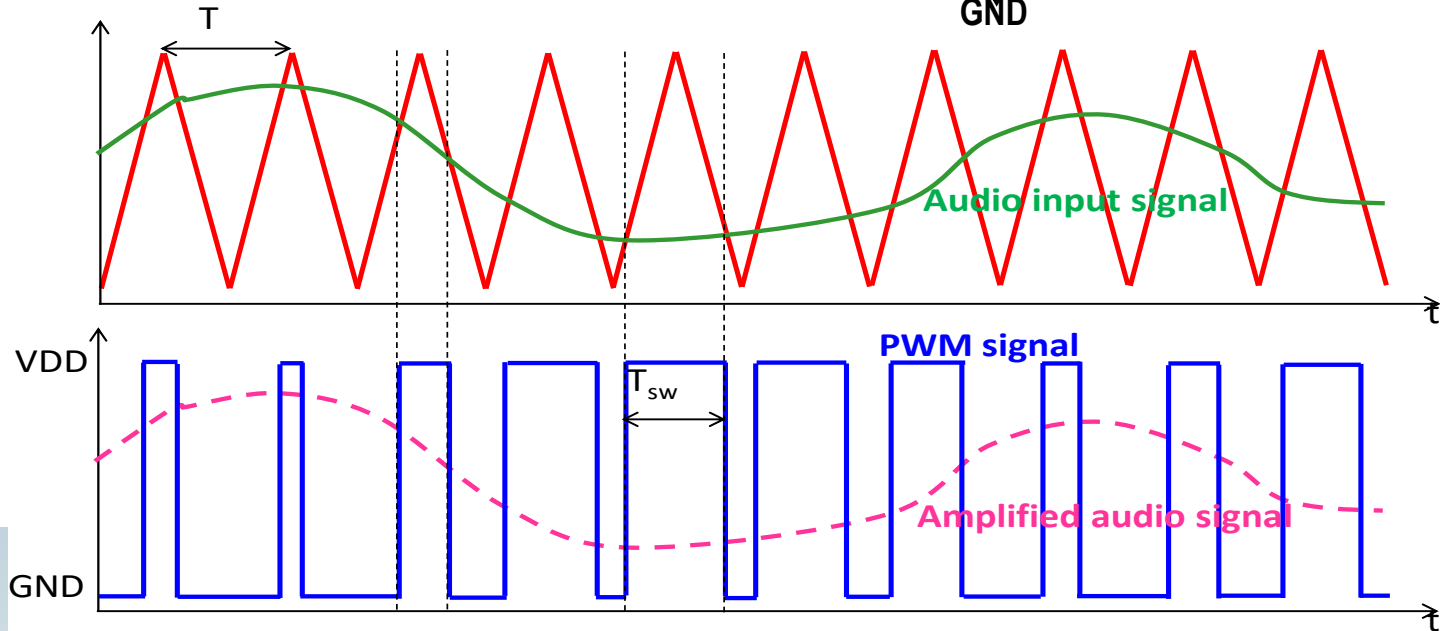
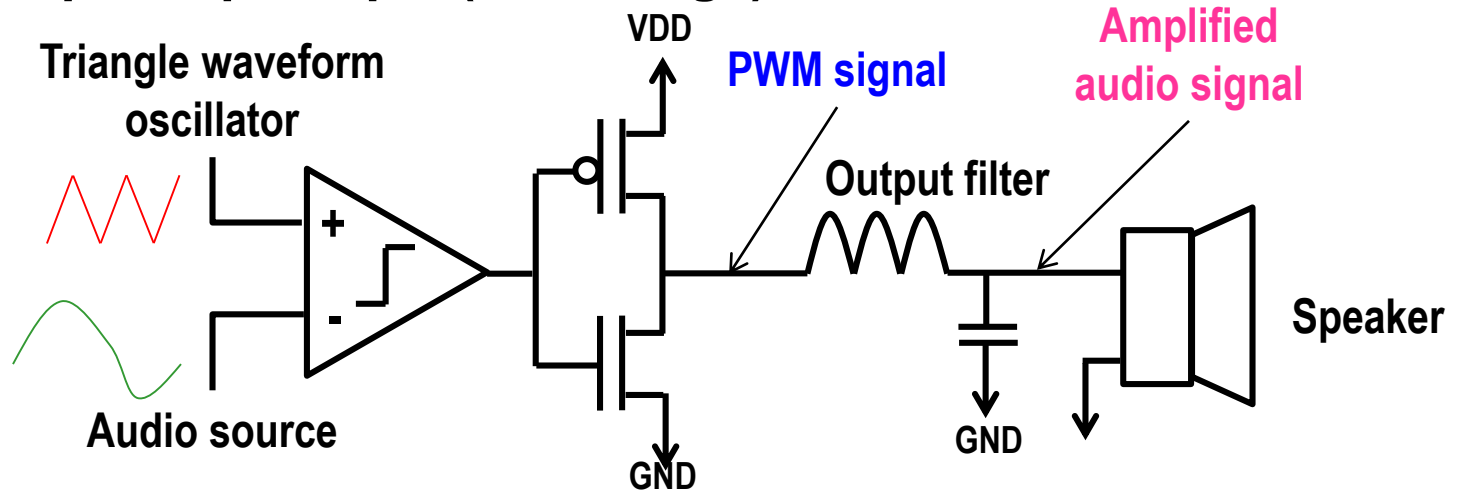
[www.maxim.com](http://www.maxim.com)

January 22

# CM vs DM current – Cable radiation

## Electromagnetic emission from a class-D amplifier

### ■ Class D amplifier principle (half-bridge):



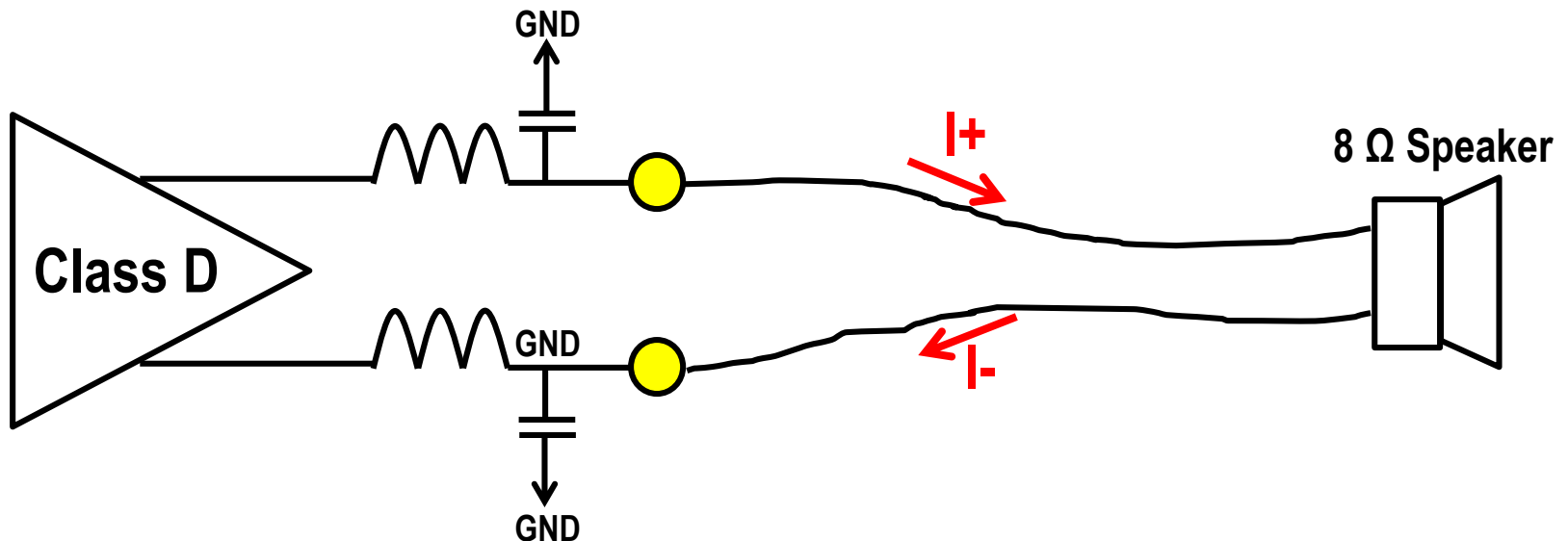
$$out(t) = V_{DD} \frac{T_{sw}(t)}{T}$$



# CM vs DM current – Cable radiation

## *Electromagnetic emission from a class-D amplifier*

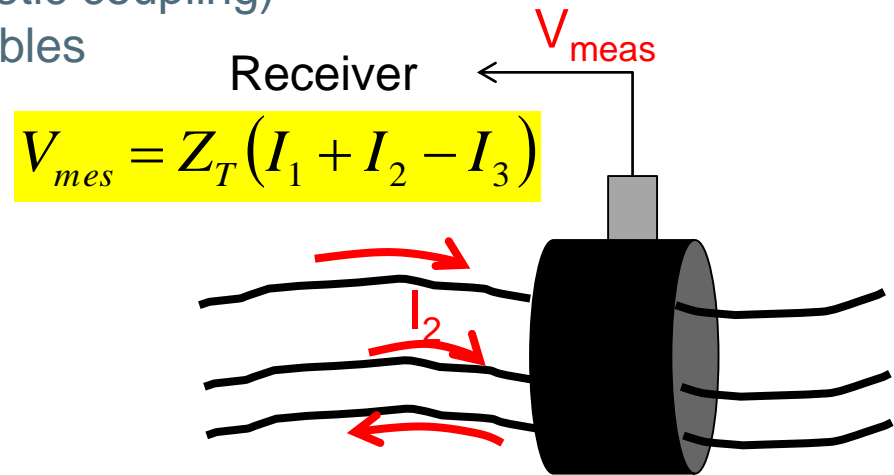
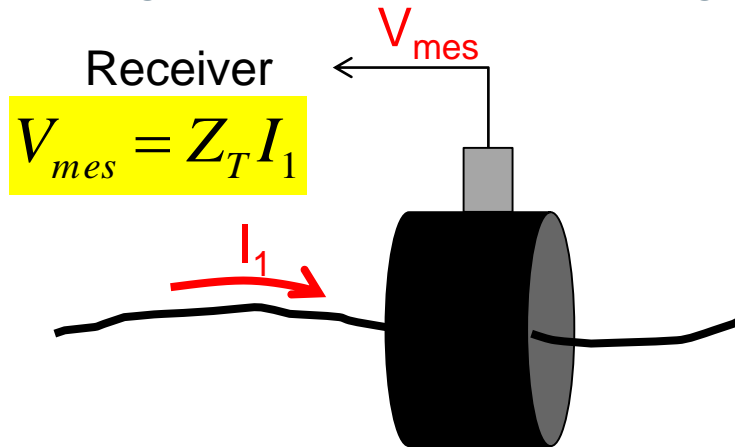
- Measure and compare the currents circulating on wires OUT+ and OUT- of the speaker cable.
- Are they perfectly balanced ?



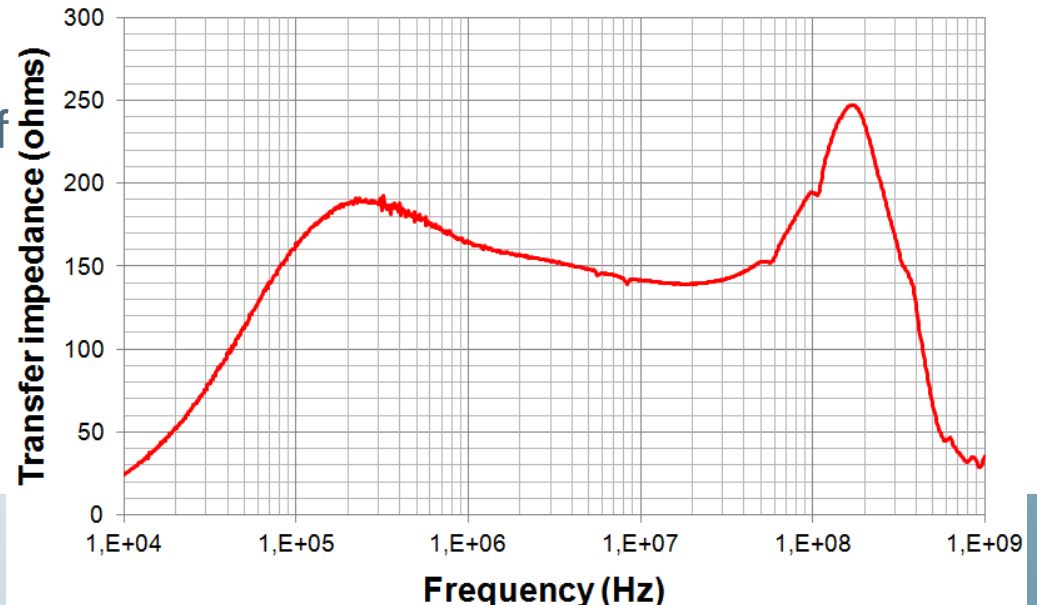
# Differential and common-mode current

## Differential vs. common mode current measurement

- Transducer current  $\rightarrow$  voltage (magnetic coupling)
- Diagnosis of current circulating on cables



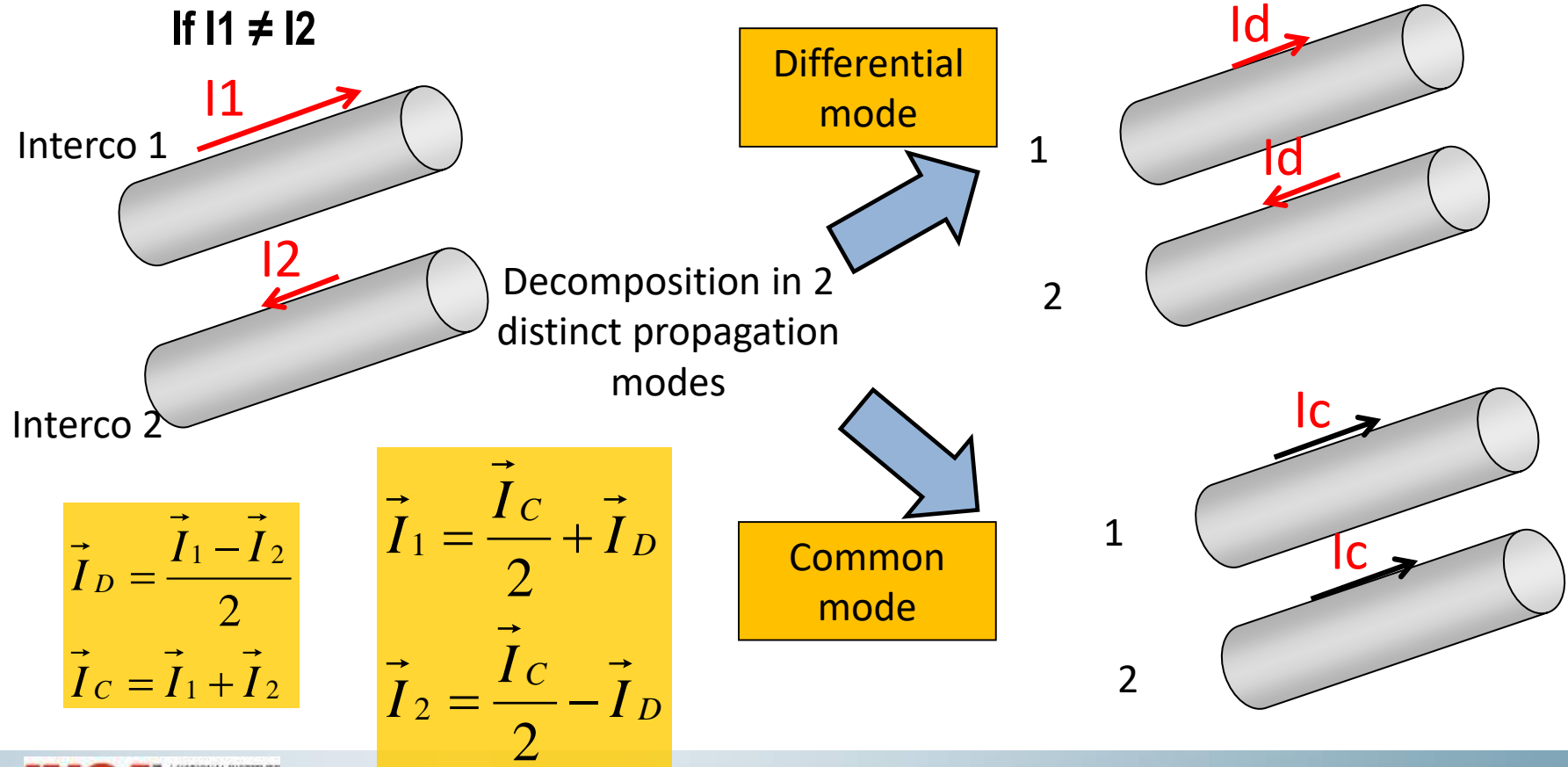
- Example: transfer impedance of TESEQ MD4070 :



# Differential and common-mode current

## Differential vs. common mode currents

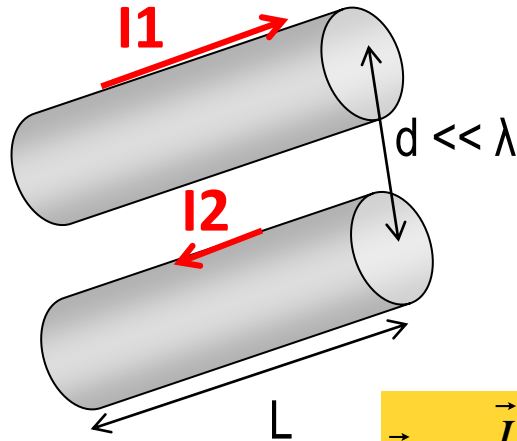
- Common mode appears when the return current path is not perfectly defined or differential driver and load are not perfectly balanced.



# Simple radiated emission model

## Cable radiation: Differential vs. Common-mode radiation

- Simplified model of worst-case radiation of a two conductor cable



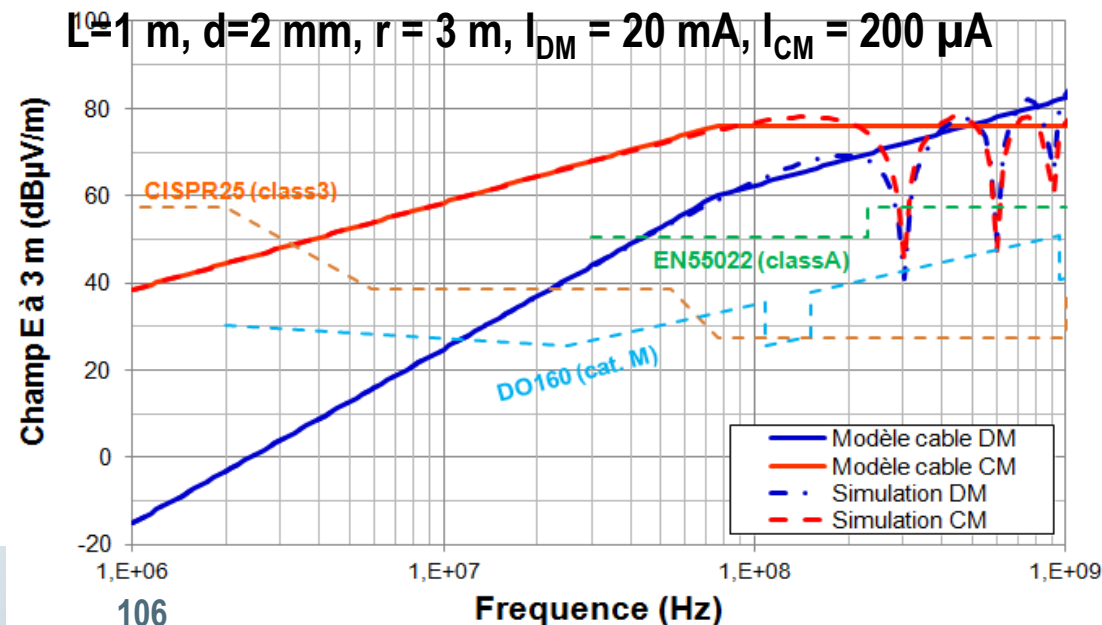
$$\vec{I}_D = \frac{\vec{I}_1 - \vec{I}_2}{2}$$

$$\vec{I}_C = \vec{I}_1 + \vec{I}_2$$

$$|E_D|_{\max} = 1.316 \cdot 10^{-14} \frac{L \cdot d \cdot f^2}{r} I_D, L = \min \left( \text{Long}, \frac{\lambda}{4} \right)$$

$$|E_C|_{\max} = 1.257 \cdot 10^{-6} \frac{L \cdot f}{r} I_C, L = \min \left( \text{Long}, \frac{\lambda}{4} \right)$$

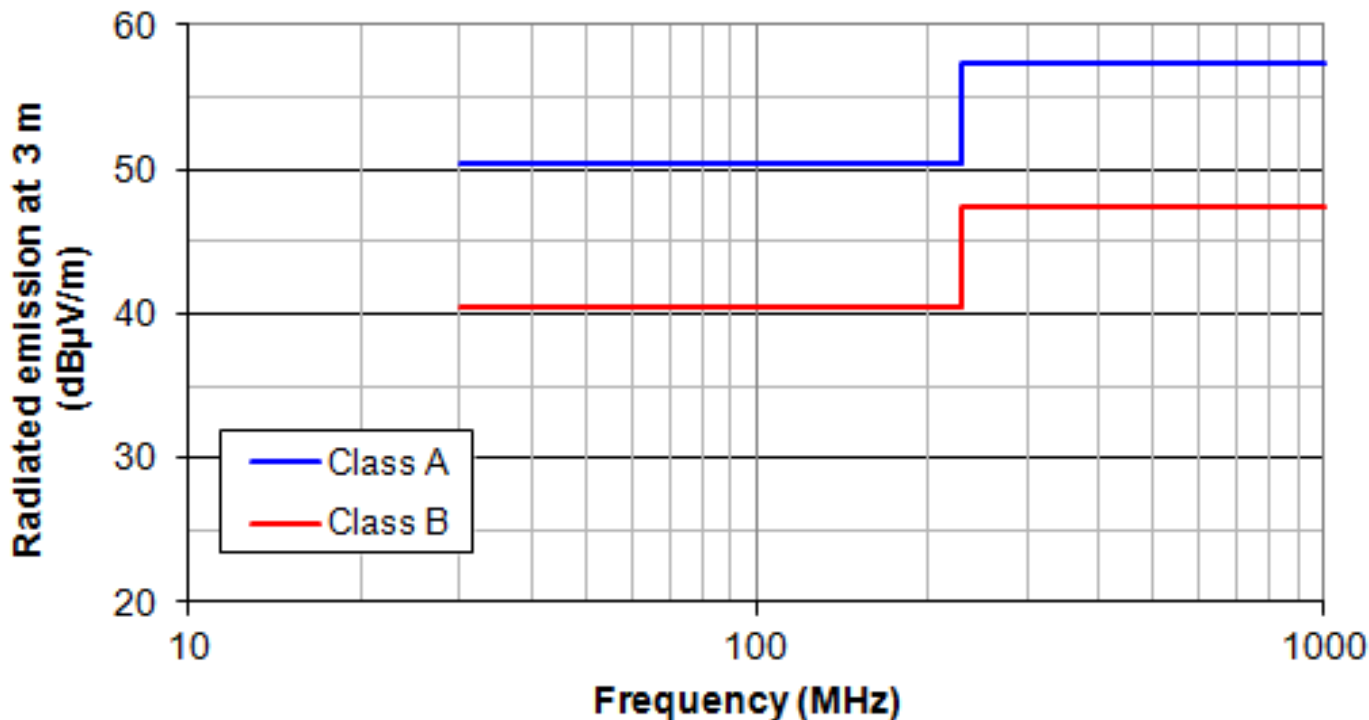
- In electronic equipment, cables are usually the main antennas, especially due to common-mode current.



# CM vs DM current – Cable radiation

## *Electromagnetic emission from a class-D amplifier*

- Evaluate the differential and common-mode radiation at 3 m produced by the speaker cable.
- Does it comply with EN55022 class B standard ?



# CM vs DM current – Cable radiation

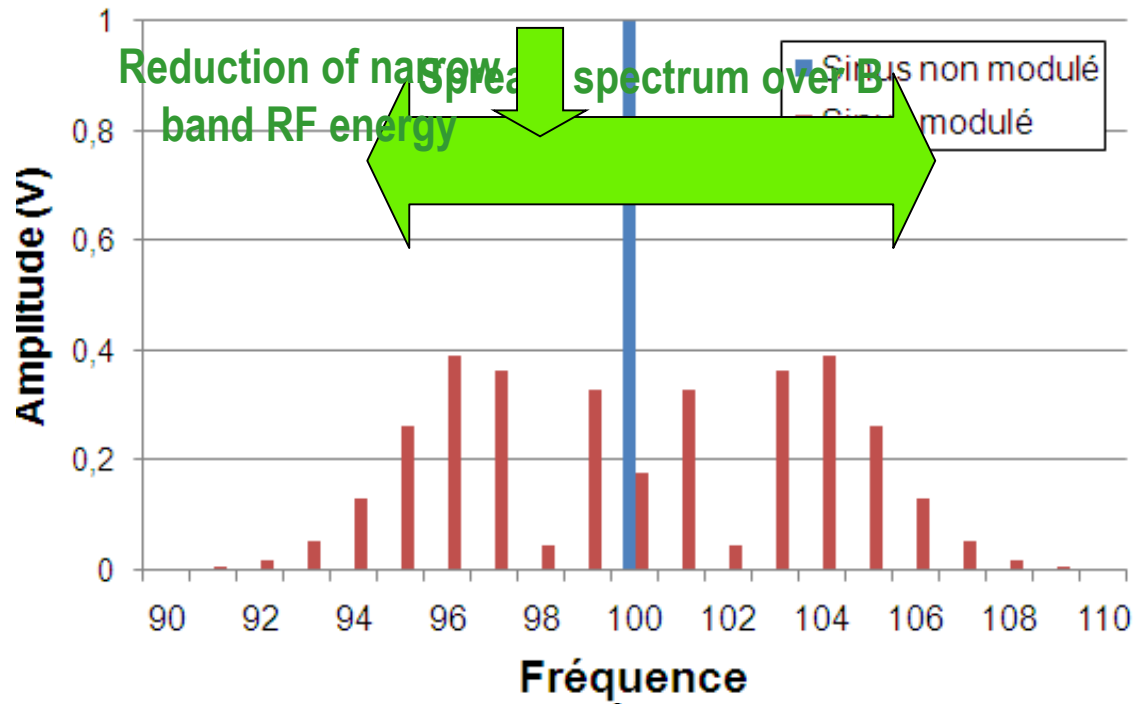
*Electromagnetic emission from a class-D amplifier*

■ Solutions ?

# Spread spectrum frequency modulation

## Frequency modulation

- Frequency modulation spreads the spectrum of a signal
- Example : sinus clock at  $F_c = 100$  MHz vs modulated sinus clock:



Carrier frequency  $F_c = 100$  MHz

Modulation frequency  $F_M = 1$  MHz

Frequency excursion  $dF = \pm 5$  MHz

→ Modulation index  $md = 5$

$$S_{FM}(t) = \cos\left(\omega_c t + \frac{df}{F_M} \cos \omega_M t\right)$$

$$S_{FM}(t) = \cos(\omega_c t + md \cos \omega_M t)$$

Carson rule:

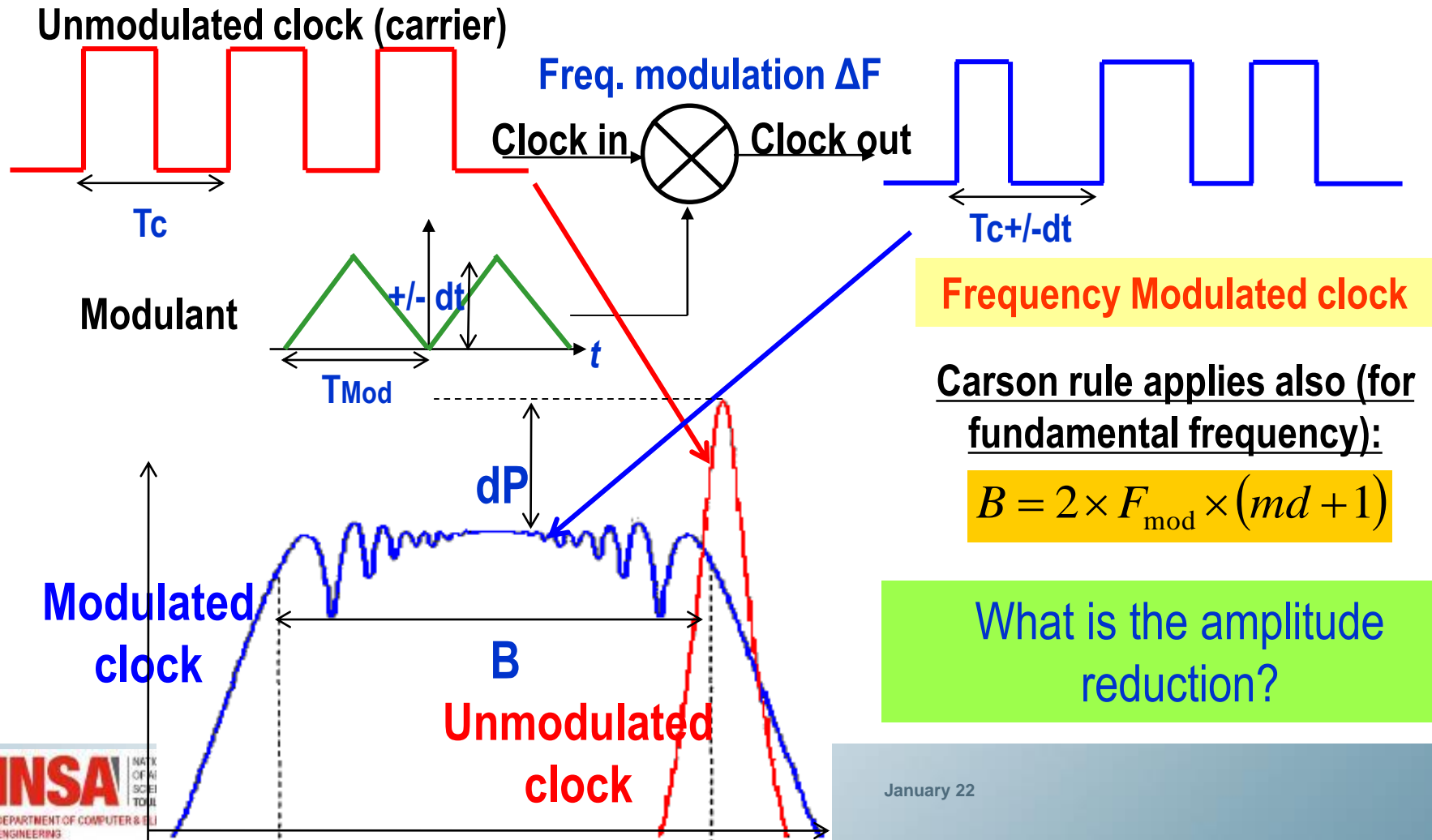
$$B = 2 \times F_M \times (md + 1)$$



# Spread spectrum frequency modulation

## Principle

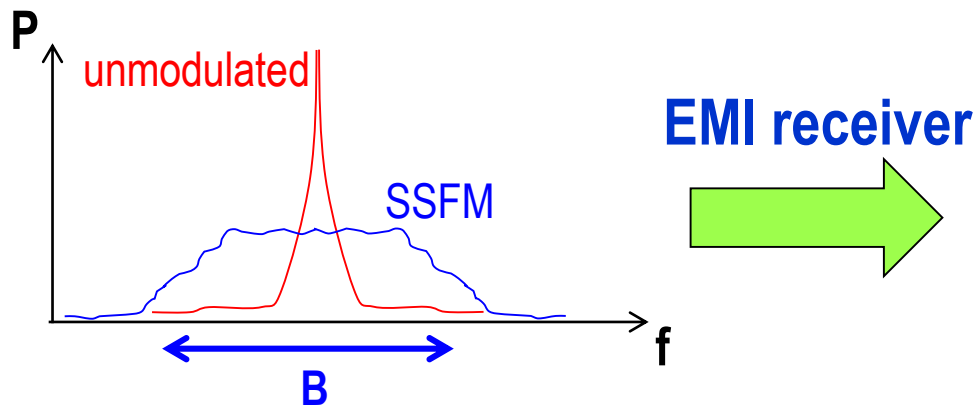
- Emission from clock or PWM signal can be reduced by using spread spectrum frequency modulation (SFFM)



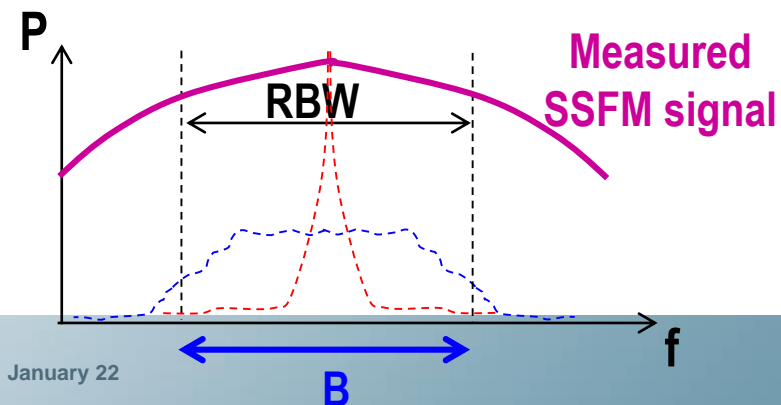
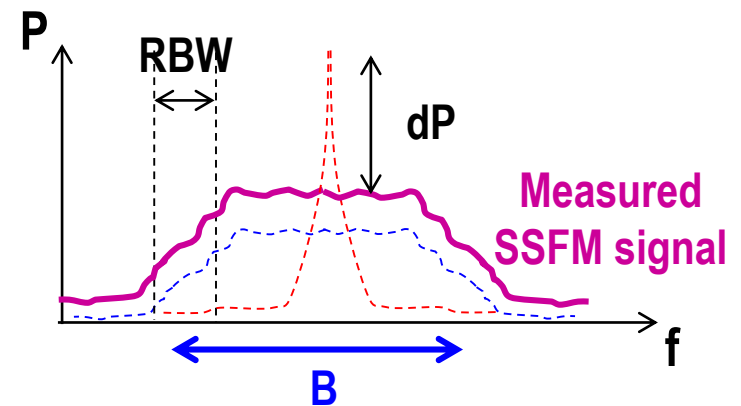
# Spread spectrum frequency modulation

## Emission improvement

- The reduction of spectrum amplitude depends on:
  - Parameters of the modulation (md and Fm)
  - The modulant waveform (selection of a waveform that makes the spectrum as flat as possible)
  - Receiver bandwidth RBW:



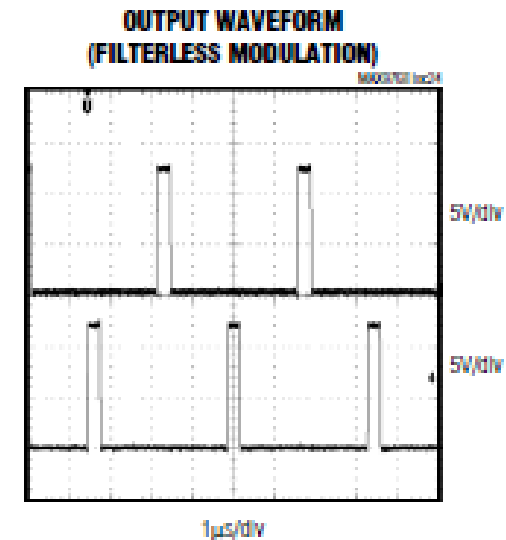
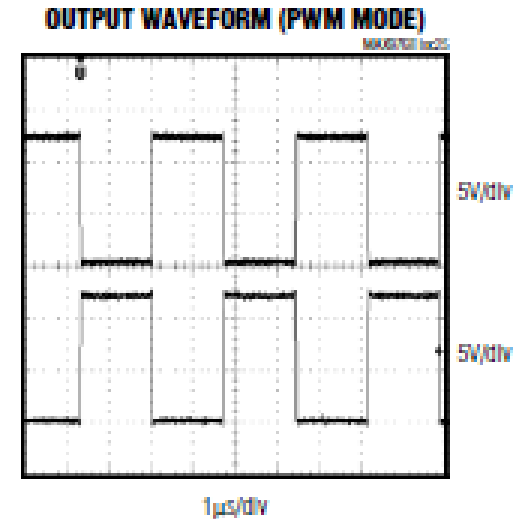
$$dP(dB) \approx 10 \log \left( \frac{B}{RBW} \right)$$



# Spread spectrum frequency modulation

## Case study – Class-D amplifier MAX9768

- Two output modulations:
  - Classic PWM mode
  - Filterless modulation mode
- Three operating modes:
  - Fixed frequency (300 or 360 kHz)
  - SSFM ( $F_c = 300$  kHz,  $df = \pm 7.5$  kHz)
  - External clock (1 to 1.6 MHz)



# Spread spectrum frequency modulation

## *Case study – Class-D amplifier*

- Observe the effect of the internal SSFM on the fundamental frequency of the common-mode noise which propagates along the speaker cable. Use a narrow RBW.
- Observe the effect of the internal SSFM on the spectrum of the common-mode noise which propagates along the speaker cable. Use a narrow RBW.
- EN55022 recommends the following RBW:
  - 9 kHz from 150 kHz to 30 MHz
  - 120 kHz from 30 MHz to 1 GHz
- What is the effect of the internal SSFM on the conducted emission?